Agilent 4395A Network/Spectrum/Impedance Analyzer Operation Manual

Manual Change

Agilent Part No. N/A

January 2007

Change 1

Change the equations for the noise level measurement (page 8-35) to the following.

Converting to a Different Equivalent Noise Bandwidth

1. Calculate the conversion factor using the following equations with displayed units:

Where, *BW* is the target equivalent noise bandwidth.

Change 2

Change options 1CN, 1CM and 1CP in the package contents of the 4395A (page 2-3) to the following.

マニュアル チェンジ

$8-36$

Agilent 4395A Network/Spectrum/Impedance Analyzer Operation Manual

Manual Change

Agilent Part No. N/A May 2007

Change 1

Regarding the Data Processing of Impedance Analyzer Mode, refer to the 4396B Operating Hand book (Page 5-6 to 5-9), or the 4396B Function reference. You can also download the 4396B Manual with the following process.

- 1. Open the Agilent Technologies Website. <http://www.agilent.com/>
- 2. In the search box, enter 4396B, and then open the page of 4396B Network/Spectrum Impedance Analyzer.
- 3. Click the manuals in the Technical Support of 4396B RF Network/Spectrum/Impedance Analyzer.
- 4. Download the manual

マニュアル チェンジ

変更 1

インピーダンス・アナライザ・モードでの内部データ処理については、4396B オペレーティング・ハンドブ ック (5-6 から 5-9 ページ)または、4396B の機能解説書を参照して下さい。 また、4396B のマニュアルは以下の手順でダウンロードする事ができます。

- 1. アジレント・テクノロジーのホームページを開きます。 http://www.agilent.com/
- 2. 検索の欄に "4396B"を入力し、4396B ネットワーク/スペクトラム/インピーダンスアナライザのページ を開きます。
- 3. 4396B RF ネットワーク/スペクトラム/インピーダンスアナライザの、テクニカルサポート/イベントか らマニュアルをクリックします。
- 4. マニュアルをダウンロードします。

 $\hat{\boldsymbol{\gamma}}$

Safety Summary

When you notice any of the unusual conditions listed below, immediately terminate operation and disconnect the power cable.

Contact your local Agilent Technologies sales representative or authorized service company for repair of the instrument. If you continue to operate without repairing the instrument, there is a potential fire or shock hazard for the operator.

- **Instrument operates abnormally.**
- Instrument emits abnormal noise, smell, smoke or a spark-like light during the operation.
- Instrument generates high temperature or electrical shock during operation.
- Power cable, plug, or receptacle on instrument is damaged.
- Foreign substance or liquid has fallen into the instrument.

Herstellerbescheinigung

GERÄUSCHEMISSION

 $\begin{array}{c} \text{LpA} < 70 \text{ dB} \\ \text{am Arbeitsplatz} \end{array}$ normaler Betrieb nach DIN 45635 T. 19

Manufacturer's Declaration

ACOUSTIC NOISE EMISSION

 $LpA < 70$ dB operator position normal operation per ISO 7779

Caution

Do not exceed the operating input power, voltage, and current level and signal type appropriate for the instrument being used, refer to your instrument's Operation Manual.

 Electrostatic discharge(ESD) can damage the highly sensitive microcircuits in your instrument. ESD damage is most likely to occur as the test fixtures are being connected or disconnected. Protect them from ESD damage by wearing a grounding strap that provides a high resistance path to ground. Alternatively, ground yourself to discharge any static charge built-up by touching the outer shell of any grounded instrument chassis before touching the test port connectors.

Agilent 4395A Network/Spectrum/Impedance Analyzer Operation Manual

SERIAL NUMBERS

This manual applies directly to instruments which have the serial number prefix JP1KE and MY411. For additional important information about serial numbers, read "Serial Number" in Appendix D of this Manual.

Agilent Part No. 04395-90040 Printed in JAPAN May 2003

Sixth Edition

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Manual Printing History

The manual printing date and part number indicate its current edition. The printing date changes when ^a new edition is printed. (Minor corrections and updates that are incorporated at reprint do not cause the date to change.) The manual part number changes when extensive technical changes are incorporated.

Certification

Agilent Technologies certifies that this product met its published specifications at the time of shipment from the factory. Agilent Technologies further certies that its calibration measurements are traceable to the United States National Institute of Standards and Technology, to the extent allowed by the Institution's calibration facility, or to the calibration facilities of other International Standards Organization members.

Warranty

This Agilent Technologies instrument product is warranted against defects in material and workmanship for ^a period of one year from the date of shipment, except that in the case of certain components listed in General Information of this manual, the warranty shall be for the specied period. During the warranty period, Agilent Technologies will, at its option, either repair or replace products that prove to be defective.

For warranty service or repair, this product must be returned to ^a service facility designated by Agilent Technologies. Buyer shall prepay shipping charges to Agilent Technologies and Agilent Technologies shall pay shipping charges to return the product to Buyer. However, Buyer shall pay all shipping charges, duties, and taxes for products returned to Agilent Technologies from another country.

Agilent Technologies warrants that its software and firmware designated by Agilent Technologies for use with an instrument will execute its programming instruction when property installed on that instrument. Agilent Technologies does not warrant that the operation of the instrument, or software, or firmware will be uninterrupted or error free.

Limitation Of Warranty

The foregoing warranty shall not apply to defects resulting from improper or inadequate maintenance by Buyer, Buyer-supplied software or interfacing, unauthorized modication or misuse, operation outside the environmental specifications for the product, or improper site preparation or maintenance.

No other warranty is expressed or implied. Agilent Technologies specifically disclaims the implied warranties of merchantability and fitness for a particular purpose.

Exclusive Remedies

The remedies provided herein are buyer's sole and exclusive remedies. Agilent Technologies shall not be liable for any direct, indirect, special, incidental, or consequential damages, whether based on contract, tort, or any other legal theory.

Assistance

Product maintenance agreements and other customer assistance agreements are available for Agilent Technologies products.

For any assistance, contact your nearest Agilent Technologies Sales and Service Office. Addresses are provided at the back of this manual.

Safety Summary

The following general safety precautions must be observed during all phases of operation, service, and repair of this instrument. Failure to comply with these precautions or with specific WARNINGS elsewhere in this manual may impair the protection provided by the equipment. In addition it violates safety standards of design, manufacture, and intended use of the instrument.

The Agilent Technologies assumes no liability for the customer's failure to comply with these requirements.

Ground The Instrument

To avoid electric shock hazard, the instrument chassis and cabinet must be connected to ^a safety earth ground by the supplied power cable with earth blade.

DO NOT Operate In An Explosive Atmosphere

Do not operate the instrument in the presence of flammable gasses or fumes. Operation of any electrical instrument in such an environment constitutes ^a denite safety hazard.

Keep Away From Live Circuits

Operating personnel must not remove instrument covers. Component replacement and internal adjustments must be made by qualied maintenance personnel. Do not replace components with the power cable connected. Under certain conditions, dangerous voltages may exist even with the power cable removed. To avoid injuries, always disconnect power and discharge circuits before touching them.

DO NOT Service Or Adjust Alone

Do not attempt internal service or adjustment unless another person, capable of rendering first aid and resuscitation, is present.

DO NOT Substitute Parts Or Modify Instrument

Because of the danger of introducing additional hazards, do not install substitute parts or perform unauthorized modifications to the instrument. Return the instrument to a Agilent Technologies Sales and Service Office for service and repair to ensure that safety features are maintained.

Dangerous Procedure Warnings

ware examples , such as the example below, precedent as the example procedures throughout the word was assembly when this manual. Instructions contained in the warnings must be followed.

Warning Dangerous voltages, capable of causing death, are present in this instrument. Use extreme caution when handling, testing, and adjusting Ů this instrument.

Safety Symbols

General definitions of safety symbols used on equipment or in manuals are listed below.

Instruction manual symbol: the product is marked with this symbol when it is necessary for the user to refer to the instruction manual. Alternating current. Direct current. \mathbf{I} On (Supply). Off (Supply). In position of push-button switch. Out position of push-button switch. Frame (or chassis) terminal. ^A connection to the frame (chassis) of the equipment which normally include all exposed metal structures. **Warning** This Warning sign denotes ^a hazard. It calls attention to ^a procedure, practice, condition or the like, which, if not correctly performed or adhered to, could result in injury or death to personnel. This Caution sign denotes ^a hazard. It calls attention to ^a procedure, practice, **Caution** condition or the like, which, if not correctly performed or adhered to, could result in damage to or destruction of part or all of the product. This Note sign denotes important information. It calls attention to ^a **Note** procedure, practice, condition or the like, which is essential to highlight. Affixed to product containing static sensitive devices use anti-static handling procedures to prevent electrostatic discharge damage to component.

Typeface Conventions

Documentation Map

The following manuals are available for the analyzer.

Operation Manual (Option ABA only) (Agilent Part Number 04395-900x0)

The Operation Manual describes all function accessed from the front panel keys and softkeys. It also provides information on options and accessories available, specifications, system performance, and some topics about the analyzer's features.

Programming Manual (Option ABA only) (Agilent Part Number 04395-900x1)

The Programming Manual shows how to write and use BASIC program to control the analyzer and describes how Instrument BASIC works with the analyzer..

Instrument BASIC Users Handbook (Option ABA only) (Agilent Part Number 04155-9015x)

The Instrument BASIC User's Handbook introduces you to the Instrument BASIC programming language, provide some helpful hints on getting the most use from it, and provide ^a general programming reference. It is divided into three books, Instrument BASIC Programming Techniques, Instrument BASIC Interface Techniques, and Instrument BASIC Language Reference.

Service Manual (Option 0BW only), (Agilent Part Number 04395-901x0)

The Service Manual explains how to adjust, troubleshoot, and repair the instrument. This manual is option 0BW only.

The number indicated by " x " in the part number of each manual, is allocated for numbers increased by one each time ^a revision is made. The latest edition comes with the product.

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7. Calibration

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Introduction

About the 4395A Network/Spectrum/Impedance Analyzer

The 4395A Network/Spectrum/Impedance Analyzer provides excellent vector network and spectrum measurement performance from 10 Hz to 500 MHz. Providing both network and spectrum measurement capabilities, the 4395A is a cost effective solution for the development and production testing of electronic devices.

Optionally, the 4395A can serve as an impedance analyzer as well. This requires Option ⁰¹⁰ and the 43961A Impedance Test Kit.

About This Guide

This guide is the Operation Manual for the 4395A. It includes the following chapters/appendixes:

Document Guide

For information on using GPIB commands to program the 4395A, refer to Programming Manual, which contains ^a complete command reference with ready-to-use sample programs.

Installation Guide

This chapter provides installation and setup instructions. It contains the following information:

- **Incoming Inspection**
- **Replacing Fuse**
- **Power Requirements**
- Operation Environment
- Providing clearance to dissipate heat at installation site
- Instruction for Cleaning
- Rack/Handle Installation
- Connecting Cables
- Connecting ^a Test Set for Network Analyzer Mode
- \blacksquare Connecting an Active Probe
- Connecting an Impedance Test Kit and ^a Test Fixture \blacksquare
- Connecting a Keyboard
- Setting Up ^a ⁷⁵ Measurement For Spectrum Analyzer Mode

Incoming Inspection

V3

Warning To avoid hazardous electrical shock, do not turn on the 4395A when there are signs of shipping damage to any portion of the outer enclosure (for example, covers, panel, or display)

Inspect the shipping container for damage. If the shipping container or cushioning material is damaged, it should be kept until the contents of the shipment have been checked for completeness and the 4395A has been checked mechanically and electrically. The contents of the shipment should be as listed in Table 2-1. If the contents are incomplete, if there is mechanical damage or defect, or if the 4395A does not pass the power-on selftests, notify the nearest Agilent Technologies office. If the shipping container is damaged, or the cushioning material shows signs of unusual stress, notify the carrier as well as the Agilent Technologies office. Keep the shipping materials for the carrier's inspection.

Description	Agilent Part Number	Quantity
Network/Spectrum/Impedance Analyzer	4395A	1
CD-ROM (Manuals)	$04395.905xx^1$	1
Sample Program Disk (2 disks)	04395-180x0	1
Power Cable ²		1
Option ABA only		
Operation Manual	04395.900×01	1
Programming Manual	04395.900x1 ¹	$\mathbf{1}$
Instrument BASIC Users HandBook	04155-90151	1
Option 810 only		
mini-DIN Keyboard		$\mathbf 1$
Option 010 only		
BNC(m)-BNC(m) Cable	8120-1839	$\mathbf{1}$
Option 0BW only		
Service Manual	04395.901x01	$\mathbf{1}$
Option 1D5 only		
BNC Adapter	1250-1859	1
Option 1D7 only		
$50\Omega/75\Omega$ Minimum Loss Pad	11852B option 004	$\mathbf{1}$
Option 1CN Handle Kit		
Handle Kit	5062-3991	$\mathbf{1}$
Option 1CM Rack Mount Kit		
Rack Mount Kit	5062-3979	$\mathbf{1}$
Option 1CP Rack Mount & Handle Kit		
Rack Mount & Handle Kit	5062-3985	1

Table 2-1. Contents

1 The number indicated by "x" in the part number of each manual, is allocated for numbers increased by one each time a revision is made. The latest edition comes with the product.

² The power cable depends on where the instrument is used,see Figure 2-1.

Fuse Selection

Select proper fuse according to the Table 2-2.

For ordering the fuse, contact your nearest Agilent Technologies Sales and Service Office.

Procedure

Lever ^a small minus screwdriver to dismount the fuse holder above the AC line receptacle on the rear panel.

To check or replace the fuse, pull the fuse holder and remove the fuse. To reinstall the fuse, insert a fuse with the proper rating into the fuse holder.

Caution Use the proper fuse for the line voltage selected. Use only fuses with the required current rating and of the specied type as replacements. DO NOT use a mended fuse or short-circuit the fuse-holder in order to by-pass a blown fuse. Find out what caused the fuse to blow!

Power Requirements

The 4395A requires the following power source:

Voltage :90 to 132 Vac, 198 to 264 Vac

Frequency : ⁴⁷ to 63 Hz

Power : ³⁰⁰ VA maximum

Power Cable

In accordance with international safety standards, this instrument is equipped with ^a

three-wire power cable. When connected to an appropriate ac power outlet, this cable grounds the instrument frame.

The type of power cable shipped with each instrument depends on the country of destination. Refer to Figure 2-1 for the part numbers of the power cables available.

Warning For protection from electrical shock, the power cable ground must not be defeated.

> The power plug must be plugged into an outlet that provides ^a protective earth ground connection.

Figure 2-1. Power Cable Supplied

Operation Environment

The 4395A must be operated under within the following environment conditions, and sufficient space must be kept behind the $4395A$ to avoid obstructing the air flow of the cooling fans.

Providing clearance to dissipate heat at installation site

To ensure the specications and measurement accuracy of the product, you must keep ambient temperature around the product within the specied range by providing appropriate cooling clearance around the product or, for the rackmount type, by forcefully air-cooling inside the rack housing. For information on ambient temperature to satisfy the specications and measurement accuracy of the product, refer to Chapter 11, Specifications and Supplemental

When the ambient temperature around the product is kept within the temperature range of the operating environment specification (refer to "Operating Conditions" in Chapter 11), the product conforms to the requirements of the safety standard. Furthermore, under that temperature environment, it has been confirmed that the product still conforms to the requirements of the safety standard when it is enclosed with cooling clearance as follows:

Table 2-3.

Instruction for Cleaning

To prevent electrical shock, disconnect the 4395A power cable from the receptacle before cleaning. Wipe with a dry cloth or a soft cloth that is soaked with water and wrung tightly without undue pressure to clean the casing. Do not attempt to clean the 4395A internally.

Rack/Handle Installation

The 4395A can be rack mounted and used as a component in a measurement system. Figure 2-2 shows how to rack mount the 4395A.

Option	Description	Agilent Part Number
1CN	Handle Kit	5062-3991
1 CM	Rack Mount Kit	5062-3979
1 C P	Rack Mount & Handle Kit	5062-3985

Table 2-4. Rack Mount Kits

Figure 2-2. Rack Mount Kits Installation

Option 1CN Handle Kit

Option 1CN is a handle kit containing a pair of handles and the necessary hardware to attach them to the instrument.

Installing the Handle

- 1. Remove the adhesive-backed trim strips (1) from the left and right front sides of the 4395A.
- 2. Attach the front handles $\circled{3}$ to the sides using the screws provided.
- 3. Attach the trim strips ϕ to the handles.

Option 1CM Rack Mount Kit

Option 1CM is a rack mount kit containing a pair of flanges and the necessary hardware to mount them to the instrument in an equipment rack with 482.6 mm (19 inches) horizontal spacing.

Mounting the Rack

- 1. Remove the adhesive-backed trim strips $\textcircled{1}$ from the left and right front sides of the 4395A.
- 2. Attach the rack mount flange Q to the left and right front sides of the 4395A using the screws provided.
- 3. Remove all four feet (lift bar on the inner side of the foot, and slide the foot toward the bar).

Option 1CP Rack Mount & Handle Kit

Option 1CP is a rack mount kit containing a pair of flanges and the necessary hardware to mount them to an instrument which has handles attached, in an equipment rack with 482.6 mm (19 inches) spacing.

Mounting the Handle and Rack

- 1. Remove the adhesive-backed trim strips (1) from the left and right front sides of the 4395A.
- 2. Attach the front handle \mathcal{I} and the rack mount flange \mathcal{I} together on the left and right front sides of the 4395A using the screws provided.
- 3. Remove all four feet (lift bar on the inner side of the foot, and slide the foot toward the bar).

Connecting Cables

Use shielded cables when you connect the DUT and accessories for testing.

For more information about the cables, see chapter 12.

Connecting a Test Set for Network Analyzer Mode

To use the network analyzer mode of the 4395A, a test set is required to measure the transmission and reflection characteristics of the device under test (DUT).

You can use either the $87512A/B$ transmission/reflection (T/R) test set or the $87511A/B$ S-parameter test set. The 87512A/B T/R test set measures reflection and transmission in the forward direction only. The 87511A/B S-parameter test set measures both the forward and reverse directions without reconnection.

For more information about the test sets, see Chapter 12.

Connecting a Transmission/Reflection Test Set

Figure 2-3. Connecting a Transmission/Reflection Test Set

- 1. Place the transmission/reflection (T/R) test set in front of the 4395A.
- 2. Connect the R and A ports of the 4395A and the T/R test set to each other.
- 3. Connect the RF OUT port of the 4395A and the RF IN port of the T/R test set with a semi-rigid cable.

 \mathbf{N} MORE SET ZO. Then press $\lceil 7 \rceil \lceil \overline{5} \rceil \lceil \overline{21} \rceil$ to set the characteristic impedance $\left(\omega_0 \right)$ to ω .

Figure 2-4. Connecting an S-parameter Test Set

- 1. Place the 4395A on the S-parameter test set.
- 2. Connect the TEST SET-I/O INTERCONNECT interface on the rear panel of the 4395A and the NETWORK ANALYZER-I/O INTERCONNECT interface of the test set using the cable furnished with the test set.
- 3. Connect the RF OUT, R, A, and ^B inputs of the 4395A to the S-parameter test set to each other.

Connecting an Active Probe

The active probe allows you to analyze an in-circuit signal or device that has no port for connecting to the test set. The active probe can be used for both spectrum and network

The 4395A can use the following active probes:

- \blacksquare 41800A Active Probe (5 Hz to 500 MHz)
- 11802 and 1110 and 10000 in 10000 in 1000

For more information about these active probes, see Chapter 12.

For Spectrum Analyzer Mode

Figure 2-5. Spectrum Analyzer Mode (One Active Probe)

- 1. Connect the output connector of the active probe to the R,A,or B port of the 4395A.
- 2. Plug the probe power plug into the PROBE POWER connector.

For Network Analyzer Mode

Using One Active Probe

Figure 2-6. Network Analyzer Mode (One Active Probe)

- 1. Connect the power splitter to the RF OUT port.
- 2. Connect one output from the power splitter to the R input.
- 3. Connect the other output of the power splitter to the DUT.
- 4. Connect the active probe to the ^B input and plug the probe plug into the PROBE POWER connector.
- 5. If necessary, terminate the DUT with ^a load.

Note The following power splitters are available for the 4395A:

-
- 11850C,D Three-way Power Splitter
- 11667A Two-way Power Splitter

For more information about these power splitters, see Chapter 12.

Connecting an Active Probe

Using Two Active Probes

Figure 2-7. Network Analyzer Mode (Two Active Probes)

- 1. Connect one active probe to the ^R input.
- 2. Connect the other active probe to the ^B input.
- 3. Connect the RF OUT port to the DUT.
- 4. If necessary, terminate the DUT with ^a load.

Using a Transmission/Reflection Test Set

Figure 2-8. Using a Transmission/Reflection Test Set

- 1. Connect the 87512A/B T/R test set.
- 2. Connect the active probe to the ^B input.
- 3. If necessary, terminate the DUT with ^a load.

Connecting an Impedance Test Kit and ^a Test Fixture for Impedance Analyzer Mode

Connecting an Impedance Test Kit

To start the impedance measurement, you need to connect the 43961A Impedance Test Kit to the 4395A. See Figure 2-9.

- 1. Verify the $4395A$ is turned off.
- 2. Connect the N-cable to the RF OUT port of the 4395A.
- 3. Connect two connectors of the 43961A to the ^R and ^A ports of the 43961A.
- 4. Connect the other connector of the N-cable to the RF IN port of the 43961A.
- 5. Turn on the 4395A.

Figure 2-9. Connecting the Impedance Test Kit

Connecting a Test Fixture to the Impedance Test Kit

To connect the test fixture to the impedance test kit, see the applicable test fixture manual for instructions. The following is a general procedure:

- 1. Turn the APC-7 connector of the impedance test kit OUTPUT port.
- 2. Verify that the connector sleeve is retracted fully.
- 3. Set the mounting posts of the test station into the twin locating holes at the corner of the test fixture.
- 4. Connect the connector on the underside of the test fixture to the OUTPUT port of the impedance test kit.

Figure 2-10. Connecting Test Fixture

Connecting a Keyboard

An mini-DIN keyboard can be connected to the mini-DIN connector on the rear panel of the 4395A. The mini-DIN keyboard provides an easier way to enter characters for the file names, display titles, and Instrument BASIC programs. It can also access the 4395A softkey functions by using keyboard function keys. For more information on the mini-DIN keyboard, see Programming Manual.

Figure 2-11. Connecting ^a Keyboard

Setting Up a 75 Measurement For Spectrum Analyzer Mode

ud

Note This operation requires the option 1D7 50 to 75 Input Impedance Conversion. For detail information about option 1D7, see Chapter 12.

- 1. Attache the 11852B Option 004 60 minimal to minimum loss pad to B, A, Or B input.
- 2. Press (Cal).
- 3. Press INPUT Z .
- 4. Press * to set the impedance of the source (75). Then press Entry O.
- 5. Select the input port:

 σ . Enter the most don loss of the minimum loss pad in db and press μ , μ

Note Perform this procedure each time the 4395A is preset because the 4395A does not retain this setting in memory.

Quick Start Guide

Network Analyzer Tour

In this section, you explore the network analyzer mode of operation. Before starting this tour, verify that the 4395A is correctly installed (see chapter 2, "Installation Guide," if you need additional information).

Before You Leave On The Tour

On this tour, you will learn how to make ^a basic network analyzer measurement by measuring the transmission characteristics of a bandpass filter.

The following is ^a short summary of the tour:

- 1. Preparing for ^a measurement
	- Turning ON the 4395A
	- Connecting the DUT
- 2. Setting up the 4395A
	- Selecting the analyzer type
	- Setting the active channel
	- Setting the input port
	- Setting the frequency range
	- **Performing the automatic scaling**
- 3. Making ^a calibration
- 4. Reading a measurement result
	- Reading a measured value by using marker
- 5. Printing out the measurement result
	- \blacksquare Configuring and connecting a printer
	- Making a hardcopy of the display

After you finish this tour, you will understand how to make a basic measurement in the network analyzer mode of operation.

Required Equipments

To perform all the steps in this tour, you must have the following equipments:

- 4395A Network/Spectrum/Impedance Analyzer
- **Measurement Device:**
	- \Box This tour assumes the device under test (DUT) is a 70 MHz bandpass filter
- THRU (BNC female-to-female connector)
- **Two BNC cables**
- Test Set (use either of the following)
	- \Box Transmission/Reflection (T/R) Test Set
		- Two N-to-BNC adapters
	- S-Parameter Test Set
		- Two APC7-to-N adapters
		- Two N-to-BNC adapters
- \blacksquare HP DeskJet Printer
- Parallel Interface Cable ^{*}

* If you wish to test some other device, you will need to change particular measuring conditions, such as the frequency range, according to the general characteristics of the DUT.

* If you do not have an HP DeskJet printer and cable, skip step 5, \Printing Out the Measurement Results".

Figure 3-1. Required Equipment

Step 1: Preparing for the Measurement

You must set up the test set before you turn ON the 4395A. The setup procedure for the test set is described in "Connecting a Test Set for Network Analyzer Mode" in Chapter 2.

Turning ON the 4395A

The 4395A performs ^a power on self-test. About ²⁰ seconds later, the model name, revision number, and other information should appear on the LCD to indicate that the 4395A has normally started up.

Connecting the DUT

Connect the DUT as shown in Figure 3-2 or Figure 3-3.

Figure 3-2. Transmission/Reflection Test Set Setup

Figure 3-3. S-Parameter Test Set Setup
Step 2: Setting up the 4395A

Before you start the measurement, you must set up the 4395A to fit your measurement requirements. For example, you must set the frequency range of the measurement. In this step, you will set the following parameters:

Setting the Analyzer Type

To use the 4395A in the network analyzer mode, you must set the analyzer type to the network analyzer mode after selecting the active channel.

In the MEASUREMENT block, press [Meas]. Press ANALYZER TYPE .

Press NETWORK ANALYZER.

Setting the Active Channel

Because the 4395A has two measurement channels you can have two different measurement setups at the same time. To change the active channel to channel 1:

Note Changing the analyzer type presets the 4395A for the active channel. If you want to keep the current measurement settings when changing the analyzer type, first set the other channel to active.

Selecting the Input

The 4395A uses three inputs for network measurements (R, A, and B). Usually, the ^R input is connected to the RF OUT signal directly, the A input measures the reflected signal from the DUT, and the ^B input measures the signal through the DUT.

This example assumes you are using the T/R test set. Therefore, because you are going to measure the transmission characteristics of the DUT, select B/R to measure the ratio of ^B and ^R inputs.

When you use the S-parameter test set, you can measure the forward and reverse characteristics of a 2-port device without reconnecting the inputs. In that case, select S_{21} for a transmission measurement in the forward direction.

Setting the Frequency Range

To display the transmission characteristics of the 70 MHz bandpass filter, you should specify the frequency range for the measurement. In this example, set the 4395A to ^a ⁷⁰ MHz center frequency with a 500 kHz span.

Performing the Automatic Scaling

Often, the trace obtained after specifying the frequency range is too large or too small vertically for the grid. However, by using the automatic scaling function, you can obtain the optimum vertical setting automatically.

The transmission characteristics trace of the filter is displayed as shown below:

All the settings are displayed on the LCD.

- 1. Active channel is set to channel 1.
- 2. Inputs are set to B/R.
- 3. Format is set to log magnitude mode.
- 4. Center frequency is set to 70 MHz.
- 5. Frequency span is set to 500 kHz.

Step 3: Making a Calibration

To ensure accurate measurement results, calibrate the 4395A before making a measurement. Calibration reduces error factor due to uncertainty. In this example, you perform the response calibration to cancel ^a frequency response error. A THRU (BNC female-to-female connector) is necessary to perform ^a response calibration for the transmission measurement.

Performing ^a Response Calibration (for the Transmission Measurement)

Press THRU . WAIT - MEASURING CAL STANDARD is displayed.

Press DONE: RESPONSE.

The THRU softkey label is underlined when the measurement is completed.

Disconnect the THRU and reconnect the DUT.

"Cor" is displayed on the left side of the display to show that the frequency response error is corrected.

The measured value is now corrected for the frequency response error.

Note If the trace is changed, it requires an adjustment of the scale. Perform the automatic scaling again by pressing Scale Ref

Step 4: Reading a Measurement Result

You may want to readout the measured values on the displayed trace. You can use the marker function for this purpose. The marker shows the frequency and response value at the marker point.

Reading a Measured Value by Using Marker

In the MARKER block, press $\overline{\text{Market}}$. Verify a marker appears on the trace.

Turn the knob to the right to move the marker toward the right.

Read the values at the right top of the display.

The marker has a search function that makes it easier and faster to evaluate the trace results. For example, to search for the maximum value and its frequency on the trace:

maximum point on the displayed trace. Also displayed at the inper right of the display.

Step 5: Printing Out the Measurement Result

You may want a hardcopy of the measured results for a permanent record of the measurement. The 4395A can print out the data as a snapshot of the display or as a list of values without using any external controller.

Conguring and Connecting ^a Printer

Locate the parallel interface connector on the back of the 4395A.

Making ^a Hardcopy of the LCD Display

Spectrum Analyzer Tour

In this section, you explore the spectrum analyzer mode of operation. Before starting this tour, verify the 4395A is correctly installed (see chapter 2, "Installation Guide," if you need additional information).

Before You Leave On The Tour

On this tour, you will learn how to make a basic spectrum analyzer measurement by measuring the output signal of ^a signal generator.

The following is a short summary of the tour:

- 1. Preparing for a measurement
	- Turning ON the 4395A
	- Connecting the test signal source
- 2. Setting up the 4395A
	- \blacksquare Selecting the analyzer type
	- Setting the active channel
	- \blacksquare Selecting the input
	- Setting the frequency range
- 3. Making ^a Measurement
	- Reading the peak level using the marker
	- Setting the resolution bandwidth to see low level signals
	- Searching for harmonics using the search function
- 4. Saving and recalling the 4395A settings
	- \blacksquare Preparing the disk
	- \blacksquare Saving 4395A settings
	- \blacksquare Entering the file name
	- Recalling the 4395A settings

After you finish this tour, you will understand how to make a basic measurement in the spectrum analyzer mode of operation.

Spectrum Analyzer Tour

Required Equipments

To perform all the steps in this tour, you must have the following equipments:

- 4395A Network/Spectrum/Impedance Analyzer
- Test signal source $(-20dBm, 20MHz, sine wave)$ ^{**} \blacksquare
- ^N to BNC Adapter (50)
- **BNC** cable
- 3.5 inch 2HD Blank Disk

** If you wish to test some other test signal, you will need to change particular measuring conditions, such as the frequency range, according to the general characteristics of the signal.

Figure 3-4. Required Equipments

Step 1: Preparing for a Measurement

Turning ON the 4395A

Verify the power source setting is correct before you turning ON the 4395A. If necessary, see chapter 2, "Installation Guide."

Press the LINE switch

The 4395A performs ^a power on self-test. About 20 seconds later, the model name, revision number, and other information should appear on the LCD to indicate that the 4395A has normally started up.

Connecting the DUT

Connect the test signal source $(-20$ dBm, 20 MHz) to Input R of the 4395A.

Step 2: Setting Up the 4395A

In this step, you will set the following parameters:

Setting the Analyzer Type

To use the spectrum analyzer mode, you must set the analyzer type to the spectrum analyzer mode after selecting an active channel.

Press SPECTRUM ANALYZER

Note Changing the analyzer type presets the 4395A for the active channel. If you want to keep the current measurement settings when changing the analyzer type, first set the other channel to active.

Setting the Active Channel

The 4395A has two measurement channels. This allows you to have two different measurement setups. Other selections you make on the front panel affect only the active channel. To set the active channel to channel 2:

Note All selected settings are stored separately for each channel. You must select an active channel (1 or 2) before you can change the measurement setup for that channel.

Selecting the Input

The 4395A has three inputs; R, A, and B. Any of the inputs (R, A, or B) can be used for ^a spectrum measurement.

In the spectrum analyzer mode, the ^R input is selected by default. In the following steps, you verify the ^R input is selected.

In the MEASUREMENT block, press $(Meas)$. Verify the R in SPECTRUM: R is underlined. (This shows that the R input is selected for a spectrum analyzer measurement.)

Setting the Frequency Range

The CAL OUT signal (20 MHz at -20 dBm) is connected as test signal source. To see this signal on display, you must set the appropriate frequency range (in this case, 0 to 80 MHz):

Verify the 20 MHz signal is displayed as shown below:

Step 3: Making a Measurement

Reading the Peak Level Using the Marker

Let's try to read peak signal level by using the marker:

 $\frac{z}{Hz}$

Press SEARCH:PEAK . Marker moves to the top of the CAL OUT signal.

Read the marker value shown at the upper right of grid.

Setting the Resolution Bandwidth to See Low Level Signals

To see lower level signals that are approximately the same level as the noise floor, use a narrow resolution bandwidth (RBW) setting.

Before you set the RBW, set the maximum peak level as the reference level. This increases the visibility of the lower level signal. This technique is useful when you are measuring two signals and one is very close to the noise level.

The trace moves upward to place the tip of the maximum peak at the top line of the grid.

Now, with the noise floor level lowered by narrowing the resolution bandwidth, the second and third harmonics can be seen as shown below:

Searching for Harmonics Using the Search Function

You can easily readout ^a harmonics' frequency and level by using the peak search function:

10 dB/ REF -20.6 dBm 73.904 dBm ctru вb MH An Malnach und Syndystheodological probabilistic technical probabilistic descriptions of the special control o

To move the marker to the second (or third) harmonic, press NEXT PEAK again.

Step 4: Saving and Recalling 4395A Settings

You can store the settings or measurement data on a 3.5 inch disk using the 4395A's disk drive. In this tour, you save and recall the settings that you selected previously in this tour.

Preparing the Disk

To use a disk, you must first initialize it by performing the following steps:

Verify the disk is not write protected. Insert the disk into the disk drive

Press (Save). Press FILE UTILITIES .

Note The 4395A can initialize a 1.44 MB 3.5 inch flexible disk only.

Saving 4395A Settings

In the following example, use "SATOUR" as the file name of the 4395A settings you want to save.

The 4395A requests the file name you want to use for the saved settings.

Entering the File Name

Note If a keyboard is connected, you can use it for file name entry. If not, use the front-panel controls as described in the following steps.

Step 4: Saving and Recalling 4395A Settings

2 **SELECT** LETTER **SPACE RACK** SPACE **ERASE TITLE**

Turn the rotary knob to move the arrow below the first character, S.

If you enter ^a wrong character, press BACK SPACE to erase the character.

To complete the file name entry, press DONE . Verify the disk access indicator lights (this

shows that the 4395A is saving the settings to the disk).

Note The file name for a LIF format can be up to 10 characters long. However, with the $4395A$, the last 2 characters are reserved for a suffix. Therefore, you can enter a file name of up to 8 characters. Either upper or lower case is recognized in the LIF format.

> A file name for a MS-DOS(DOS) format consists of a file name and an extension. The file name can be up to 8 characters long and the extension contains up to 3 characters. A period separates the extension from the file name. The extension

part reserved by the 4395A. Therefore, you can enter a file name of up to 8 characters. The file name is not case sensitive in the DOS format.

Recalling the 4395A Settings

You can recall the file containing the saved 4395A settings anytime you want. This is true, even if you change the current 4395A settings. In this example, you will preset the 4395A and then recall the settings in the SATOUR file.

Presetting

The 4395A isset to the preset conditions. However, the 4395A settings from the previous examples are stored in the SATOUR file on the disk.

Step 4: Saving and Recalling 4395A Settings

Recalling the SATOUR file.

Press (Recall). The disk access lamp lights.

The stored file is listed in the softkey label area. Press $\texttt{SATOUR_S}$ to recall the $4395\textnormal{A}$ settings that you saved.

Note Suffix, "_S," means the 4395A settings are saved. If you save the 4395A settings in a DOS format, an extension, ".sta," is appended to the file name.

After the disk access lamp goes out, all 4395A settings that you set are recalled. You can verify them on the display. If you want to know what settings are saved, see chapter 8.

Impedance Analyzer Tour

In this section, you explore the impedance analyzer mode of operation. Before starting this tour, make sure that your 4395A is correctly installed (see chapter 1, "Installation and Setup Guide," if you need additional information).

U.

Note Your 4395A must be equipped with option 010 to serve as an impedance analyzer. Otherwise, impedance analyzer mode is not available.

Before You Leave On The Tour

Through this tour, you will learn how to make a basic impedance analyzer measurement by measuring the impedance characteristics of a chip capacitor.

Overview

The following is ^a short summary of the tour:

- 1. Preparing for ^a measurement
	- Connecting the impedance test kit
	- Turning ON the 4395A
- 2. Setting up the 4395A
	- \blacksquare Selecting the analyzer type
	- Activating Channel 1
	- \blacksquare Setting the sweep parameters
	- Setting the output level
	- Setting the IF bandwidth
- 3. Calibrating the 4395A
	- OPEN calibration
	- **SHORT** calibration
	- **LOAD** calibration
- 4. Connecting and setting up a test fixture
	- \blacksquare Connecting the fixture
	- Setting the electrical length
	- **Fixture compensation**
- 5. Carrying out impedance measurement
	- Selecting the measurement parameters for Channel 1
	- Connecting the DUT
	- **Performing the Automatic Scaling**
- 6. Switching from Channel 1 to Channel 2
- 7. Selecting the measurement parameters for Channel 2
- 8. Dual channel display

Impedance Analyzer Tour

After you finish this tour, you will understand how to make a basic measurement in impedance analyzer mode. If you want to learn how to perform more complex tasks, refer to Chapters ⁵ through 9.

Required Equipments

To perform all the steps in this tour, you must have the following equipments:

Figure 3-5. Required Equipments

- 1. 4395A Network/Spectrum/Impedance Analyzer with Option ⁰¹⁰ equipped
- 2. 43961A Impedance Test Kit
- 3. Calibration kit (included in the 43961A)
- 4. Test fixture of your choice
- 5. Short device for the test fixture
- 6. DUT (chip capacitor)*

If you wish to test some other device instead of a chip capacitor, you will need to change particular measuring conditions, such as the frequency range, according to the general characteristics of the DUT.

Step 1: Preparing for the Measurement

Connecting the Impedance Test Kit

The 4395A requires the 43961A Impedance Test Kit to apply signals to, and measure the impedance characteristics of, ^a DUT (see Figure 3-6). To connect the 43961A Impedance Test Kit, follow these steps:

Figure 3-6. Connecting the Impedance Test Kit

- 1. Make sure that the power to the 4395A is OFF.
- 2. Connect the N-N cable to the 4395A's RF OUT port.
- 3. Make sure that the 43961A's APC7 connector sleeve is completely exposed.
- 4. Connect the two connectors of the 43961A to the ^R and A ports of the 4395A, by tightening the two connectors little by little alternately while holding the test kit.
- 5. Connect the other end of the N-N cable to the RF IN port of the 43961A.

Turning ON the 4395A

Verify the power source setting is correct before you turning ON the 4395A. If necessary, see chapter 2, "Installation Guide."

Press the power switch.

The 4395A performs ^a power on self-test. About ²⁰ seconds later, the model name, revision number, and other information should appear on the LCD to indicate that the 4395A has normally started up.

Setting Up the 4395A Setting the Analyzer Type

Available analyzer modes are listed in the menu under the ANALYZER TYPE softkey. You can use the 4395A as an impedance analyzer by selecting the corresponding analyzer mode from that menu. Follow these steps:

Choose ANALYZER TYPE.

Press the (Meas) key in the MEASRUREMENT block.

Choose IMPEDANCE ANALYZER.

Activating Channel ¹

The 4395A has two channels, each of which can retain different measuring conditions. To demonstrate how effectively you can use these two channels to perform impedance measurement, this tour uses the following scenario:

- 1. Activate Channel 1, and set the parameters that apply to Channel ¹
- 2. Switch to Channel 2, and set the parameters that apply to Channel 2 (see "Step 6: Switching from Channel ¹ to Channel 2")
- 3. Display both channels in parallel (see "Step 8: Dual Channel Display")

First, activate Channel ¹ through these steps:

Press the $(\overline{Chan 1})$ key in the ACTIVE CHANNEL block.

Make sure that the indicator lamp beside the $\overline{\text{Chan 1}}$ key is ON.

Impedance Analyzer Tour

Setting the Sweep Parameters

This tour assumes that the frequency is being swept from ¹⁰⁰ kHz to ⁵⁰⁰ MHz.

Follow these steps:

Press the (Sweep) key. Choose SWEEP TYPE MENU to access the sweep type menu.

Choose LOG FREQ to have the 4395A accept log frequency settings.

To specify the frequency at which to start the sweep, enter $[1]$ $[0]$ $[0]$ using the numeric keys.

Press the $\overline{k/m}$ key to indicate that the unit is $\overline{\text{kHz}}$.

To specify the frequency at which to stop the sweep, enter $[5]$ $[0]$ $[0]$ using the numeric keys.

Setting the Output Level

This tour assumes an output level of $+0.5$ dBm.

Follow these steps:

Setting the IF Bandwidth

This tour assumes an IF bandwidth of ³⁰⁰ Hz. Follow these steps:

Setting the Averaging Factor

This tour assumes the averaging factor of 8.

Follow these steps:

ud

Note When you perform impedance measurement with the 43961A, you must set IF bandwidth equal to or less than 300 Hz and averaging factor equal to or greater than 8.
Step 3: Making ^a Calibration

Calibrating the 4395A in impedance analyzer mode requires that the 4395A be connected with the 43961A impedance test kit. ^A proper calibration is required for the 4395A to perform measurements within the guaranteed accuracy range.

For impedance analyzer mode, the 4395A must be calibrated for each of the following three circuit states:

- \blacksquare OPEN (0 S termination)
- SHORT (0 termination)
- LOAD (50 termination)

To calibrate the 4395A, access the calibration menu through these steps:

With the calibration menu displayed on the LCD screen, calibrate the 4395A for the OPEN, SHORT, and LOAD states in order.

Note Be sure to use the calibration kit included in the 43961A package.

Œ

OPEN Calibration

Connect the ⁰ ^S termination to the 43961A's OUTPUT port.

Wait until the OPEN softkey's label is underlined to indicate that the OPEN calibration is complete.

Remove the ⁰ ^S termination.

SHORT Calibration

43961A's OUTPUT port.

Press SHORT.

Wait until the SHORT softkey's label is underlined to indicate that the SHORT calibration is complete.

remove the communication.

LOAD Calibration

the 43961A's OUTPUT port.

Wait until the LOAD softkey's label is underlined to indicate that the LOAD calibration is complete.

Choose DONE: CAL . Make sure that a "Cor" marker is displayed at the left-hand edge of the screen.

Remove the 50 termination.

Step 4: Connecting and Setting Up ^a Test Fixture

Connecting the fixture

This tour does not assume any specific test fixture. You can use a test fixture of your choice. For how to connect your test fixture to the impedance test kit, refer to the documentation that comes with the test fixture. A typical test fixture can be installed in such a procedure as shown below:

- 1. Turn the OUTPUT port APC-7 connector of the impedance test kit.
- 2. Make sure that the connecting sleeve is completely retracted.
- 3. Set the test station's mount post to the pair of holes located at one corner of the test fixture.
- 4. Turn the fixing ring counterclockwise until it is fully tightened.
- 5. Connect the impedance test kit's OUTPUT port to the connector located on the back side of the test fixture.

Figure 3-7. Connecting the test fixture

Setting the Electrical Length

Connecting a test fixture adds an extra electrical length to the test circuit. This electrical length, which is specific to the test fixture you use, must be known to the 4395A so that it can compensate for the extra electrical length and eliminate errors due to phase shifts.

The 4395A incorporates a database of Agilent test fixtures with their own electrical lengths.

For example, if the model number of your test fixture is 16192 , you would set the electrical length as follows:

Press the (Meas) key. Choose FIXTURE .

Choose SELECT FIXTURE . Select 16192.

4 FIXTURE:
NONE 16191 16192 16193

Press RETURN twice. Make sure that the FIXTURE label on the screen is followed by your selected model number (16192, in this case).

Fixture Compensation

Fixture compensation is a process that calibrates the 4395A with a test fixture installed, thereby eliminating errors produced between the test fixture electrode and the impedance test kit's OUTPUT port. Normally, the 4395A must be fixture-compensated for the OPEN and SHORT circuit states. It can optionally be fixture-compensated for the LOAD state.

Note For how to connect standards, refer to the documentation that comes with the test fixture you use. ud

Connect the appropriate short Connect the appropriate short Press the $\overline{\text{Cal}}$ key.
device to the fixture.

4 **COMPEN MENU**

Choose SHORT.

Wait until the SHORT softkey's label is underlined to indicate that the SHORT compensation is complete.

Remove the short device to put the circuit into the OPEN state.

Choose OPEN.

Wait until the OPEN softkey's label is underlined to indicate that the OPEN compensation is complete.

Make sure that a "Cmp" marker is displayed in place of the "Cor" marker.

Step 5: Carrying Out Impedance Measurement

Selecting the Measurement Parameters for Channel ¹

To begin impedance measurement, the 4395A must know which characteristics it should measure and how it should report the measured values. This tour assumes that the following measurement parameters are specied for Channel 1.

Characteristic Libbolate rante of impedance ([Zj) value

Format Log

To set the parameters listed above, follow these steps:

These settings are applied to Channel 1, which has been the active channel in the scenario of this tour. Note that, in Steps ⁶ and 7, you will switch from Channel ¹ to Channel 2, and assign different settings to Channel 2.

Connecting the DUT

How to connect a DUT differs depending on which test fixture you use. For more information, refer to the documentation that comes with your test fixture.

As soon as you have connected the DUT, the 4395A will measure and display the impedance characteristics.

Performing the Automatic Scaling

Often, the trace obtained after specifying the frequency range is too large or too small vertically for the grid. However, by using the automatic scaling function, you can obtain the optimum vertical setting automatically.

Step 6: Switching from Channel ¹ to Channel ²

All the settings you have made so far are assigned to Channel 1. Now, activate Channel 2 instead of Channel 1.

Press the $(\overline{Chan 2})$ key in the ACTIVE CHANNEL block.

Make sure that the indicator lamp beside the $\overline{\text{Chan 2}}$ key is ON.

Setting the Averaging Factor for Channel ²

This tour assumes the averaging factor of 8.

Follow these steps:

Press the $\overline{\text{Bw/Avg}}$ key. Choose AVERAGING FACTOR.

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Step 7: Selecting the measurement parameters for Channel ²

This tour assumes that the following measurement parameters be specied for Channel 2.

Characteristic value Phase (θ_z)

Format Linear

To set the parameters listed above, follow these steps:

Press the (Format) key. Choose LIN Y-AXIS .

Now both Channels ¹ and ² are assigned specic settings. You can not only have one of the two channels displayed at ^a time, but also have both channels displayed in parallel, as you will learn in the next step.

Step 8: Dual Channel Display

The 4395A provides ^a feature that displays the measurement results for both channels at the same time. This feature is called "dual channel display."

Follow these steps:

The screen is split into upper and lower halves. The upper half shows the absolute impedance value while the lower half shows the phase.

Two graphs are merged into ^a single coordinate plane.

Front and Rear Panels

Features of 4395A

This chapter describes the features of the front and rear panels of 4395A. It provides illustrations and descriptions of the front panel features, the LCD display and its labels, and the rear panel features and connectors.

Front Panel

The front panel provides ^a number of hardkeys (physical keys) and softkeys (menu items displayed on the LCD), which allow you to activate various analyzer functions (Figure 4-1).

Figure 4-1. Front Panel Layout

1. Hardkeys

The hardkeys (physical keys) located on the front panel are divided into 6 blocks--- labeled "ACTIVE CHANNEL", "MEASUREMENT", "SWEEP", "MARKER", "INSTRUMENT STATE", and "ENTRY", respectively. Some of the front panel hardkeys control instrument functions directly while others provide access to softkey menus.

ACTIVE CHANNEL Block

The ACTIVE CHANNEL block contains two hardkeys: $(\overline{Chan 1})$ and $(\overline{Chan 2})$. By pressing either of these two keys, you can make the channel 1 or 2 active.

All measuring conditions you specify through the front panel, such as sweep settings, are assigned to the currently **active channel**. Once you have assigned your desired settings to each channel, you can instantly switch between the two different sets of measuring conditions by simply pressing the $(\overline{Chan 1})$ or $(\overline{Chan 2})$ key.

MEASUREMENT Block

The MEASUREMENT block contains hardkeys associated with measuring parameters, display formats, and calibration.

SWEEP Key Block

The SWEEP block contains hardkeys associated with sweep settings.

MARKER Block

The MARKER block contains hardkeys associated with the marker function that facilitates reading values on the measurement trace.

INSTRUMENT STATE Block

The INSTRUMENT block contains hardkeys that affect the instrument state of 4395A.

ENTRY keys

The ENTRY block contains the following:

- numeric keys
- a rotary knob
- step keys for incrementing or decrementing your entered values
- edit keys
- unit terminator keys

You can use the rotary knob to change the value of the currently active parameter.

2. Softkeys

Softkey menus are lists of up to eight related functions that can be displayed in the softkey label area at the right-hand side of the display. The eight keys to the right of the LCD are the softkeys. Pressing one of the softkeys selects the adjacent menu function. This either executes the labeled function and makes it the active function, causes instrument status information to be displayed, or presents another softkey menu.

Some of the softkey menus are accessed directly from front panel keys and some from other menus. For example, the sweep menu accessed by pressing the (Sweep) key presents all the sweep functions such as sweep type, number of points, and sweep time. Pressing

4-2 Front and Rear Panels

NUMBER of POINTS allows the required number of points displayed per sweep to be entered directly from the number pad. RETURN softkeys return to previous menus. DONE in completion of ^a specic procedure and then returns to an earlier menu.

Softkeys that are Joined by Vertical Lines

When several possible choices are available for ^a function, the softkeys are joined by vertical lines. For example, in the spectrum input port menu under the (\overline{Meas}) key, the available inputs are listed: R , A , $-$, B with a vertical line between the soft them. Note that one software can be software them. I can be software t selected at ^a time. When ^a selection has been made from the listed alternatives, that selection is underlined until another selection is made.

Softkeys That Toggle Between On and Off States

Some softkey functions can be toggled on or off, for example averaging. This is indicated in the softkey label. The current state, on or o \overline{r} , is capitalized in the softkey label.

Example:

Softkeys that Show Status Indications in Brackets

Some softkey labels show the current status of ^a function in brackets. These include simple toggle functions and status-only indicators. An example of ^a toggled function is the PRINT [STANDARD] or PRINT [COLOR] softkey. The DATA MATH[] softkey is an example of ^a status-only indicator, where the selected equation of the data math function is shown in brackets in the softkey label.

3. GPIB "REMOTE" Indicator

The "REMOTE" Indicator turns on when the analyzer is in the remote state.

4. $(Present)$ Key

This key returns the instrument to ^a known standard preset state from any step of any manual procedure. A complete listing of the instrument preset conditions is provided in Appendix C.

5. PROBE POWER Connector

This connector (fused inside the instrument) supplies power to an active probe for in-circuit measurements of AC circuits. Applicable active probes are described in Chapter 12.

6. Analyzer Input Terminals R, A, and B

These are input terminals through which the 4395A receives signals output from the RF OUT terminal and then fed through the test circuit. How to use these input terminals differs depending on which analyzer mode you use:

In network analyzer mode, use the A and B terminals to receive signals output from the RF OUT terminal and then fed through the device under test (DUT), and use the ^R terminal to directly feed back the signal output from the RF OUT terminal to provide the reference input signal. You may want to use a power splitter to split the RF OUT signal among the input terminals. terminals.

In spectrum analyzer mode, you can use any of these three terminals to monitor the spectrum of the input signals.

In impedance analyzer mode, which is available with option 010, use the ^R and ^A terminals to monitor the voltage and current across the DUT being fed with the signals output from the RF OUT terminal.

These terminals comply with INSTALLATION CATEGORY ^I of IEC 1010-1.

Note Electrostatic discharge(ESD) can damage the highly sensitive

microcircuits in your instrument. ESD damage is most likely to occur as the test fixtures are being connected or disconnected. Protect them from ESD damage by wearing ^a grounding strap that provides ^a high resistance path to ground. Alternatively, ground yourself to discharge any static charge built-up by touching the outer shell of any grounded instrument chassis before touching the test port connectors.

7. RF OUT Connector 7. RF OUT Connector

Connects the RF output signal from the analyzer's internal source to ^a test set or power \mathcal{S} is the output impedance at this connection is 50 m.

Note that, in spectrum analyzer mode, the RF output is disabled by default. When you perform zero span measurement in spectrum analyzer mode, you can turn the RF output on.

8. DC SOURCE (DC Voltage/Current Output) Connector (Option 001)

This connector, located on the front panel, supplies up to ± 40 V / ± 100 mA of DC voltage/current.

9. Built-in Flexible Disk Drive 9. Built-in Flexible Disk Drive Disk Drive

You can use this disk drive to store your measurement data, instrument , list sweep tables, and HP Instrument BASIC programs. Supported data formats include the LIF (logical interchange format) and DOS (disk operating system) format.

10. LINE Switch

Turns on/off the power to the 4395A.

11. Liquid Crystal Display (LCD)

Displays measurement results, softkey menus, instrument settings, system orerror messages

Screen Display

The LCD displays ^a grid on which the measurement data is plotted, the currently selected measurement traces, and other information describing the measurement. Figure 4-2 shows the locations of the different information labels.

In addition to the full-screen display shown in Figure 4-2, a split display is available (see "Dual") Channel Display" in Chapter 6). In this case, information labels are provided for each half of the display.

The screen can also be used as the HP Instrument BASIC display. HP Instrument BASIC uses either ^a full-screen display or ^a half-screen display below the graphic display as ^a text screen.

Figure 4-2. Screen Display (Single Channel, Cartesian Format)

1. Active Channel

Displays either "CH1" or "CH2" to indicate the number of the currently active channel (one that was selected keys in the ACTIVE CHANNEL block). When the dual channel function is enabled and traces for the two channels are overlaid, both "CH1" and "CH2" appear in this area.

2. Measured Input(s)

Shows the input terminals currently in use, the values of the S parameters, or ratio of inputs (such as A/R ratio). Use the $(Meas)$ key to select the item to appear in this area.

\sim Formation \sim

Shows the currently selected display format. Use the $\overline{Fermat}}$ key to select your desired display format.

4. SCALE/DIV

Shows the currently selected scale in the unit appropriate to the ongoing measurement. Use the (Scale Ref) key to select your desired scale.

5. Reference Level 5. Reference Level

Displays the value of ^a reference line in Cartesian formats or the outer circle in polar formats. It is selected using the $\sqrt{S_{\text{cale}}$ Ref key. However, the reference line is invisible (it is indicated by ^a small triangle adjacent to the graticule at the left). The position of the reference line for the spectrum analyzer is fixed at the top of the Cartesian format.

6. Marker Data Readout

Displays the values of the marker in the unit appropriate to the current measurement (see Chapter 8). The status of the marker is also displayed under the marker values. The following status notations are used:

7. Marker Statistics and Width Value 7. Marker Statistics and Width Value

Displays the statistical marker values determined by using the menus accessed with the $\overline{[Utility]}$ key, and the width value determined by using the menus accessed with the $\overline{S\text{earth}}$ key. See Chapter 8.

Screen Display

8. Softkey Labels

Displays the menu labels that define the function of the softkeys immediately to the right of the label

9. PASS/FAIL

Indicates the values used for limit testing using limit lines. See "Limit Line Concept" in Appendix A.

10. Sweep Time

Displays the sweep time. When sweep time is manually changed, # is displayed between SWP and the sweep time value.

11. Sweep Parameter Span/Stop Value

Displays the stop frequency of the sweep range in frequency domain measurements or the upper limit of ^a power sweep if 4395A isin network analyzer mode or impedance analyzer mode. When the sweep parameter is in center/span mode, however, this area indicates the span instead. You can suppress the display of the sweep parameter values (see Chapter 6).

12. Power Level

Displays the power level of RF output if the 4395A is in network analyzer mode or impedance analyzer mode and frequency sweep is selected. When power sweep is selected or the 4395A is in another mode, this area is blank.

13. CW Frequency

Displays the measured frequency if the 4395A is in network analyzer mode or impedance analyzer mode and power sweep is being performed. When frequency sweep is selected or the 4395A isin another mode, this area is blank.

14. Video Bandwidth (VBW)

Displays the video bandwidth if the 4395A is in spectrum analyzer mode.

15. Input Attenuator

Displays the input attenuator value at the inputs R, A, B if the 4395A is in spectrum analyzer mode.

16. Sweep Parameter Center/Start Value

Displays the start frequency of the sweep range in frequency domain measurements or the lower power value in power sweep if the 4395A is in network analyzer mode or impedance analyzer mode. When the sweep parameter is in center/span mode, this area shows the sweep center value instead.

17. RBW/IFBW

Displays the RBW (in spectrum analyzer mode) or IFBW (in network analyzer mode or impedance analyzer mode). When RBW or IFBW is manually changed, a sharp sign (#) is displayed between RBW or IFBW and the value.

18. Status Notations

Displays the current status of various functions for the active channel. The following notations are used:

² Frequency span expanded, etc.

<u>ud</u>

Note No status notation is displayed when Gate trigger is used.

Screen Display

19. External Reference

ExtRef is displayed when an external reference signal is connected to the external reference input on the rear panel. This applies even if the phase is not locked to the external reference signal.

20. Active Entry Area

Displays the name of the currently active input parameter with its current value.

21. Message Area

Displays prompts or error messages. See \Error Messages" for more information on error messages.

22. Title

Displays a user-defined title which can consist of alphanumeric characters.

Rear Panel Features and Connectors

Figure 4-3 shows the features and connectors on the rear panel. Requirements for the input signals to the rear panel connectors are provided in Chapter 11.

CB002003

Figure 4-3. Rear panel

1. External Reference Input Connector

Connects an external frequency reference signal to the analyzer that is used to phase lock the analyzer for increased accuracy in frequency.

When the 4395A is equipped with the external oven (Option 1D5), this connector must be connected to REF OVEN connector (14). The external frequency reference function is automatically enabled when a signal is connected to this input. When the signal is removed, the analyzer automatically switches back to its internal frequency reference.

2. Internal Reference Output Connector

Connects to the frequency reference input of an external instrument to phase lock it to the 4395A for stable synchronization with the internal frequency of the 4395A.

Rear Panel Features and Connectors Rear Panel Features and Connectors

3. External Program RUN/CONT Input

Externally triggers RUN or CONT of the HP Instrument BASIC program. The positive edge of a pulse whose width is 20 μ s or larger in the LOW state triggers RUN or CONT. The signal is TTL-compatible.

$4. I/O$ Port \sim \sim \sim \sim \sim \sim \sim

This is a 12-bit data communications port that connects to external devices such as ^a handler on a production line. It can communicate ⁸ bits of output data and ⁴ bits of input data at ^a time. For more information, see Chapter ¹¹ and Programming Manual.

5. Power Cable Receptacle

This receptacle accommodates the main power cable. Insert the main-power cable plug only into ^a socket outlet that has ^a protective ground contact. Note that the fuse that protects the power line is located inside the rear panel cover.

Connects the analyzer to an external controller and other instruments to configure an automated system. This connector is also used when the analyzer itself serves as the controller of compatible peripherals. For more information, see Programming Guide.

This terminal outputs measurement results to an external color monitor. Color monitors supporting VGA (scan rate of 31.5 kHz) can be connected to this terminal.

8. Parallel Interface

This interface can be used to redirect the displayed results to ^a printer. It complies with the Centronics parallel interface standard. See \Printer" in Chapter ¹² for supported printers.

9. 24-bit I/O Port

In addition to the 12-bit I/O port (described in item ⁴ above), the 4395A isequipped with ^a 24-bit data communications port that connects to external devices such as ^a handler on ^a production line. This port can communicate ² sets of 8-bit output data and ² sets of 4-bit bidirectional data at a time. For more information, see Programming Guide.

10. mini-DIN Keyboard Connector

Connect a mini-DIN keyboard to this connector usually when using Instrument BASIC.

Note Be sure to use the specified PS/2, 101 keyboard. Using any other keyboard can cause failure. cause failure.

11. Test Set I/O Interface

You can use this interface to establish a connection between the 4395A and the test set using the cable included in the S-parameter test set package to control the test set from the 4395A. See Chapter 12 for the test set that can be connected. This interface is not used for the 87512A/B transmission/reflection test set.

Caution Do not connect ^a printer to this interface. Doing so could damage the printer.

12. Gate Output (Option 1D6 Only)

Outputs a signal that indicates the status of the gate when the 4395A is performing gate trigger in EDGE mode. The signal is TTL-compatible; high indicates gate on, low indicates gate off.

13. External Trigger Input

Triggers a measurement sweep. The positive (or negative) edge of a signal in the LOW (Or HIGH state) starts a measurement. The signal is TTL-compatible. To use this connector, set the trigger mode to external using softkey functions.

14. Reference Oven Output (Option 1D5 Only)

Connects to the EXT REF INPUT connector when Option 1D5 is installed. Option 1D5 improves the frequency accuracy and stability of the 4395A.

Preparations for Measurements

This chapter provides the each procedure needed to prepare for network , spectrum, and impedance (with Option 010) measurements. The procedures are:

- Selecting an appropriate connection of DUT
- \blacksquare Presetting 4395A

If you are using the 4395A for the first time, it is recommended to get started by reading Chapter ¹ through Chapter ³ of this manual.

Selecting an appropriate connection of DUT

For Network Measurement

Connections of DUT in the network measurement varies depending upon your measurement parameters as described in this section.

Connecting DUT for Directional Transmission Characteristic Measurement

When you measure the transmission characteristic supplying ^a signal to your DUT from one direction, connect the DUT to the analyzer with the power splitter and the cables as shown in Figure 5-1.

You should manually change cabling when measuring the characteristic for reverse direction.

Figure 5-1. Connecting DUT for Directional Transmission Characteristic Measurement

Selecting an appropriate connection of DUT

Connecting DUT for Directional Transmission and Reflection Characteristics Measurement

When you measure the transmission and reflection characteristics supplying a signal to your DUT from one direction, connect the DUT to the analyzer with the transmission/reflection test set.

You should manually change cabling when measuring the characteristics for reverse direction.

Figure 5-2.

Connecting DUT for Directional Transmission and Reflection Characteristics Measurement

Connecting DUT for Bi-directional Transmission and Reflection Characteristics (Four S Parameters) Measurement

Bi-directional transmission and reflection characteristics, or all four S parameters, can be measured effectively with the S parameter set.

The device allows you to measure all the four parameters without changing cable connection manually at each measurement.

Figure 5-3.

Connecting DUT for Bi-directional Transmission and Reflection Characteristics (Four S Parameters) Measurement

Connecting DUT for Transmission Characteristic Measurement When the Output Signal is in ^a Circuit

If the output signal of DUT is in ^a circuit, use the active probe to capture ^a signal from the test channel as shown in Figure 5-4.

Figure 5-4. Connecting DUT for Transmission Characteristic Measurement When the Output Signal is in a Circuit

Use the transmission/reflection test set with the active probe, when measuring the reflection characteristic at the input lead simultaneously. See Figure 5-5.

Figure 5-5. Connecting DUT for Transmission and Re
ection Characteristics Measurement When the Output Signal is in ^a Circuit
Connecting DUT for Transmission Characteristic Measurement When the Input and Output Signals are in ^a Circuit

If both of the input and output signals of DUT are in ^a circuit, attach the active probes to both of the reference channel and the test channel, as shown in Figure 5-6.

Figure 5-6. Connecting DUT for Transmission Characteristic Measurement When the Input and Output Signals are in ^a Circuit

Selecting an appropriate connection of DUT

For Spectrum Measurement

Connections of DUT in the spectrum measurement varies depending upon how the measurement signal can be obtained as described in this section.

Connecting DUT When Directly Measuring the Signal

When you measure ^a signal which is directly supplied from the DUT to 4395A, connect the DUT as shown in Figure 5-7.

Figure 5-7. Connecting DUT When Directly Measuring the Signal

Connecting DUT When Measuring the Signal in ^a Circuit

Use the active probe to capture the measurement signal which is in ^a circuit as shown in Figure 5-8.

Figure 5-8. Connecting DUT When Measuring the Signal in ^a Circuit

For Impedance Measurement (Option 010)

Connecting the Impedance Test Kit

In the impedance measurement, the 43961A Impedance Test Kit is required to connect your DUT to the analyzer. See Figure 5-9.

- 1. Verify the 4395A is turned off.
- 2. Connect the N-cable to the RF OUT port of the analyzer.
- 3. Connect two connectors of the 43961A to the ^R and ^A ports of the 43961A.
- 4. Connect the other connector of the N-cable to the RF IN port of the 43961A.
- 5. Turn on the 4395A.

Figure 5-9. Connecting the Impedance Test Kit

Note The connection between DUT and the analyzer is accomplished when a test xture is mounted on the impedance test kit. Note that all the measurement settings and calibrations should be completed before you mount the test fixture. Follow the steps described in Chapter 6 and Chapter 7.

Presetting 4395A

Before starting measurement, press the green (Preset) key in the INSTRUMENT STATE block to set the 4395A to the preset state.

For additional information about the preset state, see Appendix C.

Setting and Optimizing Measurement Conditions

This chapter provides following procedures for setting and optimizing measurement conditions:

- Select the analyzer mode
- Select the active channel
- Set up the trigger system
- \blacksquare Set the sweep conditions
- \blacksquare Select the input port/measurement parameter
- Select the measurement format
- Select the display unit
- Set the frequency range
- Set the vertical scale
- Set the IF/resolution/video bandwidth (IFBW/RBW/VBW)

Selecting the Analyzer Mode

- 1. Press (Meas).
- $2\cdot$ Press ANALYZER TYPE . $-$

3. Select one of the following analyzer modes:

¹ Option 010 only.

Selecting the Active Channel

In the ACTIVE CHANNEL block, press $(\overline{chan 1})$ (channel 1) or $(\overline{Chan 2})$ (channel 2) to select the active channel.

The 4395A has two independent channels. You can assign a different set of measurement conditions to each channel and switch between the two channels with just ^a single keystroke, provided that you use both channels for the same analyzer mode. By switching between the channels, you can effectively evaluate the DUT's characteristics under different measurement conditions.

Dual Channel Display

- 1. Press (Display).
- $2\cdot$ Toggle DUAL CHAN on OFF to ON off .
- 3. Press MORE.
- 4. Select one of the following options:

Split the screen into the two channels Merge the channels into one screen

Figure 6-1. Dual Channel Display

Setting Up the Trigger System

This section provides procedures for setting the trigger system.

- Setting up the trigger system
	- \Box Using the external trigger

Setting Up the Trigger System

- 1. Press (Trigger).
- 2 . Press TRIGGER: [].
- 3. Select one of the following options:

1 See "Using the External Trigger" that follows.

² Option 1D6 and SA (spectrum analyzer) mode only. Chapter ⁸ describes how to use this trigger mode.

Using the External Trigger

- 1. Connect the trigger source to the EXT TRIGGER connector on the rear panel of the 4395A.
- 2. Press (Trigger).
- 3. Press TRIGGER: [].
- $4\cdot$ Press EXTERNAL .
- 5. Input ^a trigger signal to the analyzer.

The external trigger signal level must be TTL Level.

Figure 6-2. Location of EXT TRIGGER Connector

Setting the Trigger Signal Polarity

- 1. Press (Trigger).
- 2 . Press TRIGGER: [] . .
- 3 . Toggle TRIG PLRTY POS neg to pos NEG to turn the trigger polarity to the negative logic.

Generating ^a Trigger Event on Each Measurement Point (NA, ZA Mode)

- 1. Press (Trigger).
- 2 . Press TRIGGER: [] . .
- 3. Select one of the following options:

- 4. Toggle TRIG EVENT [ON SWEEP] to [ON POINT].
- 5 To generate a trigger event, press MANUAL (for manual) or input the external trigger signal (for external).

Setting the Sweep Conditions

The sweep indicator (\dagger) " moves to each point every time a trigger event is generated. You can select this mode only after you have selected MANUAL or EXTERNAL as the trigger source, or activated the bus trigger mode. For more information about the bus trigger mode, see the Programming Manual.

Setting the Sweep Conditions

The 4395A controls the sweep process based on the following conditions:

- Sweep mode
- Sweep type
- Sweep parameters

This section describes how to select the sweep mode and sweep type. For how to set the sweep parameters, see "Setting the Frequency Range". For how to use the power sweep function, see "Using the Power Sweep Function (NA, ZA Mode)".

In addition, the 4395A is capable of automatically controlling the sweep process in accordance with a user-specified sweep list. For more information on the list sweep function, refer to Chapter 9 of this manual.

Selecting the Sweep Mode

Select one of the following options

Selecting the Sweep Type

^{1.} Press $\overline{S}_{\text{WeeD}}$ and choose SWEEP TYPE MENU.

2. Select one of the following options:

¹ NA, ZA mode.

Using the Power Sweep Function (NA, ZA Mode)

- \sim 1. I ess Source | \sim CW FREQ . The CW frequency is the CW frequency. The CW frequency is the CW frequency of the CW frequency. The CW frequency is the CW frequency of the CW frequency is the CW frequency of the CW frequency of the CW frequency
- 2. Press (Sweep).
- 3. Press SWEEP TYPE MENU .
- $^{\rm 4.}$ Press POWER SWEEP .
- 5. Enter the start and stop power levels.

 \sim . Strattle for a from β from β dBm, to β to dBm, press found β -15 β -1, β -1, β -1, β -1, β -1, β

Note Vou can set the sweep power in increments of 0.1 dB. **Maximum power sweep range (start to stop) is 20 dB within range of** -50 dBm to $+15$ dBm.

Selecting the Input Port/Measurement Parameter

This step provides following procedures:

- To select the input port in NA mode
- To select the input port in SA mode
- To select the measurement parameter in ZA mode

To Select the Input Port in NA Mode

 \blacksquare Press (Meas)

With the S-Parameter Test Set

 \blacksquare Press (Meas)

Selecting the Input Port/Measurement Parameter

To Select the Input Port in SA Mode

The 4395A has three input ports: R, A, and B. You can use any of these input ports for spectrum measurements.

In the preset state, the 4395A uses the ^R input port for spectrum measurements. To explicitly specify the input port, choose one of the following softkeys:

To Select the Measurement Parameter in ZA mode

Selecting the Measurement Format (NA, ZA Mode)

Selecting the Measurement Format in NA Mode

- 1. Press (Format).
- 2. Select one of the following options:

1 See "Group Delay" in Chapter 8.

2 See "Displaying the Trace as a Smith Chart (NA, ZA Mode)".

Displaying the Trace as a Smith Chart (NA, ZA Mode)

- 1. Press (Format).
- 2 Press SMITH CHART to display the trace as a smith chart.

 \degree Use the marker to read a measured value, by pressing (Marker) and turning \degree .

Note To display the Smith Chart in the ZA mode, set the measurement parameter to MAG(||) in the measurement menu.

To change the marker readout format, use the following procedure:

How To Change Marker Readout Format (NA, ZA Mode)

- \sim 1.1 PSS | Utility | פר SMTH/POLAR MENU . SM
- 2. Select one of the following options by pressing the corresponding softkey:

Using the Impedance Conversion Function (NA Mode)

- 1. Press (Meas).
- $2.$ Press CONVERSION [] .
- 3. Select one of the following options:

Selecting the Measurement Format (NA,ZA Mode)

Convert To	Selected Port	Softkey	
Impedance	A/R, S11, S12	7.8 efl	
	B/R, S21, S22	<u> Z:Trans</u>	
Admittance	A/R, S11, S12		
	B/R, S21, S22	lrans.	

The marker readout value is a linear impedance or admittance value even if the LOG MAG format is selected.

To Display Phase beyond ± 180 Degrees (NA, ZA Mode)

By default, the 4395A wraps the trace around at ± 180 degree phases. However, there are occasions when it is more convenient to display the trace without ± 180 degree wrap-around. If this is the case, you can use the **Expanded Phase Format**, which displays phases beyond ± 180 degrees as shown in Figure 10-6.

To select the expanded phase format, follow these steps:

- 1. Press (Format)
- $2\cdot$ Toggle EXP PHASE on OFF to ON off .

Using the Complex Plane Format (ZA Mode)

Displaying R-X in the Complex Plane

- 1. Press M eas) and choose IMPEDANCE: MAG($|Z|$).
- $2.$ Press F_{ormat} and choose COMPLEX PLANE to select the complex plane format.
- ^{3.} Press $\overline{S_{\text{calc Ref}}}$ and choose AUTO SCALE to adjust the scale.

In the complex plane, the measurement parameter is always a complex number even if you select a scalar parameter (such as $|Z|$).

Using the Marker

1. Press (Marker). Then move the marker using the rotary knob.

The marker displays the real and imaginary value of the marker position at the upper-right corner of the grid as shown in Figure 6-5.

Figure 6-5. Marker Readout of Complex Plane

Adjusting the Scale Setting

- 1. Press (Scale Ref)
- 2. Change the following settings to adjust the scale of the complex plane:

The reference position of the complex plane is always at the center of the grid. You can adjust the scale by changing the scale per division setting or the reference coordinate value.

Selecting the Display Unit

Selecting the Display Unit in SA Mode

- 1. Press (Format)
- 2. Select one of the following options by choosing the corresponding softkey:

You can change the unit of ^a displayed value anytime you want. The 4395A automatically converts values into your specied format (unit) using the internally stored data. This eliminates the need of re-sweeping. Also, the 4395A can convert values even when it is in the held state.

In spectrum analyzer mode, marker readout unit can be selected apart from the display unit. See "To Select Marker Readout Unit (SA Nide)" in Chapter 8 for details.

If you want to perform ^a noise measurement instead of ^a spectrum measurement, see "Measuring the Noise Level" in Chapter 8.

Selecting the Phase Unit (NA, ZA Mode)

You can display the phase in either degrees or radians. To switch between the two units, follow these steps:

- 1. Press (Format).
- 2. Do one of the following:
	- \blacksquare To switch from degrees to radians, toggle PHASE UNIT [DEG] to [RAD].
	- \blacksquare To switch from radians to degrees, toggle PHASE UNIT [RAD] to [DEG].

Setting the Frequency Range

The 4395A has some useful features for setting the frequency range. This section provides the following procedures that are related to setting the frequency range.

- Setting the center frequency
	- \Box Setting the marker position to center
	- \Box Setting the maximum peak to center
	- \Box Changing the center with the specified step size
- \blacksquare Setting the frequency span
	- \Box Narrowing the span setting (SA mode)
	- \Box Setting the frequency range to full span
	- \Box Setting the sweep parameters using (Start) and (Stop)
- Zooming to a part of the trace
	- \Box Changing the zooming factor
	- \Box Displaying a zoomed trace on the other channel
	- \Box Zooming between the marker and the Δ marker

Setting the Center Frequency

- 1. Press (Center) to activate the center frequency function.
- 2. Change the center frequency to place the target signal in the center of the grid by using the following keys:

1 You can change the step size of $\bigoplus \bigoplus$. See "Change the Center Frequency by the Specied Step Size" in this section.

Setting the Marker Position to Center

- 1. Press $(Marker \rightarrow)$. A reverse-triangle shaped marker appears.
- 2. Place the marker on the position you want to set to the center by using the rotary knob.
- $3.$ Press MKR \rightarrow CENTER .
- 4. Press (Entry Off)

The above procedure causes the 4395A to immediately use the marker-pointed frequency as the center frequency. If you are measuring an unknown signal, display the signal in full span first. Then move the signal to the center using this function.

Setting the Frequency Range

Move the marker Press NNNNNNNNNNNNNNNNNNNNNNNNNNNNNNNNNN MKR!CENTER

Figure 6-6. Marker to Center

Setting the Maximum Peak to Center

- 1. Press $(Marker \rightarrow).$
- 2 . Press PEAK \rightarrow CENTER . $-$
- 3. Press (Entry Off).

This function changes the center frequency to display the maximum peak at the center of the grid.

Note ^A large frequency span may prevent the peak from appearing accurately at the center of the grid. If this is the case, press $PEAK \rightarrow CENTER$ again so that the peak is redisplayed in the middle.

Figure 6-7. Peak to Center

Change the Center Frequency by the Specied Step Size

- 1. Do one of the following:
	- Choose Center CENTER STEP SIZE . Then directly enter your desired step size using $[0]$... $[9]$ and the units terminator keys.
	- **Press (Marker)** and move the marker to the point you want to use as the step size frequency. Then choose Center MARKET . THE STEP . STE
- 2 . Toggle STEP SIZE AUTO man to auto MAN.
- 3. Press (Center)
- 4. Press \mathcal{F} to increment (or \mathcal{F}) to decrement) the center frequency setting by the specified step size.

This function is useful to display peaks that have a constant interval (such as harmonics) one after another. The following is an example of using this function to display harmonics .

Setting the Frequency Range

Example: Displaying Harmonics (SA Mode)

To display the fundamental and harmonics of ^a ¹⁰⁰ MHz signal, follow these steps:

- 1. Press Center 100 $\overline{(M/\mu)}$. Then set the span to display the fundamental at the center of the grid.
- 2. Press $(Span)$ 150 (M/μ)
- ^{3.} Press Search and toggle SEARCH TRK on QFF to QN off to enable the search track function.
- 4. Choose SEARCH: PEAK to move the marker on the fundamental.
- ^{5.} Press Center) and choose MKR —CNTR STEP . Enter 100 MHz (so the step size matches the fundamental frequency).
- $6.$ Toggle STEP SIZE AUTO man to auto MAN to enable the specified step size.
- 7. Press (Center). Then press \textcircled{f} to display the second harmonic.
- 8. To display higher order harmonics, press \mathcal{F} as required.

The marker searches for the next harmonic each time you change the center frequency using the search track function.

Fundamental Second Harmonics

Figure 6-8. Displaying Harmonics

Setting the Frequency Span

- 1. Press (Span).
- 2. Enter the frequency span to display the target peak in the optimum grid setting.

Setting the Frequency Range

Narrowing the Span Setting (SA Mode)

- 1. Press (Search)
- $^{\mathrm{2.}}$ Choose SEARCH: PEAK to place the marker on the carrier.
- 3 . Toggle SIGNAL TRK on OFF to ON off .
- 4. Narrow the span setting. See the "Setting the Frequency Span" procedure.

An extremely small span setting may cause the test signal to disappear from display. This happens because of the difference between the displayed and actual frequencies. For example, when the span setting is set to full span, the displayed test signal frequency has an error of approximately ⁶⁰⁰ kHz because of its resolution (500 MHz/800). A span setting smaller than the error frequency can cause the test signal to disappear from the screen depending on the error range.

The signal track function allows you to avoid this situation. When signal track is enabled, the analyzer narrows the span setting while centering the test signal as you narrow the span setting. Therefore, the test signal is placed at the center of the grid.

The following figure shows an example of narrowing the span with the signal track function. The actual signal frequency is 250.100025 MHz. When the center is fixed and the span is 10 kHz, the signal is out of display. The signal track function tracks the signal by changing the center frequency, and keeps displaying the signal at the center of the display.

Figure 6-9. Narrowing Span with Signal Track

Setting the Frequency Range to Full Span.

- 1. Press (Span)
- 2. Press FULL SPAN

This function is useful when you want to get a general view of the spectrum after you have obtained the detailed view of a specic signal.

Setting the Sweep Parameters Using (S_{tar}) and (S_{top})

You can set the sweep parameters using $[Start]$ and $[Stop]$ instead of $[Center]$ and $[Span]$:

- 1. Press $\sqrt{\text{Start}}$ to put the 4395A into a mode where it accepts your entered value as the frequency at which to start the sweep process.
- 2. Set the start frequency using the following keys:

- 3. Press Stop to put the 4395A into ^a mode where it accepts your entered value as the frequency at which to stop the sweep process.
- 4. Set the stop frequency using the keys listed in the previous table.

Figure 6-10. Setting the Sweep Parameters

Setting the Frequency Range

Zooming To a Part of the Trace

- 1. Move the marker to the point where you want to observe the signal details.
- 2. Press $(Marker \rightarrow)$
- 3. Press MKR ZOOM .
- $^{4}\cdot$ To zoom more, press MKR ZOOM again.

Change the Zooming Factor.

- -1.1 CSS Marker -1.2
- 2. Enter your desired zooming aperture as a percentage of the span.

If you want to obtain ^a 20-fold zoom, for example, enter 5% for as the zooming factor.

Displaying ^a Zoomed Trace on the Other Channel.

- 1. Press $\overline{Display}$ and toggle DUAL CHAN on OFF to ON off to display two channels on the LCD.
- 2. Move the marker to the point where you want to observe the signal details.
- 3. Press $(Marker-)$
- $4\cdot$ Choose MKR \rightarrow XCH MENU .
- ^{5.} Choose MKR XCH ZOOM .

The other channel displays the zoomed trace.

Figure 6-11. Zooming the Trace

Adjusting the Scale and Reference

The 4395A provides you with several means to adjust the scale and reference of the trace so that the entire trace is displayed within the grid area. For example, when the trace is out of the grid or is too flat to see the required characteristics, you can adjust the trace settings by adjusting the reference or the scale.

- Automatically adjusting the scale and reference
- Manually adjusting the scale and reference
- Setting the reference
- Changing the scale per division

Automatically Adjusting the Scale and Reference (NA, ZA Mode)

- 1. Press (Scale Ref)
- 2 Press AUTO SCALE to fit the trace within the grid.

The scale and reference settings are automatically adjusted to provide an optimum trace display.

Figure 6-12. Autoscale Function

Manually Adjusting the Scale and Reference (NA, ZA Mode)

If you want to manually adjust the scale and reference settings, the following functions are $axailable'$

- \blacksquare To change the scale per division setting, press SCALE/DIV.
- To change the reference position that is shown as " \blacktriangleright ", use REFERENCE POSITION and \textcircled{n} \textcircled{n} keys.
- To change the reference value, use REFERENCE VALUE .

If you are displaying a data trace and a memory trace together, you need to consider whether you want to change the scale for one or both traces. You can change the traces as follows:

Adjusting the Scale and Reference

- If you want to change the scale setting for the data trace only, set SCALE FOR [DATA] and D&M SCALE [UNCOUPLE] under Scale Ref key.
- If you want to change the scale setting for the memory trace only, set SCALE FOR [MEMORY] and D&M SCALE [UNCOUPLE].
- If you want to change the scale settings for the both traces, set $D&M$ SCALE [COUPLE].

Setting the Reference (SA Mode)

Using the Numeric Keys.

- 1. Press (Scale Ref).
- $2\cdot$ Choose REFERENCE VALUE .

Using the Marker.

- 1. Press \widehat{S} and choose SEARCH: PEAK to move the marker to the peak.
- 2. Press (Scale Ref)
- ^{3.} Choose MKR→REFERENCE .

Figure 6-13. Marker to Reference

Changing the Scale per Division (SA Mode)

- 1. Set the reference level to the peak level of the target signal. See the "Using the Marker" procedure.
- 2. Press (Scale Ref)
- ^{3.} Choose SCALE/DIV .
- 4. Change the scale/division setting to display additional details using the following keys:

This function can be used to display ^a small peak on ^a full grid.

Figure 6-14. Changing Scale/Div.

Setting the IF/Resolution/Video Bandwidth

Setting the IF Bandwidth (NA, ZA Mode)

- 1. Press $\sqrt{\frac{Bw}{Avg}}$
- $^2\cdot$ Choose IF BW . $^-$
- 3. Press \mathbb{R} or \mathbb{Q} , or enter an IF bandwidth value directly from the numeric keypad.

^A smaller IF bandwidth increases the dynamic range but slows down the sweep process.

IF Bandwidth 30 kHz **IF Bandwidth 100 Hz**

Figure 6-15. Setting IF Bandwidth (IFBW)

Note The IF bandwidth should be set equal to or less than $1/5$ of the measurement frequency. When making impedance measurements with the 43961A, you must set the IF bandwidth equal to or less than 300 Hz and set the averaging factor equal to or greater than 8.

Setting the IF Bandwidth to Auto Mode

If the sweep type is log frequency, the IF bandwidth can be set to auto mode.

- 1. Press $\sqrt{\frac{Bw}{Ay}}$
- 2 . Toggle IF BW auto MAN to AUTO man .

In auto mode, the IF bandwidth is automatically set equal to or less than 1/5 of each measurement frequency. If you want to set an upper limit of IF bandwidth in auto mode, press AUTO IFBW LIMIT AND ENTERED IN THE USE USE WITH A BELIEVE IT AN A LIMIT WITH WITH A LIMIT WITH A LIMIT WAS ARRESTED ON A LIMIT OF A LI

Setting the Resolution Bandwidths (SA Mode)

Adjusting the RBW can improve the resolution of the frequency and lower the displayed noise $floor$

- 1. Press $\sqrt{\frac{B_W}{Avg}}$.
- $2\cdot$ Choose RES BW . $-$
- \sim . Change the RBW setting at \sim , \sim , \sim the ...

Measuring two or more mutually adjusting signals requires special considerations on the width of the 4395A's internal IF filter. If the internal IF filter is wider than the difference between the signals, the analyzer cannot separate them. To avoid this problem, you must provide a resolution bandwidth (RBW) small enough for the 4395A to identify the respective signals.

^A small RBW can reduce the noise power per display point, thereby lowering the displayed noise floor and making it possible to display lower level signals.

For example, the trace of ^a ⁴⁰⁰ Hz amplitude modulated signal conceals sidebands in the skirt of the carrier trace when the RBW is ³⁰⁰ Hz. In this case, you can split the carrier and sidebands completely and lower the displayed noise floor by setting the RBW to 10 Hz.

Figure 6-16. Setting Resolution Bandwidth (RBW)

Setting the Resolution Bandwidth to Auto Mode

You can automatically set the resolution bandwidth in accordance with the percentage of the sweep span.

- 1. Press (Bw/Avg) .
- ². Press RBW/SPAN RATIO and enter the percentage of the sweep span with entry keys.
- $^3\cdot$ Toggle to AUTO man .

Setting the IF/Resolution/Video Bandwidth

Setting the Video Bandwidth (SA Mode)

- 1. Press $\sqrt{\frac{Bw}{Ay}}$
- $^{\mathrm{2}}\cdot$ Choose VIDEO BW .

3. Set the video bandwidth using the following keys:

When the target signal and the noise are hard to distinguish because of noise variation, narrow the video bandwidth. This reduces the noise variations and makes the signal clearly visible. Note, however, that reducing the video bandwidth slows down the sweep process.

You can set the VBW to a value that is $1/1$, $1/3$, $1/10$, $1/30$, $1/100$, or $1/300$ of the RBW setting currently in effect.

Resetting the Video Bandwidth.

- \sim 1.1000 DW/AVg PV.
- 2. Enter the same value as the RBW setting.

Figure 6-17. Setting Video Bandwidth (VBW)

Calibration

This chapter describes calibration procedures required for measurement in the network analyzer mode and the impedance analyzer mode. For details about calibration procedures, see Appendix A.

In the spectrum analyzer mode, the 4395A requires no calibration procedure in the measurement.

Note When performing the ⁷⁵ measurement in the spectrum analyzer mode, see Chapter 2 to set the 4395A properly.

Calibration Required for the Network Analyzer Mode

This section provide procedures for performing calibration. The calibration eliminates the errors and improves the measurement accuracy. The analyzer has six different methods of calibration. You can select the method that fits your measurement requirement by reading "To Select an Appropriate Calibration Method" procedure. This section also contains ^a procedure to

- Selecting an appropriate calibration method
- Performing a response calibration
- Performing a response & isolation calibration
- Performing an S11 1-port calibration
- Performing an S22 1-port calibration
- Performing a full 2-port calibration
- Performing a 1-path 2-port calibration
- Selecting the calibration kit
- \blacksquare Customizing the user defined calibration kit

To Select an Appropriate Calibration Method

The analyzer has six calibration methods. You can choose the appropriate calibration method to fit your measurement by using Table 7-1.

Calibration Required for the Network Analyzer Mode

Table 7-1. Calibration Method Selection Table

Performing ^a Response Calibration

- \sim 1.1 \approx Press LGa \sim CALIBRATE MENU RESPONSE to display the response calibration menu.
- 2. Connect one of following standards. Then press the corresponding key.

3. Press DONE: RESPONSE.

Performing a Response & Isolation Calibration

- \sim 1.1 CSS [Call \sim CALIBRATE MENU RESPONSE $\&$ ISOL'N to display the response and isolation calibration menu.
- 2. Press RESPONSE.
- 3. See 2 of the \Performing a Response Calibration" procedure.
- $4.$ Press DONE: RESPONSE.
- 5. Connect isolation standard (LOAD).
- 6. Press ISOL'N.
- ^{7.} Press DONE RESP ISOL'N CAL.

Performing an S11 1-Port Calibration

Step 1: Opening the S-11 1-Port Calibration Menu

- 1. Press $\boxed{\mathsf{Cal}}$
- 2. Select the proper calibration kit. If the connector type or calibration kit name shown in the CALL AILLY SOFTING IS NOT TO INC. SAME AS THE CALIBRATION WITH THE CALIFORNIA OF WOOD FOLLOW THE GIVEN THE CALI "Selecting the Calibration Kit" procedure.
- 3. Press CALIBRATE MENU S11 1-PORT.

Step 2: Measuring the OPEN

- 1. Connect OPEN standard to port 1.
- 2. Press (S11): OPEN (for the 7 mm or 3.5 mm cal kit) or $(S11)$: OPENS (for the type-N cal kit).

When the 7 mm or 3.5 mm calibration kit is selected, the message "WAIT - MEASURING CAL STANDARD" is displayed while the OPEN data is measured. The softkey label OPEN is then underlined. Skip to step 3.

- 3. If the type-N calibration kit is selected, do the following:
	- a. Press OPEN [M] (for a male port connector) or press OPEN [F] (for a female port connector).

The OPEN data is measured and the softkey label is then underlined.

b. P_{ress} DONE: OPENS .

Step 3: Measuring the SHORT

- 1. Disconnect the OPEN. Then connect a SHORT standard to port 1.
- 2. Press SHORT (for the 7 mm or 3.5 mm calibration kit) or SHORTS (for the type-N calibration kit).

When the 7 mm or 3.5 mm calibration kit is selected, the SHORT data is measured and the softkey label is underlined.

- 3. If the type-N calibration kit is selected, do the following:
	- a. Press SHORT [M] (for a male port connector) or press SHORT [F] (for a female port connector).

The SHORT data is measured and the softkey label is then underlined.

b. Press DONE: SHORTS .

Step 4: Measuring the LOAD

- 1. Disconnect the SHORT, and connect an impedance-matched LOAD (usually 50 or 75) at port 1.
- ^{2.} Press LOAD . Then wait the LOAD is measured and the LOAD softkey is underlined.

Step 5: Completing the Calibration

1. Press DONE 1-PORT CAL to complete the calibration.

The 4395A calculates the error coefficients, and then redisplays the correction menu with a CORRECTION ON ON ON ON ON A CORPORATION ON A COLORADO AND A CORRECTED STATE IS ON A CORPORATION ON A CORD AND side of the screen.

If you press DONE without measuring all the required standards, the message "CAUTION: ADDITIONAL STANDARDS NEEDED" is displayed.

Performing an S22 1-Port Calibration

This calibration is similar to the S11 1-port calibration except that S22 is selected automatically. It is used only with an S-parameter test set.

For S-parameter measurements in the reverse direction with a transmission/reflection test kit, use the S11 1-port or 1-path 2-port calibration and reverse the DUT between measurement sweeps.

Performing ^a Full 2-Port Calibration

Step 1: Opening the Full 2-Port Calibration Menu

- 1. Press (Cal)
- 2. Select the proper calibration kit. If the connector type or calibration kit name shown in the CALL AILLY SOFTEN IS NOT TO THE SAME AS THE SAME AS THE SAME AS THE SAME AS THE USE THE BELL OF THE LABEL IS L the Calibration Kit" procedure.
- 3. Press CALIBRATE MENU FULL 2-PORT REFLECT'N.

Step 2: Measuring the Reflection

- 1. Connect a shielded OPEN to port 1.
- 2. Press (S11): OPEN (for the 7 mm or 3.5 mm calibration kit) or $(S11)$: OPENS (for the type-N calibration kit).

When the 7 mm or 3.5 mm calibration kit is selected in step 1, the OPEN data is measured and the softkey label OPEN is underlined.

- 3. If the type-N calibration kit is selected, do the following:
	- a. Press OPEN [M] (for a male port connector) or press OPEN [F] (for a female port connector).

The OPEN data is measured. The softkey label is then underlined.

- b. P_{ress} DONE: OPENS .
- 4. Disconnect the OPEN and connect the SHORT to port 1.
- $5.$ Press (S11): SHORT (for the 7 mm or 3.5 mm calibration kit) or (S11): SHORTS (for the type-N calibration kit).

When the 7 mm or 3.5 mm calibration kit is selected, the SHORT data is measured and the softkey label SHORT is underlined.

- 6. If the type-N calibration kit is selected, do the following:
	- a. Press SHORT [M] (for a male port connector) or press SHORT [F] (for a female port connector).

The SHORT data is measured and the softkey label is then underlined.

- b. Press DONE: SHORTS
- 7. Disconnect the SHORT and connect an impedance-matched LOAD (usually 50 or 75) at port 1.
- $8.$ Press (S11): L0AD, Then confirm the L0AD softkey label is underlined.
- 9. Repeat the OPEN-SHORT-LOAD measurements described above, connecting the devices in turn to port 2 and using the (S22) softkeys.
- $10.$ Press REFLECT'N DONE .

The reflection calibration coefficients are computed and stored. The two-port calibration menu is displayed (with the REFLECT'N softkey underlined).

Step 3: Measuring the Transmission

- 1. Press TRANSMISSION.
- 2. Connect ^a THRU connection between port ¹ and port ² at the points where the test device is connected.
- 3. When the trace settles, press FWD. TRANS. THRU. Then wait the S21 frequency response is measured and the softkey label is underlined.
- 4. Press FWD, MATCH THRU, Then wait the S11 load match is measured and the softkey label is underlined.
- 5. Press REV. TRANS. THRU. Then wait the S12 frequency response is measured and the softkey label is underlined.
- 6. Press REV. MATCH THRU . Then wait the S22 load match is measured and the softkey label is underlined.
- 7. Press TRANS. DONE.

The transmission coefficients are computed and stored. The two-port calibration menu is displayed (with the TRANSMISSION softkey underlined).

Step 4: Measuring the Isolation

- $1.$ If correction for isolation is not required, press ISOLATION $\,$ DMIT ISOLATION ISOLATION DONE . Then skip to step 5.
- 2. If correction for isolation is required, connect impedance-matched LOADs to port ¹ and port $\overline{2}$.
- 3. Press FWD ISOL'N ISOL'N STD. Then wait the S21 isolation is measured and the softkey label is underlined.
- 4. Press REV ISOL'N ISOL'N STD. Then wait the S12 isolation is measured and the softkey label is underlined.
- 5. Press ISOLATION DONE.

The isolation error coefficients are stored. The two-port calibration menu is displayed (with the ISOLATION softkey underlined).

Step 5: Completing the Calibration

1. Press DONE: 2-PORT CAL to complete the calibration.

The error coefficients are computed and stored. The correction menu is displayed (with \mathcal{C} . A correction of \mathcal{C} at the left of th screen indicates that two-port error correction is ON.

Now the test device can be connected and measured. Save the calibration data on the built-in disk drive.

Performing ^a 1-Path 2-Port Calibration

Step 1: Opening the 1-Path 2-Port Calibration Menu

- 1. Press (Cal)
- 2. Select the proper calibration kit. If the connector type or calibration kit name shown in the CALL AILLY SOFTEN IS NOT TO THE SAME AS THE SAME AS THE SAME AS THE SAME AS THE USE THE BELL OF THE LABEL IS L the Calibration Kit" procedure.
- 3. Press CALIBRATE MENU ONE-PATH 2-PORT REFLECT'N.

Step 2: Measuring the Reflection

- 1. Connect a shielded OPEN to the test port.
- 2. Press (S11): OPEN (for the 7 mm calibration kit) or $(S11)$: OPENS (for the type-N calibration kit).

The OPEN data is measured, and the softkey label OPEN is underlined.

- 3. If the type-N calibration kit is selected, do the following:
	- a. Press QPEN [M] (for a male port connector) or press QPEN [F] (for a female port connector).

The OPEN data is measured and the softkey label is then underlined.

- b. P_{ress} DONE: OPENS .
- 4. Disconnect the OPEN and connect ^a SHORT to the test port.
- 5. Press SHORT (for the 7 mm or 3.5 mm calibration kit) or SHORTS (for the type-N calibration kit).

When the ⁷ mm or 3.5 mm calibration kit is selected, the SHORT data is measured and the softkey label SHORT is underlined.

- 6. If the type-N calibration kit is selected, do the following:
	- a. Press SHORT [M] (for a male port connector) or press SHORT [F] (for a female port connector).

The SHORT data is measured and the softkey label is then underlined.

- b. P_{ress} DONE: SHORTS .
- 7. Disconnect the SHORT and connect an impedance-matched LOAD (50 or 75) to the test port.
- 8. Press LOAD. Then wait the LOAD is measured and the softkey label LOAD is underlined.
- ^{9.} Press REFLECT'N DONE .

The reflection calibration coefficients are computed and stored. The two-port calibration menu is displayed (with the REFLECT'N softkey underlined).

Step 3: Measuring the Transmission

- 1. Connect a THRU between the test port and the return cable to the analyzer (connect to the points at which the test device is connected).
- $2.$ Press TRANSMISSION.
- 3 Press FWD. TRANS. THRU . Then wait the S21 frequency response is measured and the 3 softkey label is underlined.
- 4. Press FWD. MATCH THRUE Then wait the S11 load match is measured and the softkey label is underlined.
- 5. Press TRANS. DONE.

The transmission coefficients are computed and stored. The two-port calibration menu is displayed (with the TRANSMISSION softkey underlined).

Step 4: Measuring the Isolation

- $1.$ If correction for isolation is not required, press ISOLATION $\,$ DMIT ISOLATION ISOLATION DONE . Skip to step 5.
- 2. If correction for isolation is required, connect impedance-matched LOADs to the test port and the return port.
- $3.$ Press FWD ISOL'N ISOL'N STD . Then wait the S21 isolation is measured and the softkey label is underlined.
- 4. Press ISOLATION DONE .

The isolation error coefficients are stored. The two-port calibration menu is displayed (with the ISOLATION softkey underlined).

Step 5: Completing the Calibration

1. Press DONE 2-PORT CAL to complete the calibration.

The error coefficients are computed and stored. The correction menu is displayed with CORRECTION ON ON ON ON OUR CORRECTED TRACED IS A CORPORATE AT THE LEFT OF THE LEFT OF THE LEFT OF THE LEFT OF T screen indicates that 2-port error correction is ON.

Step 6: Performing the Measurement

1. Connect the test device in the reverse direction. Then press PRESS to CONTINUE.

 2 Reconnect the test device in the forward direction. Then press PRESS to CONTINUE .

Now the error corrected trace is displayed. If you measure the other test device, press (Trigger) MEASUREMENT RESTART . THE PERFORM TO START . THE PROCEDURE OF START . THE PROCEDURE OF A START . THE PROCEDURE

Save the calibration data on a floppy disk or memory disk.

For additional information about calibration, see Appendix A.

Calibration Required for the Network Analyzer Mode

Selecting the Calibration Kit

- 1. Press $\boxed{\mathsf{Cal}}$.
- 2. Press CAL KIT [] .

3. Select one of the following options by pressing the corresponding key:

Customizing the User Defined Calibration Kit

Defining the Standard Definition

Step 1: Preparation.

1. Prepare the "Standard Definitions" table of the standard kit you want to use.

Table 7-2 is an example of a standard definition table.

STANDARD							OFFSET			$FREQ.$ (GHz)			
NO.	TYPE		$\begin{bmatrix} 0 \\ \times 10^{-15} \text{F} \end{bmatrix} \times 10^{-27} \text{F}$	\vert C ₂ ×10 ⁻³⁶ \vert C ₃ ×10 ⁻⁴⁵ FIXED OR F/Hz	F/Hz	SLIDING	DELAY LOSS $ Z_0 $ MIN. ps	$M\Omega/s$	Ω		MAX.	COAX or WAVEGUIDE	STANDARD LABEL
1	SHORT						$\mathbf{0}$	700	50	Ω	999	COAX	SHORT (M)
$\overline{2}$	OPEN	108	55	130	0		$\mathbf{0}$	700	50	Ω	999	COAX	OPEN (M)
3	LOAD					FIXED	Ω	700	50	Ω	999	COAX	BROADBAND
4	DELAY/ THRU						0	700	50	Ω	999	COAX	THRU
5													
6													
7	SHORT						17.544	700	50	Ω	999	COAX	SHORT(F)
8	OPEN	62	17	28	0		17.544	700	50	$\bf{0}$	999	COAX	OPEN(F)

Table 7-2. Example of the Standard Definitions

Step 2: Opening the Define Standard Menu.

- 1. Press $\overline{\text{Cal}}$.
- 2. Press CAL KIT [].
- ^{3.} Press MODIFY [] .
- $^{\rm 4.}$ Press DEFINE STANDARD .
- 5. Select standard number.

6. Select standard type.

If you did not select standard type as OPEN in step 2, skip to step 4.

Step 3: Entering C Parameters.

- 1. Press CO, Then enter C0 $(\times 10^{-15} \text{F})$.
- 2 Press C1 . Then enter C1 ($\times 10^{-27}$ F/Hz).
- $3\cdot$ Press C2 . Then enter C2 ($\times 10^{-36} \mathrm{F/Hz^2}$).

Step 4: Entering OFFSET Parameters.

- $1.$ Press SPECIFY OFFSET.
	- Press OFFSET DELAY. Then enter the offset delay value.
	- Press OFFSET LOSS. Then enter the offset loss value.
	- **Press OFFSET Z0.** Then enter Z_0 .
- $^{\prime\prime}$. Press STD OFFSET DONE .

Step 5: Entering a Standard Class Label.

- 1. Press LABEL STD.
- 2. Enter ^a standard label (up to ¹⁰ characters).
- 3. Press DONE .

Step 6: Completing the Definition of a Calibration Kit.

- $1.$ Press STD DONE (DEFINED).
- $^{\mathrm{2.}}$ Press KIT DONE (MODIFIED) . $^-$

Calibration Required for the Network Analyzer Mode

Defining a Class Assignment

Step 1: Preparing for the Class Assignment.

1. Prepare the standard class assignment table for your calibration kit.

Table 7-3. Example: Standard Class Assignment of the 85032B

Step 2: Specifying the Standard Class.

1. Press SPECIFY CLASS.

2. Select standard class.

3. Enter the standard number from A to G.

4. Press CLASS DONE (SPEC'D).

Step 3: Creating the Standard Class Label.

- 1. Press LABEL CLASS to label the standard class.
- 2. Select the standard class. See ² of Step 2.
- 3. Enter or modify the correspondent standard class label.
- 4. Press LABEL DONE .

Labeling and Saving Calibration Kit.

- 1. Press LABEL KIT.
- 2. Enter label.
- 3. Press DONE KIT DONE (MODIFIED).
- $^{\mathrm{4.}}$ Press CAL KIT [] SAVE USER KIT USER KIT.
- ^{5.} Press RETURN.

Once you have defined your own calibration kit, you can verify the definition using the copy function that lists standard parameters and class assignment.

Verifying the Definition of the User-Defined Calibration Kit.

- \sim 1.000 | Call \sim CAL KIT [] USER KIT to specify the calibration kit as ^a user-dened kit.
- Γ Less \lfloor Copy \lfloor Fil MORE CAL KIT DEFINITION.
	- \blacksquare To display the standard parameters defined, press STANDARD DEFINITON. Then press the softkey whose label corresponds to the standard number if you want to list the defined parameters.
	- \blacksquare To display the defined class assignment, press CLASS ASSIGNMENT.
- 3 . To make a hardcopy, press PRINT <code>[STANDARD]</code> .
- $^{4}\cdot$ To return to the normal display, press RESTORE DISPLAY .

Calibration Required for the Impedance Analyzer Mode

This section provide procedures for performing the calibration when measuring in the impedance analyzer mode. This section also covers how to customize the user defined

OPEN/SHORT/LOAD Calibration

In the impedance analyzer mode, 4395A should be calibrated with the 43961A impedance test kit attached. Calibration denes the measurement accuracy at the OUTPUT port on the impedance test kit. After calibration, the analyzer can measure within its specied measurement accuracy.

The calibration is performed in terms of the three items:

- \blacksquare OPEN (using 0 S termination)
- se value in die voorbeelde van die volkende van die volkende van die volkende van die volkende van die volkend
- LOAD (using ⁵⁰ termination)

Note You must use the calibration kit that is furnished to the 43961A for the standard calibration kit.

Calibration Procedure

Follow the steps below to perform the OPEN/SHORT/LOAD calibrations.

- 1. Press \overline{Ca} .
- $2\cdot$ Press CALIBRATE MENU .
- 3. Connect the ⁰ ^S termination to the OUTPUT port.
- 4. Press OPEN .

After an open calibration sequence is completed, the OPEN softkey label is underlined.

- 5. Disconnect the ⁰ S termination, then connect the 0 termination to the OUTPUT port.
- 6. Press SHORT .

After a short calibration sequence is completed, the SHORT softkey label is underlined.

- . I a billication then the strainered the second termination, the strainered the strainered the second termina
- 8. Press LOAD .

After a load calibration sequence is completed, the LOAD softkey label is underlined.

- ^{9.} Press DONE: CAL .
- 10. Verify the "Cor" notation is displayed on the left of the screen.

Figure 7-1. Connecting Calibration Standards

Note The OUTPUT port of the impedance test kit and the calibration standards have APC-7 connectors. The APC-7 connector is very sensitive to damage and dirt. You need to do the following when handling and storing APC-7 connectors:

- Keep the connectors clean.
- Do not touch the mating plane surfaces.
- Do not set the connectors contact-end down.
- Before storing, extend the sleeve or connector nut.
- Use end caps over the mating plane surfaces.
- Never store connectors loose in a box or a drawer.

Connecting the Test Fixture

To connect the test fixture to the impedance test kit, see the applicable test fixture manual for instructions. The following is ^a general procedure:

- 1. Turn the APC-7 connector of the impedance test kit OUTPUT port.
- 2. Verify that the connector sleeve is retracted fully.
- 3. Set the mounting posts of the test station into the twin locating holes at the corner of the test fixture.
- 4. Connect the connector on the underside of the test fixture to the OUTPUT port of the impedance test kit.

Figure 7-2. Connecting Test Fixture

Setting the Electrical Length of the Test Fixture

After connecting the test fixture, you need to enter the extended electrical length of the fixture. This is required to eliminate a phase shift error caused by the extended electrical length.

The analyzer has electrical length data for some fixtures as preset data.

- 1. Press (Meas)
- $2\cdot$ Press FIXTURE SELECT FIXTURE .
- 3. Select the fixture model number that you are using.
- $4.$ Press RETURN.
- 5. Verify that "Del" notation appears on the left side of the display.

If your fixture is not listed on the softkey label in the fixture selection menu, use the user fixture setting menu. (See "Setting the User Defined Fixture ".)

Setting the User Defined Fixture

Selecting FIXTURE [NONE] SELECT FIXTURE under (Meas) displays the list containing Agilent fixtures. To use a fixture that is not listed in the fixture list, perform the following procedure:

1. Determine the following parameters before defining the user fixture:

Port Extension The equivalent electrical length of the fixture [m].

Label The fixture identification that is displayed in the softkey label.

- $-$. The set and interest \mathcal{L} FIXTURE [NONE] MODIFY [NONE] to display the user fixture setting menu.
- 3 Press DEFINE EXTENSION . Then enter an equivalent electrical length by using the numerical keys.
- 4. Press LABEL FIXTURE . Enter a label by using the rotary knob and then press DONE . Pressing \mathbb{R} \mathbb{R} changes the character set for entry. Up to 8 characters are allowed.
- ^{5.} Press KIT DONE.
- 6 . To store the setting data into the non-volatile memory, press SAVE USER FXTR KIT .

To use the user fixture setting, select USER under Meas) FIXTURE [NONE] SELECT FIXTURE.

Calibration Required for the Impedance Analyzer Mode

Performing Fixture Compensation

Fixture compensation reduces the parasitic error existing between the test fixture electrode and the impedance test kit OUTPUT port. Fixture compensation consists of OPEN, SHORT and LOAD compensations. For basic measurements, the OPEN and SHORT compensations are required.

Note For the instructions on how to connect the standards, see the applicable test xture manual.

- 1. Connect the SHORT bar to the fixture.
- 2. Press Cal NN FIXTURE COMPEN NNNNNNNNNNNNNNNNNNNNNNNNNNNNNNNNNNN COMPEN MENU .
- 3. Press SHORT .

After the short compensation sequence is done, the SHORT softkey label is underlined.

- 4. Remove the SHORT bar and set the OPEN condition.
- 5. Press OPEN.

After the open compensation sequence is done, the OPEN softkey label is underlined.

- ^{6.} Press DONE: COMPEN.
- 7. Verify that "Cor" changes to "Cmp" notation.

Selecting the Calibration Kit

See "Selecting the Calibration Kit" in "Calibration Required for the Network Analyzer Mode" for selecting the calibration kit.

Defining a Custom Fixture Compensation Kit

This section explains how to define a custom fixture compensation kit.

The 4395A incorporates a database of Agilent's genuine test fixtures and their specific compensation coefficients. Therefore, as long as you use an Agilent's genuine test fixture, you can use the fixture without defining an associated compensation kit.

If you use your custom test fixture to meet your actual needs, however, you must define the compensation kit associated with the fixture before you can use your custom test fixture. Once you have defined a fixture compensation kit, the 4395A preserves the definitions so you can select the compensation kit whenever you need to use it.

The 4395A uses the following equivalent circuit to perform fixture compensation for each of the OPEN, SHORT, and LOAD circuit states:

Figure 7-3. Model of Fixture Compensation Kit

Defining a fixture compensation kit involves the following steps:

- 1. Opening the fixture compensation kit modification menu
- 2. Specifying parameter values
- 3. Specifying the standard label

The above steps are described in the following subsections in order.

Step 1: Opening the Fixture Compensation Kit Modication Menu

To open the fixture compensation kit modification menu, do the following:

- 1. Press (\overline{Ca}) .
- $^{\rm 2.}$ Choose COMPEN KIT <code>[USER]</code> .
- ^{3.} Choose MODIFY [USER] .
- $^{\rm 4.~Choose~DEFINE~STANDARD}$.

Calibration Required for the Impedance Analyzer Mode

Step 2: Specifying Parameter Values

In this step, you specify ² parameters for each of the OPEN, SHORT, and LOAD circuit states; thus 6 parameters in all. While the parameters for OPEN and SHORT are required, those for LOAD are optional.

To specify the parameter values, do the following:

- 1. Choose OPEN: CONDUCT(G), and enter the conductance value (G) for OPEN.
- ². Choose CAP. (C), and enter the capacitance value (C) for OPEN.
- ^{3.} Choose SH0RT: RESIST. (R), and enter the resistance value (R) for SHORT.
- ^{4.} Choose INDUCT. (L), and enter the inductance value (L) for SHORT.
- ^{5.} Choose L0AD: RESIST. (R), and enter the resistance value (R) for LOAD.
- ^{6.} Choose INDUCT. (L), and enter the reactance value (L) for LOAD.
- $\mathrm{^{7}\cdot}$ Choose STD DONE (DEFINED) .

Step 3: Specifying the Standard Label

- $1.$ Choose LABEL KIT. \blacksquare
- 2. Enter the standard label (up to ¹⁰ characters).
- 3. Choose DONE . .
- $^{\mathrm{4.}}$ Choose KIT DONE (MODIFIED) . $^{\mathrm{-}}$

Analyzing the Measurement Results

The 4395A provides various analyzer functions that allow you to output, save, or further analyze measurement results obtained through the 4395A's measurement functions. The first half of this chapter provides these analyzer functions which are not dependent on ^a particular analyzer mode. In the latter half, typical measurement techniques for each analyzer mode are described.

Topics covered include:

- \blacksquare Interpreting the trace
- Storing the trace data in memory
- Using the trace math functions
- Overlaying traces
- Outputting the data to ^a printer
- Saving and recalling the settings and data
- Typical network measurement techniques
- Typical spectrum measurement techniques
- Typical Impedance measurement techniques

Interpreting the Trace

Once you have successfully displayed the correct trace on the screen, you can use the marker to interpret the trace. The 4395A provides you with powerful search functions that allow you to search for specic points (like peaks or ripples). This section provides procedures for reading values using the marker and the marker search functions.

- To read a value using the marker
- To use the sub-markers
- \blacksquare To use the Δ marker
- To search for a point that has a target value
- To search for the peak-to-peak of ripples using the statistics function
- To search for a single peak on the trace
- To search for multiple peaks
- \blacksquare To define the peak for search (to ignore unnecessary peaks)
- To specify the search range

To Read ^a Value Using the Marker

- 1. Press (Marker)
- 2. Move the marker by performing the following steps:
	- Turn the rotary knob until the marker moves to the point where you want to read the measured value.
	- **Enter the target frequency by using numerical keys.**
- 3. Read the marker value displayed on the upper right of the display.

Improving the Readout Resolution (SA Mode)

If you want ^a more accurate frequency reading of the target signal, set the span and the RBW as narrow as possible.

Note The readout resolution of the frequency is determined by the setting of the frequency span, the number of points (NOP), and the resolution bandwidth (RBW). The resolution is the sum value of $SPAN/(NOP-1)$ and RBW. For example, when the frequency span is 10 MHz, the NOP is 801, and the RBW is ¹⁰ kHz, the readout resolution is approximately 22.5 kHz.

To Select Marker Readout Unit (SA Nide)

Maker readout unit can be selected as follows:

- 1. press (Utility)
- 2. Press MKR UNIT { }.
- 3. Select one of the following options:

Interpreting the Trace

To Use the Sub-markers

- 1. Press (Marker)
- 2. Move the marker to the point where you want to set the sub-marker.
- 3. Press SUB MKR.
- $^{\text{4}}$ Select the sub-marker from SUB MKR 1 to 7 .
- 5. Press (Utility)
- ^{6.} Toggle MKR LIST on OFF to ON off to display the marker list on the bottom of the display.

The sub-marker appears at the point of that the marker is displayed. Sub-markers are fixed horizontally and you cannot move them.

The sub-marker value can only be displayed by using the marker list.

To clear a sub-marker, press Market is \mathcal{L} . The sub-matrix \mathcal{L} is the sub-matrix of sub-matrix of sub-matrix \mathcal{L} you want to erase from the display.

To clear all of the markers, press Market Market PRESENT AND RESENT AND

Figure 8-2. Sub-marker and Maker List

To Use the \triangle Marker

- 1. Press (Marker).
- 2. Place the marker at the point you want use as the reference point by using the $\hat{\odot}$.
- 3. Press AMODE MENU.
- $4\cdot$ Press AMKR.
- 5. The reference marker appears at the marker point.
- 6. To move the marker:
	- Enter an offset frequency by using the numerical keys.
	- Turn the rotary knob until the marker moves to the point you want to read the value.
- 7. Read the level and the frequency differences from the reference marker that are displayed on the upper right of the grid.

The marker value on the upper right of the grid shows the frequency and the level differences between the reference marker and the marker.

When you use the sub-markers, use the marker list to display the difference between reference the marker and the sub-markers. (Press $\overline{[Utiliv]}$ and then toggle MKR LIST on OFF to ON off.)

To Search for a Point that has the Target Value (NA, SA Mode)

- 1. Press (Search)
- $2\cdot$ Press TARGET .
- 3. Enter the target value using $\overline{0}$... $\overline{9}$ and the unit terminator keys.

Interpreting the Trace

When the Δ marker is active, the target value becomes the difference from the reference marker, not an absolute value. For example, you can search for the -3 dB cutoff point of a filter by mixing the Δ marker and the target search function.

To Search for the Peak-to-Peak of Ripples Using the Statistics Function

Step 1: To Specify the Search Range

- 1. Press (Marker). Then move the marker to the start point of the range.
- ². Press AMODE MENU AMKR to place the reference marker on the start point of the range.
- 3. Move the marker to the end point of the range.
- -1.1 \circ \circ -1 \circ -1 \circ -1 \circ -1 \circ
- $^{\rm 5.}$ Toggle PART SRCH on OFF to ON off .
- 6 . Press MKRA \rightarrow SEARCH RNG to set the range defined by the reference marker and the marker and as the search range.

Triangle-shaped indicator (\triangle) at the bottom of the grid shows current search range.

Step 2: To Search For the Ripple

- 1. Press (Utility).
- $2\cdot$ Toggle STATISTICS on OFF to ON off .

STATISTICS displays the mean value (mean), the standard deviation (s.dev), and the peak-to-peak value (p-p) of the ripple within the specied range of the active channel. This information is displayed on the upper right of the display (see Figure 8-4). If you did not specify the search range, the analyzer searches within the displayed area.

Figure 8-4. Ripple Parameters Readout

To Search for ^a Single Peak on the Trace

- 1. Press (Search).
- 2 Press SEARCH: PEAK to search a maximum peak.
- 3. If you want to search for another peak:

To Search for Multiple Peaks

- \sim 1. Less Search I and
- 2. Do any of the following:

3. Press (Utility). Toggle MKR LIST on OFF to ON off to list all marker values.

When this function is enabled, the marker is placed on the maximum peak and the sub-markers are processed on up to several peaks. The peaks of the peaks of the several contracts of the several contracts PEAKS ALL searches for all the peaks and places the sub-markers in the order of peak level.

PEAKS RIGHT and PEAKS LEFT search only to the right or left side of the peak and place the sub-markers on peaks in the order found.

If the marker is to search for peaks other than harmonics, specify the peak threshold for the search function. This makes the search function ignore the peaks that have ^a lower level than the threshold level. See the "To Define the Peak for Search (To Ignore Unnecessary Peaks)" procedure.

Figure 8-6. Searching for Multiple Peaks

To Define the Peak for Search (To Ignore Unnecessary Peaks)

You can define the target peak for the search function using the following techniques:

- \blacksquare Defining the peak slope to ignore the relatively broad peaks.
- Specifying the peak threshold to ignore the absolutely small peaks.

Defining the Peak Slope to Ignore the Relatively Broad Peaks (NA, ZA Mode) Entering Directly.

- \sim 1.1000.1000.000.000
- ^{2.} Press PEAK DEF MENU.
- 3 Press PEAK DEF: ΔX . Then enter a width of the peak.
- 4 Peak PEAK DEF: AY. Then enter a height of the peak.

Using the Marker.

- 1. Press (Marker). Then move the marker on the local maximum you want to search.
- 2. Press AMODE MENU AMKR
- ا ت [Pearch II DI $SEARCH: PERK$ PEAK DEF MENU.
- 4. Move the marker to the foot of the peak.
- $5.$ Press MKR \rightarrow PEAK DELTA .

This parameter defines the slope of the peak. The definition is made by defining ΔX and ΔY as shown in Figure 8-7. The search function searches only for peaks that are steeper than the specied slope. Use this function when the search function searches for ^a peak that has ^a gentle slope.

Figure 8-7. Peak Definition

Defining Peak Height (SA Mode)

- 1. Press (Search)
- 2. Press SEARCH: PEAK PEAK DEF MENU.
- 3 . Press PEAK DEF: AY.
- 4. Enter a peak height using the numerical keys and the units terminator keys.
- 5. Press RETURN.

Specifying the Peak Threshold to Ignore the Absolutely Small Peaks Entering Directly.

- -1.1 \sim \sim 1 \sim \sim -1 \sim -1 SEARCH: PEAK PEAK DEF MENU.
- $^{\prime 2}$. Press THRESHOLD VALUE .
- 3. Enter a threshold value. 3. Enter ^a threshold value.
- 4. Toggle THRESHOLD on OFF to ON off.

The red threshold line is displayed. The all search function searches for only the upper side of the threshold line.

Using the Marker.

- 1. Press (Search)
- 2. Press SEARCH: PEAK PEAK DEF MENU.
- 3. Move the marker to the point you want to set as the threshold value.
- $4.$ Press MKR \rightarrow THRESHOLD.
- $^{\rm D.}$ Toggle THRESHOLD on OFF to ON off .

Before Defining the Threshold **After Defining the Threshold**

To Specify the Search Range

You can set the search function to search within a specified range. To specify the search range, use one of the following two procedures:

- Using the marker
- Using the Δ marker

Using the Marker

- 1. Press (Search)
- $2\cdot$ Press SEARCH RANGE MENU .
- 3 . Toggle PART SRCH on OFF to ON off . $\,$
- 4. Move the marker to the start point of the search range.
- $5.$ Press MKR \rightarrow LEFT RNG to set the marker position as the left edge of the range.
- 6. Move the marker to the end point of the search range.
- 7. Press $MR \rightarrow RH$ RIGHT RNG to set the marker position to the right edge of the range.
- 8. Press RETURN

Using the Δ Marker

- 1. Press (Marker).
- 2. Move the marker to the start point of the search range.
- 3. Press AMODE MENU .
- 4. Press AMKR .
- 5. Move the marker to the end point of the search range.
- 6. Press (Search).
- ^{7.} Press SEARCH RANGE MENU .
- ^{8.} Toggle PART SRCH on OFF to ON off to enable the search range.
- ^{9.} Press MKR∆→SEARCH RNG.

All the search functions search within a specied search range. You can specify the search range for each channel individually. The triangle-shaped indicator at the bottom of the grid s is the contractive search range (see Figure 8-9). In this inferred (search \sim SEARCH: PEAK searches for the highest peak within the specified range. It does not search all of the grid.

Figure 8-9. Search Range

To turn of the part search, press I can be the part of SEARCH RANGE MENU , and then toggle PART SRCH ON off to on OFF.

To Use the Trace Memory

To Store the Trace into the Trace Memory

- 1. Display the trace you want to store into the trace memory.
- 2. Press (Display).
- 3. Press DATA→MEMORY .

This operation only stores the digitized trace data into the trace memory (not the display on LCD). You can store the trace data for the trace memory of each channel individually. The stored trace data is retained until new data is stored, the 4395A is preset, or power is turned α ff.

To Display Memory Traces

 \sim 1. I ess | Display | D. DISPLAY FOR THE REPORT OF THE REPORT OF

2. Select the display trace:

Memory traces are displayed as green (channel 1) or red (channel 2) to distinguish between the two traces. You can change this color by using the modify colors menu under Display

If the trace memory of the active channel is empty, the error message (CAUTION: NO VALID MEMORY TRACE) is displayed.

Notes

The scale of the memory trace is coupling with the data trace. If you want to change the scale setting for only the data or memory trace, toggle Scale Ref Description of the couple of the coupled states of the coupled of the coupled coupled of the coupled o NNNNNNNNNNNNNNNNNNNNNNNNNNNNNNNN [UNCOUPLE] . Then toggle NN SCALE FOR [DATA] or NNNNNNNNNNNNNNNNNNNNNNNNNN [MEMORY] before you change the settings.

To Use the Trace Math Function

- 1. Press (Display).
- $2\cdot$ Press DATA MATH [] . $-$
- 3. Do one of the following:

To Turn Off the Data Math Function

- 1. Press (Display).
- $2\cdot$ Press DATA MATH [] . $-$
- ^{3.} Press DATA MATH: DATA .

To Multiply the Trace

- 1. Press (Display).
- 2 . Press DATA MATH [] . $\,$
- $^3\cdot$ Press GAIN. Then enter a multiplication factor:

us

Note For more information about the settings of gain and offset value, see Appendix B.

To Clear a Multiplied Trace

- 1. Press (Display).
- $2.$ Press DATA MATH [].
- $^{\rm 3.}$ Press DEFAULT GAIN & OFS .

To Overlay Multiple Traces

To Store the Trace into the Overlay Trace

- 1. Press (Display).
- 2 . Press OVERLAY TRACES .
- 3 . Press SELECT PEN COLOR and select one of the colors:

¹ Power ON default.

- 4. Press DATA-OVERLAY.
- 5. Repeat steps 1 through 4 above to store different traces.

Note You cannot change the scale setting for the overlay traces. It is also impossible to read the overlay trace data with markers or to save the data into a floppy disk or memory disk. For those applications, use the data trace or memory trace.

To Clear the Overlay Traces

- 1. Press (Display).
- 2 . Press OVERLAY TRACES .
- ^{3.} Press CLEAR GRAPHICS .

To Print

This step provides the following procedures for printing:

- To print out a display image
- To see or print a measured value list
- To print an analyzer setting

To Print Out ^a Display Image

- 1. Connect the printer to the analyzer with ^a cable.
- $-$ Press Copy Press PRINT [STANDARD] to print out ^a display image. To wo one printing, printing over 1

To See or Print ^a Measured Value List

- 1. Press \overline{Copy}
- 2 Press MORE LIST VALUES to display the measured value list.
	- \blacksquare To see all of the measured value list, press NEXT PAGE or PREV PAGE to turn the pages.
	- \blacksquare To print out the measured value list, press PRINT [STANDARD].
	- \blacksquare To return to the measurement display, press RESTORE DISPLAY.

To Print an Analyzer Setting

- 1. Press $\overline{(Copy)}$
- ². Press MORE OPERATING PARAMETERS to display the analyzer setting table as shown below.
- 3 . Press PRINT <code>[STANDARD]</code> to print out the settings.
- $4.$ To return to the measurement display, press RESTORE DISPLAY.

Analyzer Setting Table

To Save and Recall the Settings and Data

This step provides the following procedures for saving and recalling:

- To save an analyzer setting or measurement data
- To recall a saved analyzer setting
- \blacksquare To save a display image to a TIFF file
- To save measured data for a spreadsheet
- \blacksquare To copy a file between floppy disk and memory disk
- To initialize a disk for use
- To initialize the memory disk for use
- To back up the memory disk

To Save an Analyzer Setting or Measurement Data

The 4395A supports two storage devices, a built-in flexible disk drive and a 512KB memory disk. The flexible disk drive should be used to store large numbers of files and for long term data storage. Memory disk should be used for temporary data and instrument states and to store or get data quickly.

Note When you store important data into the memory disk, perform the memory disk backup operation described in \To Back Up the Memory Disk". Otherwise, the memory disk data is lost when the power is turned off.

- 1. Insert ^a LIF or DOS formatted 3.5 inch disk into the built-in disk drive (if you are recalling an instrument state file from the memory disk, skip this step).
- 2. Press (Save).
- 3. Select ^a save data type:

1 You can specify a data array type. See the "Specifying a Data Array Type" procedure.

- 4. Select where the file is stored by pressing either $STOR$ DEV $[DISK]$ (for the built-in disk drive) or STOR DEV [MEMORY] (for the memory disk).
- $^{\mathrm{D}}\cdot$ Enter a filename. Then press DONE .

The analyzer automatically detects the disk format as either the LIF (Logical Interchange Format) or DOS (Disk Operating System). If you insert an any other format type disk, an error message is displayed.

For more information, Appendix A provides a complete list of the instrument state to be saved.

To Save and Recall

Specifying the Data Format

To save only the measurement data in the ASCII or binary format, follow these steps:

- 1. Press (Save).
- 2 Choose DATA ONLY. Then select one of the following options by choosing the corresponding softkey:

Specifying ^a Data Array Type

To save only the measurement data by specifying the data array to save, follow these steps:

- 1. Press (Save).
- $^{\mathrm{2}}$. Choose DATA ONLY . $^{\mathrm{1}}$
- ^{3.} Press DEFINE SAVE DATA
- 4. Choose the softkey associated with the data array to save so that the last two words of the key label are toggle from on OFF to ON off.

5. Choose RETURN to return to the top menu.

See Appendix A for the definition of each array.

To Recall a Saved Analyzer Setting

- 1. Insert a disk (if you are recalling an instrument state le from the memory disk, skip this step).
- 2. Press (Recall).
- ^{3.} Select where the file is stored by pressing either ST0R DEV [DISK] (for a built-in disk drive) or STOR DEV [MEMORY] (for a memory disk).
- 4. Search for the filename you want to recall (the files are listed on the softkey label).
- $5.$ If a target file is not listed on the softkey label, turn the label page by pressing PREV FILES or NEXT FILES.

6. Press the softkey corresponding to the filename label.

To Save ^a Display Image to ^a TIFF File

- 1.1 Press I. Pave I. Prince μ
- ² Select where to store the file by pressing either STOR DEV [DISK] (for a built-in disk drive) or STOR DEV [MEMORY] (for a memory disk).
- $^3\cdot$ Enter filename. Then press DONE . $\,$

The analyzer saves a TIFF file with an extension, ".TIF" for a DOS format, or a suffix, " \mathbb{I} " for ^a LIF format.

If there is a file that has the same name you entered on the disk, the error message, "filename error" will be displayed. To save the file, use the other filename to save or purge the old file. To pure it was a pressed to present the same of the sa FILE UTILITIES PURGE FILE then select the displayed filename by pressing the associated softkey.

To Save Measured Data for a Spreadsheet

- 1. Insert ^a DOS format disk into the built-in disk drive.
- 2. Press Save
- ^{3.} Press SAVE ASCII .
- 4 Select the built-in disk drive as the storage device by toggling to STOR DEV [DISK].
- $^{\mathrm{D}}\cdot$ Enter a filename. Then press DONE .

The analyzer saves an ASCII file with a ".TXT" extension.

The measured data is saved as ASCII text. Each value is separated by a tab. When you open this file from the spreadsheet software, specify the file format as the "TEXT with TAB delimiter".

\Rightarrow			STATE.TXT							
	36.	\bf{B}	\mathbf{C}	. ev.	法自我犯	※円※※	ANGO	ात		
滋										
	6 CHANNEL: 1									
	MEASURE TYPE: R									
	8 FORMAT TYPE: SPECTRUM UNIT: dBm									
	9 NUMBER of POINTS: 801									
	10 SWEEP TIME: 60 ms									
	11 SWEEP TYPE: LIN FREQ									
	12 SOURCE POWER: 0 dBm									
	13 RBW: 30 kHz VBW: 30 kHz									
14										
	15 Frequency	Data Trace	Memory Trace							
16	$1.50F + 07$	$-9.04F + 01$	$0.00F + 00$							
$\overline{11}$	1.50F+07	$-9.52E + 01$	$0.00F + 00$							
18	1.50F+07	$-8.97F + 01$	$0.00F + 00$							
19	1.50F+07	$-9.65E + 01$	$0.00F + 00$							
20	$1.51F + 07$	$-8.94F + 01$	$0.00F + 00$							
21	$151F + 07$	$-8.83F + 01$	$0.00F + 00$							
$\frac{22}{23}$	$1.51F + 07$	$-9.37E + 01$	$0.00F + 00$							
	1.51F+07	$-1.00E + 02$	$0.00F + 00$							
$\frac{24}{25}$	1.51E+07	$-8.94E + 01$	$0.00E + 00$							
	1.51F+07	$-9.65F + 01$	$0.00F + 00$							
$\frac{26}{27}$	$1.51E + 07$	$-9.37E + 01$	$0.00E + 00$							
	1.51E+07	$-9.80E + 01$	$0.00E + 00$							
28	$1.52E + 07$	$-9.63E + 01$	$0.00E + 00$							
29	1.52F+07	$-9.80F + 01$	$0.00F + 00$							
बा	152E+07	$-963F + 01$	$0.005 + 00$						國	

Figure 8-10. Reading Saved Data from Spreadsheet Software

To Copy ^a File between Floppy Disk and Memory Disk

- \sim 1.1 essential external Γ .
- ^{2.} Press COPY FILE .
- ^{3.} Select a storage device where the file is stored by toggling either ST0R DEV [DISK] (for the build-in disk drive) or STOR DEV [MEMORY] (for the memory disk).
- 4. Search for the filename you want to recall (the files are listed on the softkey label).
- 5. If ^a target le is not listed on the softkey labels, turn the label page by pressing PREV FILES OF NEXT FILES .
- 6. Press the softkey corresponding to the filename label.
- 7. Enter the filename of the target file.
- $8.$ Select the target storage device by toggling STOR DEV [DISK] or [MEMORY] .
- ^{9.} Press DONE to copy the file.

You cannot copy a file between the LIF and DOS formats. When you want to copy a file on ^a DOS formatted disk to the memory disk, you must initialize the memory disk to the DOS format.

To Initialize a Disk for Use

Note Initializing the disk erases all data on the disk.

- The 4395A can initialize a 1.44 MB 3.5 inch flexible disk only.
- 1. Verify that the disk is not write protected.
- 2. Insert the disk.
- 3. Press (Save).

us

- $4\cdot$ Choose FILE UTILITIES .
- ^{5.} Choose INITIALIZE DISK .
- 8-22 Analyzing the Measurement Results
- $6.$ Select the disk format (either DOS or LIF) by toggling F0RMAT [D0S] or [LIF] .
- ^{7.} Toggle to STOR DEV [DISK] to select the disk drive.
- 8 Press INIT DISK: YES to initialize the disk.

To Initialize the Memory Disk for Use

Note Initializing the memory disk erases all data on the memory disk. Copy important files on the memory disk to a flexible disk before initializing the memory disk.

- 1. Press Save
- ^{2.} Press INITIALIZE DISK .
- 3 Select the disk format (either DOS or LIF) by toggling FORMAT <code>[DOS]</code> or <code>[LIF]</code> .
- 4 . Toggle to STOR DEV [MEMORY] to select the memory disk.

```
<sup>5.</sup> Press INIT DISK: YES .
```
The files on the memory disk are lost when the 4395A is turned off unless the memory disk is backed up using BACK UP MEMO DISK.

To Back Up the Memory Disk

The data (files and disk format) on the memory disk can be copied to a non-volatile memory (
ash memory) by memory disk backup operation. The backup copy data is recalled to the memory disk every time the 4395A is turned on.

- 1. Press (Save).
- $2\cdot$ Press BACK UP MEMO DISK.

- When you store important data into the memory disk, You must back up the memory disk using BACK UP MEMO DISK. Otherwise, the data on the memory disk is lost when the $4395A$ is turned off.
- Backup is also important as a means of recovering your precious data in the event of a power interruption or misoperation. For example, even if you inadvertently formatted the memory disk while using the 4395A, you could easily recover the data (files and disk format) from the backup copy; all you have to do is turn OFF and ON the 4395A.
- The memory disk can endure approximately $100,000$ cycles of backup operation.

Typical Network Measurement Techniques

This section provides the following typical measurement techniques using the network analyzer mode of operation:

- \blacksquare Measuring 3 dB bandwidth using the width function
- Measuring electrical length
- Measuring phase deviation
- Compensating for the electrical delay caused by an extension cable

Measuring ³ dB Bandwidth Using the Width Function

1. Do one of the following:

- 2. Press Marker AMODE MENU AMKR to make the marker a reference.
- °' I Less Loearch I W. WIDTH \overline{N} NIDTH VALUE .
- 4. Press 3 -1 to enter 3 dB.
- $5\cdot$ Toggle WIDTH on OFF to ON off .

As shown in Figure 8-11, ^a pair of sub-markers appear on both sides of the reference marker, being lowered by the specied number of levels; also, another sub-maker is displayed in the middle between the two sub-markers. The bandwidth (BW), center frequency of the bandwidth (cent), Q factor (Q), insertion loss (loss), and left and right hand bandwidth (ΔL . F and ΔR . F) are displayed at the upper right corner of the grid.

Figure 8-12 shows a typical example of a band pass filter measurement trace and describes each parameter. 0 will be returned for all parameters when two cutoff points can not be found.

You can move the reference marker using the rotary knob. When you enable the width function, the reference marker automatically turns into a tracking Δ marker that allows you to move the reference marker.

For more information on the width function, see Appendix A.

Measuring ³ dB Bandwidth Using the Width Function

Figure 8-11. Bandwidth Measurement Using Width Function

Figure 8-12. Parameters of ^a Band Pass Filter Measurement

Measuring Electrical Length

- \sim 1.1 ess Format Pri PHASE , and then select the desired phase format.
- 2. Do one of the following procedures:
	- Using the marker:
		- a. Press (Marker)
		- b. Turn the rotary knob to move the marker to the center of the display.
		- c. Press Cal MORE ELEC DELAY MENU.
		- $\mathrm{d.}$ Press MKR \rightarrow DELAY .
	- Using the rotary knob:
		- \ldots Trop call m MORE ELEC DELAY MENU
		- ^{D.} Press ELECTRICAL DELAY .
		- c. Turn the rotary knob until the trace becomes flat at the specified frequency.
- 3. Press ELECTRICAL DELAY . Then read the electrical length that is displayed under the electrical delay time.

Before Adding the Electrical Length After Adding the Electrical Length

If the average relative permittivity (ε_R) of the DUT is known over the frequency span, the length calculation can be adjusted to better indicate the actual length of the DUT. This can be done by entering the relative velocity factor for the DUT.

Measuring Electrical Length

Setting the Velocity Factor of ^a Cable

- 1. Press Cal.
- 2. Press MORE .
- ^{3.} Press VELOCITY FACTOR .
- 1. Enter a new value. Then press \cdots

The relative velocity factor for a given dielectric can be calculated by:

$$
V_f = \frac{1}{\sqrt{\varepsilon_R}}
$$

The velocity factor defaults to 1.

Measuring Phase Deviation

Deviation from the Linear Phase

- 1. Specify the frequency range.
- \sim Display the phase trace by pressing Format \sim
- \sim Adjust the scale settings by pressing Scale Ref μ AUTO SCALE . AUTO S
- 4. Press (Marker). Then move the marker to any of the points where the sloping trace crosses the center (place the marker on the sloping portion of the trace, not the vertical phase "wrap-around").
- 5.110001001111 $MORE$ ELEC DELAY MENU $MKR \rightarrow DELAY$ to add enough electrical length to match the phase slope present at the marker frequency.
- 6. Read the phase value as ^a deviation from the linear phase.

By adding the electrical length to flatten the phase response, the linear phase shift caused by the DUT is removed. The displayed response is the deviation from the linear phase.

To turn ^o the electrical length function, press cal MORE ELEC DELAY MENU

ELECTRICAL DELAY 0 -1.

Figure 8-14. Deviation from the Linear Phase

Group Delay

The phase linearity of many devices is specied in terms of group delay or envelope delay. This is especially true of telecommunications components and systems.

Group delay is the difference in propagation time through a device as a function of frequency. It is measured as a ratio of phase change over a sample delta frequency as follows:

$$
Group\;\,Delay\,=\,-\frac{\Delta\phi}{360\Delta F}
$$

Where: $\Delta\phi$ is phase change [deg]

 ΔF (commonly called the "aperture") is the frequency difference that gives $\Delta \phi$

1. Press (Format).

Measuring Phase Deviation

- 2. Press DELAY .
- \sim 1 Leps Scale Refinition Reference Re

The group delay format displays the phase deviation to the group delay aperture. Therefore, setting the group delay aperture affects the trace shape. Setting a wider aperture makes the trace smoother. The aperture defaults to 1% of the span.

Setting the Group Delay Aperture.

- 1. Press $\sqrt{\frac{B_W}{Avg}}$
- 2. Press GROUP DELAY APERTURE .
- 3. Enter group delay aperture value as ^a percentage of the span.

The group delay aperture is based on the number of points, not the real aperture. For example, if the number of points is 201, ^a 1% group delay aperture causes the 4395A to calculate the group delay using the adjacent measurement points on both sides. Therefore, the group delay trace may differ depending on the specified number of points.

Figure 8-15. Setting Group Delay Aperture

Compensating for the Electrical Delay Caused by an Extension Cable

If the Electrical Delay of the Extension Cable is Known

- -1.1 COO 1 Call 11 MORE PORT EXTENSIONS to open the port extension menu.
- 2. Enter the electrical delay values for the respective input ports.
	- If you do not use the S-parameter test set, follow these steps:
		- \Box Press EXTENSION INPUT R. Then enter the electrical delay of the cable that is connected to the ^R input.
		- \square Press EXTENSION INPUT A. Then enter the electrical delay of the A input.
		- \Box Press EXTENSION INPUT B. Then enter the electrical delay of the B input.

If you use the transmission/reflection (T/R) test set, enter the electrical delay of the cable that is connected to the TEST PORT (for the ^R and ^A inputs).

Figure 8-16. Port Extension With the T/R Test Set

- If you use the S-parameter test set, follow these steps:
	- Enter "0" for EXTENSION INPUT R, EXTENSION INPUT A and EXTENSION INPUT B to clear the port extension of the R, A and B inputs.
	- \Box Press EXTENSION PORT 1. Then enter the electrical delay of the PORT 1.
	- \Box Press EXTENSION PORT 2. Then enter the electrical delay of the PORT 2.
- ^{3.} Toggle EXTENSION on OFF to ON off to enable the port extension.

Compensating for the Electrical Delay Caused by an Extension Cable

If the Electrical Delay of the Extension Cable is Unknown

You can determine the electrical delay of the extension cable by:

- Measuring the electrical delay of the cable
- Measuring the cable's reflection in the OPEN or SHORT circuit state.

Measuring the Electrical Length of ^a Cable.

- 1. Connect the cable as shown in Figure 8-17.
- 2. Define the frequency range according to the measurement conditions.
- \sim 1.1000 Meas Measure B/R (or S PARAMETERS Trans: FWD S21 [B/R]) to select the transmission measurement.
- 4. Press Format PHASE to select the phase format.
- 5. Press (Marker). Then move the marker to the sloping trace that crosses the center of the display.
- \sim 1.000 [Call 110] NORE ELEC DELAY MENU MKR-DELAY ELECTRICAL DELAY, then read the electrical delay of the cable.
- 7. Press 0 -1 to clear the electrical delay oset.
- 8. Enter a measured electrical delay as described in the \If the Electrical Delay of the Extension Cable is Known" procedure.

Figure 8-17. Cable Measurement Conguration (Transmission) Reflection of a Opened or Shorted Cable.

- 1. Connect the cable as shown in Figure 8-18.
- 2. Define the frequency range according to the measurement conditions.
- \sim 1.1 \sim 3.3.1 Meas Press Magnetic Measure A/R (or S PARAMETERS Refl:FWD S11 A/R) to select the reflection measurement.
- \cdots Press Formation \cdots Phase to the phase format. The phase format in the phase format of the phase format in the phase format of the
- 5. Press (M arker). Then move the marker to the sloping trace that crosses the center of the display.
- 5.1000×1000 MORE ELEC DELAY MENU MKR-DELAY ELECTRICAL DELAY, then read the electrical delay of the cable.

Note that this value is twice the real delay because there are both output and return paths.

- 7. Press 0 -1 to clear the electrical delay oset.
- 8. Enter half the value of the measured electrical delay as described in the "If the Electrical Delay of the Extension Cable is Known" procedure.

Figure 8-18. Cable Measurement Configuration (Reflection)

Typical Spectrum Measurement Techniques

This section describes typical spectrum measurement techniques. The topics covered include:

- Measuring the noise level
- Measuring the carrier to noise ratio
- \blacksquare Performing the time gated spectrum analysis
- Measuring zero span (time domain measurement)
- Tracking unstable harmonics using the search track function

Measuring the Noise Level

- 1. Press (Format).
- $^{\mathrm{2}}$. Choose NOISE.
- 3. Press $\sqrt{\frac{S_{\text{Calc}}}{S_{\text{cale}}}}$ Ref. Then press $\boxed{\mathbb{F}}$ until the noise trace gets close to the reference level.
- $4.$ Press (Bw/Avg). Then press VIDEO BW .
- 5. Press $\left(\mathbb{T}\right)$ to flatten the noise trace.
- 6. Press (Marker). Then turn the $\widehat{\{\circ}\}$ and read the normalized noise level.

The marker readout unit becomes " dBm/Hz " and is normalized by the 1 Hz equivalent noise bandwidth (ENBW). To convert the ENBW, see the "Converting to a Different Unit of Equivalent Noise Bandwidth" procedure.

Note Switching the display to a noise format causes the 4395A to perform detection in sample detection mode. Subsequently returning the format to (Format) SPECTRUM causes the 4395A to perform detection in positive peak detection mode. This is true even if you have selected the negative detection mode before switching to the noise format.

Converting to a Different Unit of Equivalent Noise Bandwidth

1. Calculate the conversion factor using the following equations with displayed units:

2. Where, BW is the target equivalent noise bandwidth.

Measuring the Noise Level

- $3.$ Press $\widehat{\mathsf{D}}$ isplay) and choose <code>DATA MATH []</code> .
	- Choose OFFSET for dBm/Hz , dBV/\sqrt{Hz} , and $dB\mu V/\sqrt{Hz}$.
	- Choose GAIN for V/\sqrt{Hz} and W/Hz .
- 1.4 Enter K, then press 1.4 .

Note The 4395A displays dBV/\sqrt{Hz} , $dB\mu V/\sqrt{Hz}$, V/\sqrt{Hz} as dBV/Hz, dB μ V/Hz, V/Hz respectively. 떫

Measuring the Carrier to Noise Ratio

- 1. Set up the frequency range within which to measure a carrier signal.
- 2. Press $(Marker)$ to place the marker on the trace.
- 3. Press (Scale Ref) and choose PEAK \rightarrow REFERENCE to set the reference level to the carrier signal level.
- 4. Adjust the scale/div to display the carrier and noise oor. Use Scale Ref SCALE/DIVIDENTIAL AND THE RESIDENCE OF A RESIDENCE
- ^{5.} Press (Marker) and choose AMODE MENU AMKR to place the reference marker on the carrier signal.
- $6.$ Press (Bw/Avg). Then choose <code>VIDEO BW</code> .
- 7. Enter an appropriate video bandwidth to reduce the variation.
- 8. Press (Marker). Then do either of the following:
	- Enter the offset frequency using the numeric keys.
	- Move the marker into the noise level of the trace using the rotary knob.
- 9. If you want to normalize the marker readout with the RBW filter, press $\overline{(Utility)}$ and toggle NOISE FORM on OFF to ON off .
- 10. Read the difference from the reference marker.

Time Gated Spectrum Analysis

The time gated spectrum analysis function can be used to measure any one of several signals separated in time (for example, burst modulated, pulsed RF, and time multiplexed). Using the gated sweep function allows the analyzer to measure the spectrum of a specific part of the signal or separate signals, and mask out interfering or transient signals. In the gated sweep mode, the analyzer is triggered to start and interrupt sweep selectively by an external trigger signal. By controlling the external trigger signal, the analyzer measures only the signals that are present when the analyzer sweeps.

The gate sweep is controlled by the following factors:

- Trigger polarity, which determines which positive or negative edge (level) causes triggering
- Gate trigger mode, which selects one of two modes (EDGE or LEVEL)
- Gate Delay, which determines how long after the trigger signal the gate actually becomes active.
- Gate Length, which determines how long the gate is on.

Gate Trigger Mode

Two gate trigger modes (EDGE and LEVEL) are provided for the gate trigger to match the trigger signal used.

Edge Mode. The edge mode allows you to position the gate relative to either the rising or falling edge of ^a TTL trigger signal. The edge initiates the gate delay. For the edge mode, the gate sweep is controlled by the following factors:

- Trigger polarity, which selects the edge (positive or negative) to initiate the start point of the gate sweep. At the start point, the edge initiates the gate delay.
- Gate Delay, which determines how long after the trigger signal the gate actually becomes \blacksquare active.
- Gate Length, which determines how long the gate is on.

Figure 8-21. Edge Mode

Measuring the Carrier to Noise Ratio

Level Mode. The level mode allows the external trigger signal to open and close the gate directly, without ^a programmed gate length. The level mode also provides the gate delay. For the level mode, the gate sweep is controlled by the following factors:

- **Trigger polarity, which selects the polarity of TTL the level (+5 V or 0 V) to open gate.**
- Gate Delay, which determines how long after the trigger signal the gate becomes active.

Figure 8-22. Level Mode

Measuring the Carrier to Noise Ratio

RBW Filter Response Time

You don't need to care about the setting time for the RBW filter because the 4395A implements the RBW filter using digital processing.

Video bandwidth (VBW) can be set without concern for the gate length setting. The analyzer implements the video filter using digital processing. The video filter of the analyzer requires no settling time for normal operation. Therefore, it is not affected by the gate length setting.

Time gated spectrum analysis involves the following steps:

- 1. Determining the Gate Trigger Parameters
- 2. Connecting the Gate Trigger Source
- 3. Setting the Center and Span Frequency
- 4. Adjusting the Gate Trigger
- 5. Setting the RBW/VBW and Using the Averaging Function
- 6. Measuring the Spectrum

Note Performing this measurement requires Option 1D6.

Step 1: Determining the Gate Trigger Parameters.

1. Connect the target signal and the trigger signal to the input port of an oscilloscope (see Figure 8-23).

Figure 8-23. Time Domain Measurement Conguration

- 2. Adjust the oscilloscope to display the two signals.
- 3. Using the oscilloscope, check the following parameters:
	- For the target signal:
		- \Box Pulse repetition width (PRI) \Box Signal width (τ) \Box Signal delay (SD)
	- \blacksquare For the trigger signal:
		- \Box Pulse width (if you use the level trigger mode)

The signal delay (SD) is the delay inherent in the signal (that is, SD isthe length of time after the trigger, but before the signal of interest occurs and becomes stable).

Figure 8-24. Target and Trigger Signal Timing on the Oscilloscope

- 4. Determine the gate parameters using the following equations:
	- Gate delay = $SUT + SD$

Figure 8-25 shows the scheme of these parameters.

Open the "gate" during the time the signal is in a stable condition. The time from the start time of a signal and the open time of a gate is the "set up time" (SUT).

Figure 8-25. Gate Parameters

Step 2: Connecting the Gate Trigger Source.

- 1. Connect the RF signal source to the ^R input of the 4395A.
- 2. Connect the trigger output from the signal source to the EXT TRIGGER connector on the rear panel of the 4395A.

Set up the center and span frequency of the 4395A to display the target signal.

Step 4: Adjusting the Gate Trigger.

- \sim 1.1 \sim Press Trigger Trigger CONTINUOUS to activate ^a gate trigger.
- 2 -Choose TRIGGER: [] . $\,$
- ^{3.} Choose GATE [] .
- ⁴. Select the gate control mode. Select LEVEL or EDGE by toggling GATE CTL: LEVEL and EDGE to the required mode.
- 5. If you have selected the LEVEL trigger mode, set the trigger polarity for starting the gate. Press RETURN. And then toggle TRIG PLRTY to POS neg (positive) or pos NEG (negative).
- $^6\cdot$ Choose GATE $\,$ T $\,$ GATE DELAY . $\,$
- 7. Set a gate delay time.
- $8.$ If you have selected the EDGE trigger mode, choose GATE LENGTH . Then set the gate open length.

You can see the gate trigger status by monitoring the GATE Output terminal using an oscilloscope. The GATE Output terminal is located on the 4395A's rear panel.

Setting the RBW/VBW and Using the Averaging Function

Setting the Resolution Bandwidth.

- 1. Press $\left(\frac{Bw}{Ay}\right)$.
- ². Press RES BW and set the resolution bandwidth in accordance with Table 8-1.

You must specify a gate length longer than the minimum gate length listed in Table 8-1. Otherwise, the sweep does not start.

RBW	Minimum Gate Length ¹
1 MHz	$6 \ \mu sec$
300 kHz	$22 \ \mu$ sec
100 kHz	44 µsec
30 kHz	$170~\mu$ sec
10 kHz	$660 \ \mu sec$
3 kHz	1.4 msec
1 kHz	5.3 msec
300 Hz	22 msec
100 Hz	43 msec
30 Hz	170 msec
10 _{Hz}	680 msec
3 Hz	1.4 sec
1 Hz	Gated sweep is not available. ²

Table 8-1. Allowable RWB Settings and Minimum Gate Length

1 If the gate control mode is "level", add the gate delay setting to the listed value.

25.5 sec when the gate control mode is "level".

Setting the Video Bandwidth (VBW).

- $1\cdot$ Choose VIDEO BW.
- 2. Set the video bandwidth.

You can set any video bandwidth (VBW) without concern for the gate length setting. The 4395A implements the video filter using digital processing. The video filter of the 4395A requires no settling time for normal operation. Therefore, it is not affected by the gate length setting.

You can also use the averaging function to reduce the variation of the trace.

Measuring the Spectrum.

- 1. Adjust the span setting to fit the trace to your requirement.
- 2. Perform your measurement.

Figure 8-27. Time Gated Spectrum Analysis

Measuring Zero Span

- 1. Determine the following parameters:
	- Sweep Time
	- Number of Display Points (NOP)
- 2. Press (Center). Then enter the frequency of the target signal.
- ^{3.} Press $\overline{S}_{\text{Dan}}$ and choose ZERO SPAN to set the frequency span to 0 Hz.
- 4. Press (Sweep)
- ^{5.} Press (Sweep) and choose SWEEP TIME, and then enter the sweep time.
- ^{6.} Press (Sweep) and choose NUMBER of POINTS . Then enter your desired number of points . (NOP).

Note **Table 8-2 lists default settings when the span is switched to normal span or** zero span in spectrum analyzer mode.

Default Settings When Switched to Normal Span or Zero Span

¹ Sweep time mode can not be changed in spectrum analyzer mode.

² Number of display points

- You must specify an RBW equal to or greater than 3 kHz. If your specied value is smaller than 3 kHz, the 4395A automatically sets the RBW to 3 kHz.
- When you change the sweep time in zero span measurement of spectrum analyzer mode, the sweep time is limited by the number of display points. If you want to set a shorter sweep time than the limited sweep time, reduce the number of display points with Sweep points with NUMBER of POINTS , and then set a desired sweep time with SWEEP. If you want to set a longer sweep time than the limited sweep time, increase the number of display points, and then set a desired sweep time.
- The minimum time resolution and maximum sweep time in measuring zero span are listed in Table 8-3.

RBW	Min. Time Resolution	Max. Sweep Time $(NOP = 801)$
5 MHz	40 nsec	1.28 msec
3 MHz	40 nsec	2.56 msec
1.5 MHz	80 nsec	5.12 msec
800 kHz	160 nsec	10.24 msec
400 kHz	320 nsec	20.48 msec
200 kHz	640 nsec	40.96 msec
100 kHz	1.28 μ sec	81.9 msec
40 kHz	$2.56 \ \mu$ sec	163.8 msec
20 kHz	$5.12 \ \mu$ sec	327.7 msec
10 kHz	10.24 μ sec	655.4 msec
5 kHz	$20.48 \ \mu sec$	1.311 sec
3 kHz	$40.96 \ \mu$ sec	2.621 sec

Table 8-3. Minimum Time Resolution

 \blacksquare The 4395A uses an exclusive filter for 5 MHz resolution bandwidth to improve the response time. Accurate measurements with ^a ⁵ MHz RBW require the center frequency to be equal to the signal frequency.

Reading Transition Time Using the Marker

- 1. Press (Utility)
- $^2\cdot$ Toggle MKR TIME on OFF to ON off .
- \degree Move the marker using the \degree \degree .
- 4. Read the transition time that is displayed on the upper right of the grid.

When you are measuring the zero span, the marker displays the same frequency on every point of trace. Using the marker time function, you can change have the 4395A display time values instead of frequency. The marker displays transition time from the left end of the grid.

Tracking Unstable Harmonics Using the Search Track Function

- 1. Set the frequency range to display the carrier and the harmonics.
- 2. Press \overline{Search} and choose SEARCH: PEAK to move the marker to the peak.
- 3 Press Marker) and choose AMODE MENU TRACKING AMKR to set up the marker as a reference Amarker that can move with the carrier.
- 4. Press Search) and toggle SEARCH TRK on OFF to ON off to cause the search function to be activated every time the 4395A performs ^a sweep process.
- $5.$ Choose MULTIPLE PEAKS PEAKS RIGHT to search for the carrier and harmonics under the $\,$ search track.
- 6. Press (Utility). Then toggle MKR LIST on OFF to ON off .

Even if the frequency of ^a carrier changes, the 4395A automatically tracks the carrier and the harmonics at the end of the sweep. Then the analyzer lists the difference between the carrier and the harmonics in the lower half of the screen.

If you wish to ignore the peaks other than the harmonics, you can use the peak threshold. For more information, See "To Define the Peak for Search (To Ignore Unnecessary Peaks)".

Figure 8-29. Tracking Unstable Harmonics Using Search Track

Typical Impedance Measurement Techniques

This section describes typical impedance measurement techniques. The topics covered include:

- Applying DC bias
- Equivalent circuit analysis
- Determining ^Q value using the width search function
- **Port extension**

Applying DC Bias

The 4395A option 001 DC source can be used to supply up to ± 40 V / ± 100 mA of DC voltage/current to external circuit or DUT through the DC SOURCE port on the front panel.

This section explains how to supply DC bias to the DUT on impedance measurement mode.

- 1. Make sure that the $4395A$'s DC SOURCE port is inactive. (The softkey label under $\sqrt{3}$ should be DC OUT on OFF .)
- 2. Connect ^a BNC cable between the DC SOURCE port and the impedance test kit's DC SOURCE INPUT port (see Figure 8-30).

The 4395A can apply DC voltage bias up to $\pm 40V$ or dc current bias up to ± 20 mA.

Figure 8-30. Connecting DC SOURCE to Impedance test kit

Caution Do not attempt to perform calibration or fixture compensation while the 4395A is applying DC bias. Doing so could damage the calibration or fixture compensation standard.

Typical Impedance Measurement Techniques

Setting the Upper Limit for DC Bias

The 4395A can control DC bias so that ^a user-specied upper limit (current or voltage) is not exceeded. This feature ensures that the device under DC bias is protected from excessively high voltage or current.

DC bias can be applied in one of two modes: current control and voltage control. You can set the upper limit voltage for current control mode, or the upper limit current for voltage control mode.

Caution Before applying DC bias, you must set the upper limit to protect the DUT.

To set the DC bias upper limit, follow these steps:

- 1. Press (Source)
- 2. Select one of the following two options:
	- \blacksquare To apply DC bias in voltage control mode, toggle DC SRC [CURRENT] to DC SRC (2008) . DO SRC [VOLTAGE] . DO SRC (2009) . DO SRC (2009) . DO SRC (2009) . DO SRC (2009) . DO SRC (200
	- \blacksquare To apply DC bias in current control mode, toggle DC SRC [VOLTAGE] to DC SRC [CURRENT] . DO SRC [CURRENT]
- 3. Set the upper limit voltage or current.
	- \blacksquare For voltage control mode, choose DC CURRENT LIMIT and enter the upper limit current using the numeric keys.
	- For current control mode, choose DC VOLTAGE LIMIT and enter the upper limit voltage using the numeric keys.

Setting up and Applying Output Voltage/Current

- 1. Press (Source)
- ². Press DC VOLTAGE (for voltage control mode) or DC CURRENT (for current control mode). and enter output DC voltage or current using the numeric keys.
- 3. Toggle DC OUT on OFF to ON off to apply the DC voltage or current to the DUT.

Equivalent Circuit Analysis

The 4395A provides a function that automatically calculates approximate values of specific parameters of an equivalent circuit that corresponds to a DUT. This function supports five circuit models. In addition, the resulting parameter values can be used to simulate the frequency-based characteristics of the equivalent circuit; this allows you to compare the simulated characteristics with the actually measured characteristics.

Menus Associated with Equivalent Circuit Analysis

To use the equivalent circuit analysis function, open the *Equivalent Circuit Menu* by pressing (D_{isplay}) and choosing EQUIV KIT MENU. The *Equivalent Circuit Menu* provides access to two submenus: Select Equivalent Circuit Menu and Define Equivalent Circuit Parameter Menu.

These three menus are described in this section.

Equivalent Circuit Menu. You can open the equivalent circuit analysis menu by pressing $(Display)$ and choosing MORE EQUIV KIT MENU. This menu provides such options as for calculating the equivalent circuit parameters or simulating the equivalent circuit's characteristics under swept frequency.

Typical Impedance Measurement Techniques

Select Equivalent Circuit Menu. This menu lets you to select one of the five supported circuit models. The 4395A calculates the parameter values within the range you specied using the marker search function.

Define Equivalent Circuit Parameter Menu. This menu lets you enter the equivalent circuit parameter values.

As shown in Table 8-4, each equivalent circuit model is suitable for analyzing specific type(s) of device.
Typical Impedance Measurement Techniques

Table 8-4. Equivalent Circuit Selection Guide

Typical Impedance Measurement Techniques

Using the Equivalent Circuit Analysis Function

Calculating Approximate Values of Equivalent Circuit Constants.

- 1. Press $\overline{Display}$ and choose MORE EQUIV CKT MENU to display the equivalent circuit menu.
- ^{2.} Choose SELECT CKT $\lceil \cdot \rceil$ to display the equivalent circuit models.
- 3. Select one of the following:

4. Choose CALCULATE EQV PARAM to calculate the equivalent circuit parameters.

After ^a beep, the calculated equivalent parameters are displayed on the screen. To hide the equivalent parameters, press $\overline{Display}$ and choose MORE EQUIV CKT MENU. Then toggle DISP EQV PARM JONN to JOFF].

You can simulate ^a frequency characteristic trace from the equivalent circuit parameters obtained and compare it with the measured trace.

- \sim TIC 00. FLORE DISPLASS MORE EQUIV CKT MENU.
- 6 . Choose SIMULATE F-CHRST .

After a beep, the simulated trace is displayed. The simulated trace is stored in the memory trace. To turn off the simulated trace, press $\overline{Display}$ and choose DISPLAY $\begin{bmatrix} 1 &$ DISPLAY: DATA, DISPLAY: DATA .

Simulating ^a Trace from the Equivalent Circuit Parameters. You can also simulate the frequency characteristics of an equivalent circuit by entering its parameters.

- 1. Press $\overline{\text{Display}}$ and choose MORE EQUIV CKT MENU to display the equivalent circuit menu.
- ². Choose SELECT EQV CKT $\lceil \cdot \rceil$ to display the equivalent circuit models.
- $^3\cdot$ Select the equivalent circuit model. Then choose RETURN . $^3\cdot$
- $^{\mathrm{4.}}$ Choose DEFINE EQV PARAMS .
- 5. Enter the equivalent circuit parameter value for the activated parameters.
- 6. Choose SIMULATE F-CHRST to simulate the frequency characteristics.

After a beep, the simulated frequency characteristics are displayed.

Determining ^Q Value Using the Width Search Function

The width search function analyzes ^a resonator and displays the center point, width, and quality factor (Q) for the specied bandwidth.

To use the width search function, open the *Widths Menu* by pressing $\sqrt{\frac{3}{2}}$ and choosing WIDTH AND MENU PROVIDES ALL AND MENU PROVIDED AT A SUBMER AND MENU PROVIDED AND MENUSIAS TO ANNOUNCE WHEN THE MENU lets you specify the bandwidth search criteria.

These two menus are described in this section.

Widths Menu

This menu controls the width search function.

Width Value Menu

This menu lets you specify the search criteria for the width search function.

Typical Impedance Measurement Techniques

Figure 8-31 shows an example of using the bandwidth search function.

Figure 8-31. ^Q Measurement Examples

Using the Anti-Resonance Point

- 1. Press (Search) to make the marker active.
- ^{2.} Toggle SEARCH TRK on OFF to ON off . Then choose MAX to move the marker to the anti-resonance point on the trace.
- 3. Press Search and choose WIDTH \lceil] WIDTH VALUE MKRVAL/($\sqrt{2}$) RETURN.
- ^{4.} Toggle WIDTH on OFF to ON off. The width value, Q factor, and several parameters are displayed on the screen.

Using the Resonance Point

- 1. Press (Search) to make the marker active.
- ^{2.} Toggle SEARCH TRK on off to 0N off. Then choose MIN to move the marker to the resonance point on the trace.
- 3. Press Search and choose WIDTH [] WIDTH VALUE MKRVAL*(,/2) RETURN.
- ^{4.} Toggle WIDTH on OFF to ON off. The width value, Q factor, and several parameters are displayed on the screen.

Using the Admittance Chart

1. Press $\overline{[Utility]}$ to make the marker active. Then choose SMTH/POLAR MENU $\overline{G+1}B$ to read conductance and susceptance (assuming that the admittance circle has been displayed on the admittance chart).

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- 2 . Press (Search) and toggle SEARCH TRK on OFF to ON off . Then choose MAX to move the marker to the point where the ^G value is maximum on the trace (resonance point).
- 3. Press Search and choose WIDTH [] WIDTH VALUE MKRVAL/2 RETURN
- ^{4.} Toggle WIDTH on OFF to ON off. The width value, Q factor, and several parameters are displayed on the screen.

The 4395A searches half of the maximum conductance points on the admittance circle.

Port Extension

The 43961A impedance test kit has ACP-7 connectors that are intended for direct connection with a test fixture. However, you can use the 4395A's port extension feature to connect an extension cable between the test kit and fixture.

Note

You must determine the electrical length of the extension cable before using it with the aid of the port extension feature.

Follow these steps:

- 1. Connect the cable to the APC-7 connector of the 43961A impedance test kit.
- $2.$ Press (Cal) and choose <code>MORE PORT EXTENSION</code>
- $^3\cdot$ Choose EXTENSION VALUE and enter the equivalent electrical length using the numeric keys.
- $4.$ Toggle EXTENSION on OFF to ON off . $\,$
- 5. If the cable's velocity factor is known, you can set the cable length more accurately. To set the velocity factor, press \overline{Cal} and choose MORE VELOCITY FACTOR.

Advanced Techniques for Optimizing **Measurements**

This chapter introduces you to advanced measurement techniques on using the 4395A that have not been covered in the previous chapters. It explains how to use these techniques to optimize your measurement tasks.

Topics covered include:

- Reducing sweep time (using list sweep)
- Improving dynamic range
	- \Box Adjusting the IF bandwidth
	- \Box Using list sweep function
- Performing GO/NO-GO test of a filter (using limit line)
- \blacksquare Simultaneous measurement with different settings (using dual channel)
- Stabilizing the trace

Reducing Sweep Time (Using List Sweep)

The analyzer has a list sweep function that can sweep frequency according to a predefined sweep segment list. Each sweep segment is independent. For the network/impedance analyzer mode, each segment can have a different number of sweep points, power level, and IF bandwidth value. For the spectrum analyzer mode, each segment can have a different number of points and RBW. Furthermore, the output voltage or current at DC SOURCE port can be set for each segment in all analyzer modes (option 001 only). This section covers:

- Planning the sweep list
- Editing a sweep list
- Executing the List Sweep

Planning the sweep list

1. Specify sweep segments.

^A segment looks like ^a normal sweep setting. The list sweep function can combine up to ⁵¹ segments settings for network or impedance analyzer mode and ¹⁵ segments settings for spectrum analyzer mode into 1 sweep.

You may want to use the list sweep function primarily to reduce the time required for the sweep process. The 4395A does not require that the sweep segments be contiguous. Therefore, you can speed up the sweep process using the following strategy:

Differentiate the sweep range of interest from other sweep ranges in terms of the number of points (Figure 9-1).

Figure 9-1. Reducing Sweep Time by Optimizing the Number of Display Points

2. Determine the following parameters before editing the sweep list.

Editing ^a Sweep List

- 1. Press Sweep Pol SWEEP TYPE MENU EDIT LIST to call the sweep list editor.
- 2 Press EDIT to edit the sweep list.

Figure 9-2. List Sweep Editor

- 3. Enter the frequency range of the segment.
	- Move the marker to the start point. Then press SEGMENT: MKR-START.
	- Move the marker to the stopping point. Then press $MKR \rightarrow ST0P$.
	- Press $\overline{\text{Start}}$ to enter the start sweep parameter. Then press $\overline{\text{Stop}}$ to enter the stop sweep parameter.
- 4. Press MORE NUMBER of POINTS. Then enter the number of points for the segment.
- 5 . Press P0WER. Then enter the output power level for the segment. (NA, ZA mode only)
- 6. Set the internal filter bandwidth:
	- When in spectrum analyzer mode, press RES BW to set the resolution bandwidth.

Reducing Sweep Time (Using List Sweep)

- When in network or impedance analyzer mode, press IF BW to set the IF bandwidth.
- ^{7.} Press DC VOLTAGE or DC CURRENT and enter DC output voltage or current.
- 8 Press RETURN SEGMENT DONE to complete editing the segment.
- $^9\cdot$ Press ADD to edit the next segment.
- 10. Repeat steps 3 through 9 until you complete editing of all required segments.
- 11. When you finish editing all the segments, press LIST DONE to complete the sweep list.

The segments do not have to be entered in any particular order. The analyzer automatically sorts them in increasing order of sweep parameter value.

Figure 9-3. Sweep List Edit Display

To Modify or Delete the Segment

- \sim 1.1 \sim 99.1 \sim 1.1 \sim SWEEP TYPE MENU EDIT LIST SEGMENT.
- 2. Select the segment you want to delete or modify:
	- Enter the segment number you want to modify. Then press -1.
	- Move the cursor, " $>$ ", to the segment you want to modify by using the \mathbb{F} , the \mathbb{F} , or the \circ
- 3. Do either of the following:

4. When you finish editing, press LIST DONE.

Executing the List Sweep

- 1. Press (Sweep).
- 2 . Press SWEEP TYPE MENU .
- ^{3.} Press LIST FREQ .
- ^{4.} If you use the DC output, press Source. Then toggle DC 0UT on OFF to 0N off .

Notes

If you want to delete an edited sweep list, press Sweep SWEEP TYPE MENU EDIT LIST CLEAR LIST CLEAR LIST YES LIST DONE .

You can save and recall the edited sweep list with all other instrument settings by pressing Save STATE . See An Analyzer See Andrews and Setting and Measurement Data in Chapter 8 for more and an Analyzer Set information.

Improving Dynamic Range (NA Mode)

This section introduces you two techniques for enhancing the dynamic range of 4395A. These

- **Adjusting the IF Bandwidth**
- **Using List Sweep**

You can increase the dynamic range by applying the highest allowable power. The output power can be set by pressing Source

Averaging can also enhance the dynamic range. See "To Use the Averaging Function" for further information.

Adjusting the IF Bandwidth

Adjusting the IF bandwidth can lower the noise flower. For example, if you changed the IF bandwidth to 1/10 of the current setting (say, ¹⁰⁰ Hz instead of ¹ kHz), the measurement noise floor would lower by approximately 10 dB. This technique increases the dynamic range, but slows down the sweep process.

- 1. Press $\left(\frac{\text{Bw}}{\text{Avg}}\right)$.
- $2\cdot$ Press IF BW.
- 3. Press \mathbb{F} or \mathbb{F} , or enter an IF bandwidth value directly from the numeric keypad.

IF Bandwidth 30 kHz **IF Bandwidth** 100 Hz

Figure 9-4. Setting IF Bandwidth (IFBW)

Using List Sweep

Figure 9-5 shows the sweep list modied from the list of the previous example(Figure 9-3) to improve dynamic range. Segments ¹ and 3 have a narrow IF bandwidth and a higher power level for the stopband of the filter. Segment 2 has a wide IF bandwidth and lower power level for passband.

- \sim 1.1 \sim \sim 1.0 \sim 1.0 SWEEP TYPE MENU EDIT LIST .
- ^{2.} To modify segment 1, press SEGMENT Ω $\overline{\chi_1}$ El
- 3 . Press POWER 15 $\overline{\times}$ 11 IFBW ³⁰ -1
- 4. To modify segments ² and 3, see Figure 9-5 for the values and modify them in a manner similar to steps ² and 3.
- 5. Press LIST DONE .
- $^6\cdot$ Press LIST FREQ .

Figure 9-5. Dynamic Range Enhancement

Performing GO/NO-GO Test of a Filter (using limit line)

The limit line is constructed by connecting the segment points as shown in Figure 9-6.

Figure 9-6. Limit Line Image

For example, if you want to specify four points for the limit test, the limit line image is as shown in Figure 9-7. Each point has frequency information and an upper and a lower limit value. Enter these values as described in the "Editing a Limit Line Table" procedure.

Figure 9-7. Frequency, Upper and Lower Limit

In this example, the limit line connects four limit points. If a measured trace exceeds the upper or lower limit line, the limit test fails.

This section covers:

- Planning the Limit Line
- Editing a Limit Line Table
- Executing a Limit Line Test
- To Offset the Limit Line

Planning the Limit Lime

1. Determine the following parameters before editing the limit line:

Editing ^a Limit Line Table

- 1. Set up the frequency range of the grid before starting the limit line edit.
- 2. If you want to use marker to set the segment, press (Marker)
- 3. Press (System).
- $^{\rm 4.}$ Press LIMIT MENU. Then toggle LIMIT LINE on OFF to ON. This makes it easier to understand the status of the limit line while you are editing it.
- $5.$ Press EDIT LIMIT LINE to call the limit line editor. $\,$
- 6 If an old limit line table is still in the limit line editor, press CLEAR LIST CLEAR LIST YES $\,$ to clear it.
- 7. Press EDIT to edit the first segment.

Figure 9-8. Limit Line Editor

8. Enter the frequency of the segment in one of the following ways:

Performing GO/NO-GO Test of a Filter (using limit line)

- **Press SWP PARAM.** Then enter the frequency of the segment.
- Move the marker to the point you want to use as the frequency of the segment. Then press MKR-SWP PARAM.
- $^9\cdot$ Press UPPER LIMIT . Then enter a upper limit value.
- $10.$ Press LOWER LIMIT. Then enter a lower limit value.
- $11.$ Press DONE to end editing the segment.
- $12.$ Press ADD to edit the next segment.
- 13. Repeat steps 7 through 11 until all segments are defined.
- 14 . When you finish editing all segments, press DONE to complete editing the limit line table.

You can enter the limit value using the middle and width method by pressing MIDDLE VALUE and DELTA LIMIT. You then enter the amplitude value as a middle amplitude value with a delta limit. The upper and lower limit lines appear at an equal positive and negative distance from the specied middle amplitude.

To Modify or Delete the Segment

- \sim 1.1000 TO A 2000 IT THE \sim $LIMIT$ MENU EDIT LIMIT LINE SEGMENT.
- 2. Select the segment you want to delete or modify:
	- Enter the segment number you want to modify. Then press -1.
	- Move cursor, ">", to the segment you want to modify by using the (\mathbb{R}) , the (\mathbb{R}) , or the \mathbb{R}^2 .
- 3. Do either of the following:

Executing a Limit Line Test

To Make a Limit Line Test Active

- 1. Press (System).
- ^{2.} Press LIMIT MENU.
- $^{\rm 3.}$ Toggle LIMIT TEST on OFF to ON off .

If the limit line test passes, a green PASS message appears on the right of the grid. If it fails, a red FAIL message is displayed. You can set the analyzer to beep if the limit line test fails. (See the "To Beep When the Limit Test is Failed" procedure.)

To Beep When the Limit Test is Failed

- 1. Press (System).
- 2. Press LIMIT MENU.
- $^3\cdot$ Toggle BEEP FAIL on OFF to ON off .

To Offset the Limit Line

- \sim 1.1 e spot System \sim 1.
- $^{\mathrm{2.}}$ Press LIMIT LINE OFFSETS .
- 3. Press the following keys:

4. Then move the limit line by entering an offset value using one of the following:

- 5. To move the limit line vertically to the marker position:
	- a. Press (Marker) Then move the marker to the point you want to set as the offset value.
	- \sim Press System Press LIMIT MENU LIMIT LINE OFFSETS MKR-> AMP. OFS. .
- $^{6}\cdot$ When you are finished offsetting the limit line, press RETURN . $\,$

Figure 9-10. Offsetting Limit Lines

To clear the offset, enter 0 for all the offset values.

Stabilizing the Trace

When the trace is not stable and the marker value changes frequently, it is difficult to read the measured value. You can use the following techniques to stabilize the trace:

- Stop the sweep.
- Use the averaging function.
- Use the maximum or minimum hold function.
- Capture the unstable signal using signal track.

To Stop the Sweep

- 1. Press (Trigger).
- $2\cdot$ Press SWEEP: HOLD.

The sweep is stopped immediately (even if the sweep is in progress). If you want to restart the sweep, press CONTINUOUS to start a free-run sweep or press SINGLE to make a single sweep.

To Use the Averaging Function

- 1. Press $\sqrt{\frac{Bw}{Avg}}$.
- $2\cdot$ Press AVERAGING FACTOR .
- 3. If needed, enter the averaging factor (number of times). Then press the $\lfloor n \rfloor$ Default averaging factor is 16.
- $4.$ Toggle AVERAGING on OFF to ON off .

The averaging notation (Avg) appears on left side of the grid when averaging is turned on. The averaging notation indicates the number of times averaging has been performed. When averaging is completed, the counter stops incrementing. However, the trace continues updating with each sweep.

Averaging requires a sweep with a specied number of times that is enough for an averaging factor to complete the averaging. You can set the number of sweeps by using the number of groups function.

If you want to change the setting of any parameter when averaging, you can restart averaging from the ⁰ count.

To restart the averaging the averaging Bw/Avg to the averaging the set of the set of the averaging the set of th $\mathcal{L} = \mathcal{L} = \mathcal$ Ω .

To Use Maximum or Minimum Hold Function

- 1. Press (Display).
- $2\cdot$ Press DATA HOLD <code>[OFF]</code> .

Stabilizing the Trace

"Max" (or "Min") appears on the right of the grid when the maximum (minimum) hold function is activated.

To the maximum of the minimum of minimum hold, press Display to the maximum hold. Data hold is a second control of the contr

Figure 9-11. Maximum Holding the Drifting Signal

To Capture an Unstable Signal Using Signal Track

- \sim 1. I ESS DISPLAY | μ DUAL CHAN on OFF to ON off .
- 2. Press (Chan 1)
- 3. Press (Search)
- ^{4.} Press SEARCH: PEAK to move the marker to the peak of the drifting test signal.
- $^{\rm D.}$ Toggle SIGNAL TRK on OFF to ON off .

The signal track function captures the peak that is indicated by the marker and places it in the center of the grid for each sweep. If the peak is unstable horizontally, use this function. The analyzer automatically changes the center frequency to keep the peak in the center of the grid.

Figure 9-12 shows ^a display when signal track is ON at channel 1. Figure 9-13 shows a display after the analyzer sweeps ^a few times. At channel 1, the center frequency has been changed to maintain the drifting signal at the center of the display. Channel 2 shows that signal frequency has drifted to a higher frequency.

Figure 9-13. Display After Signal Has Drifted

Examples of Applications

This chapter contains example applications of the 4395A for each of network, spectrum, and impedance analyzer modes.

Note In this manual, the following abbreviations are used:

-
- NA mode: Network analyzer mode
- SA mode: Spectrum analyzer mode
- **ZA mode:** Impedance analyzer mode

Network Measurement (NA Mode)

- Filter transmission measurement
	- \Box 6 dB bandwidth
	- \Box Ripple
	- \Box Magnitude and phase characteristics
	- \Box Expanded phase characteristics
-
- \Box Return loss and reflection coefficient
- \Box Standing wave ratio (SWR)
- S-parameters measurement
- \Box Impedance measurement
- Admittance measurement
- Gain compression measurement Absolute output level measurement

Spectrum Measurement (SA Mode)

- **AM** signal measurement \Box Carrier amplitude and frequency measurement using the marker \Box Modulating frequency and modulation index measurement using Δ Marker
- **FM Signal Measurement** \Box Frequency deviation of wide band FM signal

Impedance Measurement (ZA Mode)

- Evaluation of a chip capacitor
	- \Box Capacitance (C) and dissipation factor (D) under swept frequency
	- \Box Z and θ (Phase) under swept frequency
	- \Box Equivalent circuit analysis
- Evaluation of a crystal resonator
	- \Box Readout of resonance frequency (F_r) and crystal impedance (CI)
	- \Box Equivalent circuit analysis
	- \Box Admittance chart
	- \Box Using the marker
- Evaluation of a varactor diode DC bias sweep using list sweep function \Box Measuring capacitance under DC bias conditions

Measuring Transmission Characteristics of ^a Filter (NA Mode)

Insertion loss and gain are ratios of the output to input signals. The following procedure measures the insertion loss and gain of a 83.16 MHz SAW bandpass filter. This measurement can be used to obtain the key filter parameters.

Measurement Setup

Connection

Set up the 4395A as shown in Figure 10-1.

Figure 10-1. Transmission Measurement Setup

Analyzer Settings

Press (Preset). Then set the analyzer's controls as follows:

Performing Calibration

Perform a frequency response calibration for this measurement as follows:

- -1.1 COO FOR POST CALIBRATE MENU RESPONSE.
- 2. Connect ^a THRU calibration standard between the measurement cables in place of the DUT.
- $3.$ Press THRU to perform a frequency response calibration data measurement.
- ⁴ Press DONE: RESPONSE . (CORRECTION on OFF is automatically set to ON off .)

Measurement

Replace the THRU standard with the DUT. Press Scale Ref rescaled. Note that the display shows the complete response of the bandpass filter under test.

Read Out Insertion Loss Using the Marker

- Γ . Less Γ bearch Γ . Prime Γ the insertion loss and displays it at the upper right of the display.
- $-$. Tr \cap \cap Imarker Press $\triangle MODE$ MENU $\triangle MKR$ to turn on the $\triangle Marker$ (at the position of the marker).
- 3. Enter $[1]$ $[5]$ $[0]$ $\overline{k/m}$ to move the marker to the point offset from the Δ marker. The Δ marker value shows the relative attenuation at the offset position (see Figure 10-2).

Figure 10-2. Response of a SAW Filter

6 dB Bandwidth

The analyzer calculates the bandwidth of the DUT between two equal power levels. In this example, it calculates the -6 dB bandwidth relative to the filter center frequency.

- \sim 1.1000 | Ocal CII | 111 MAX to move the marker to the maximum value of the trace.
- 2 . Press WIDTHS [OFF] \Box 6 \times 1.
- 3. PressWIDTHS on OFF to ON off. The analyzer calculates the -6 dB bandwidth, center frequency, Q (Quality Factor), insertion loss, and differences between the center frequency and the cutoff frequencies of the DUT. It then lists the results at the upper right hand of the

Measuring Transmission Characteristics of a Filter (NA Mode)

display. Sub-marker 1 on the trace shows the passband center frequency while sub-markers 2 and 3 show the location of the -6 dB cutoff points.

Figure 10-3. Using the Marker to Determine ⁶ dB Bandwidth

To have the 4395A calculate the bandwidth between other power levels, select WIDTH VALUE and enter the number (for example, enter 3 - 11 - 3 - 3 - 11 - 11 - 11 - 12 - 13 - 14 - 15 - 15 - 15 - 15 - 15

Press Marker PRESET MKRS when you are nished with this measurement.

Ripple

Passband ripple is the variation in insertion loss over a specified portion of the passband.

- \sim 1.1 COO TD ISDICTY TO \sim DUAL CHAN on OFF to ON off to display channel 2 below channel 1.
- $-$ Press Sweep Press I COUPLED CH ON off to on OFF.
- 3. Press $(Marker)$ (8) (3) (1) (6) (M/μ) .
- \sim 1.1 C 22. PM 31 Ket \rightarrow 1.1 M $MKR \rightarrow XCH$ MENU ZOOMING APERTURE 1 0 \overline{X} 1.
- ^{5.} Press MKR XCH ZOOM.
- er Tress Funantz Filsearch Pru MAX . Then press Marker! MKR!REFERENCE Scale Ref SCALE/DEVICE IN 1979 CONTRACTOR COMMUNICATION CONTRACTOR CONTRACTOR CONTRACTOR CONTRACTOR -1 to magnify the trace and resolve the ripple.
- 7.1 Press Toesicul M SEARCH: PEAK . The peak is the press Market of the press Market . The peak is the peak of the peak of the peak $\triangle MODE$ MENU $\triangle MKR$.
- 8. Press Search Poi SEARCH: PEAK PEAK DEF MENU PEAK PLRTY POS neg to pos NEG. Then press RETURN RETURN SEARCH: PEAK. The passband ripple is automatically given as the peak-to-peak variation between the markers. The ripple value is displayed at the upper right of the display. Depending on the peak size, you may need to define the peak size using the peak definition feature of the 4395A.

Figure 10-4. Using Peak Search to Determine Ripple

Press Chan 1 Marker PRESET MKRS , and Chan 2 Marker PRESET MKRS when you are nished with this measurement.

Measuring Phase Response

^A two input ratio measurement can also provide information about the phase shift of ^a network. The analyzer can translate this information into ^a related parameter, group delay.

With the same connection, instrument settings, and calibration used in the previous example (see "Measurement Setup" in "Measuring Transmission Characteristics of a Filter (NA Mode)"), make the following changes:

- \sim 1. Press Formal 1 Fig. (A) see Press Press $C\text{OUPLED}$ CH on OFF to ON off to couple sweep parameters of channel ² to channel 1.
- 2. Press Chan 2 Format PHASE to display the phase response on channel 2.

If the trace needs to be rescaled, press (Scale Ref) and AUTO SCALE.

Figure 10-5 shows the phase response of the bandpass filter. Notice the linear phase shift through the passband and the rapid uctuations that occur outside this region. The random phase of the broadband noise floor causes the spurious out-of-band response.

This format displays phase over the range of -180 to $+180$ degrees. As phase increases beyond these values, a sharp 360 degree transition occurs in the display as the trace \wraps" between $+180$ and -180 degrees. This wrap causes the characteristic "sawtooth" display usually seen on devices with linearly increasing (or decreasing) phase responses.

Measuring Transmission Characteristics of a Filter (NA Mode)

Figure 10-5. Amplitude and Phase Response of ^a SAW Filter

Using the Expanded Phase Mode

The 435-A can display phase beyond 280 degrees. Press Format Press Format 180 degrees. ON off . Then press Scale Ref AUTO SCALE . The phase is displayed with \no wrap" (see Figure 10-6).

Press Format EXP PHASE ON σ is to σ on σ is the turn of the expanded phase mode.

Reflection Measurement (NA)

When making a reflection measurement, the 4395A monitors the signal going to the DUT and uses it as the reference. It compares the reflected signal from the DUT to the reference signal. The ratio of the incident and reflected signals is the reflection coefficient of the DUT or, when expressed in decibels, the return loss.

Reflection measurements require the connection of a directional device, such as a directional coupler, to separate the power reflected from the DUT. This separation is necessary so that it can be measured independently of the incident power (see Figure 10-7).

Figure 10-7. Reflection Measurement

Multi-Port Test Devices

When the device has more than one port, connect high-quality terminations (loads) to all unused DUT ports to terminate them into their characteristic impedance (usually 50 or 75 m). If this is not done, renewiths on the unused (ports will cause measurement errors.

The S-parameter test set automatically switches the termination at the unused port for each S-parameter measurement. When using a transmission/reflection test set, terminate the unused input port of the analyzer with a high quality load.

The signal reflected from the DUT is measured as a ratio with the incident signal. It can be expressed as a reflection coefficient, a return loss, or as SWR. These measurements are mathematically defined as:

return loss(dB) = -20 log(
$$
\rho
$$
)
\nreflection coefficient = $\frac{\text{reflected power}}{\text{incident power}}$
\n= ρ (magnitude only)
\n= Γ (magnitude and phase)
\n= S_{11} or S_{22} (magnitude and phase)
\nSWR = $\frac{1 + \rho}{1 - \rho}$

Measurement Setup

Connection

Set up the 4395A as shown in Figure 10-8.

Figure 10-8. Reflection Measurement Setup

Analyzer Settings

Press (Preset). Then set the 4395A's controls as follows:

Performing Calibration

Perform an S_{11} , 1-port calibration for this measurement. The following procedure is for using 7 mm standards.

- 1. Press Cal CALIBRATE MENU S11 1-PORT .
- ². Connect the OPEN standard to port 1. Then press [S11]: 0PEN . (The softkey label 0PEN . \overline{a} is underlined when the measurement is complete.)
- ^{3.} Connect the SHORT standard to port 1. Then press SH0RT, (The softkey label SH0RT is underlined when the measurement is complete.)
- 4. Connect the LOAD standard to port 1. Then press LOAD, (The softkey label LOAD is underlined when the measurement is complete.)
- $5.$ Press DONE: 1-PORT CAL . (CORRECTION on OFF is automatically set to DN off .)

Note The next example "S-Parameters Measurement" uses the calibration corrections you just completed. Do not change the calibration settings before doing the example.

Measurement

Connect the DUT to the test set. Press Scale Ref AUTO SCALE if the trace needs to be rescaled.

Return Loss and Reflection Coefficient

The return loss characteristics are displayed in the Log Mag format in Figure 10-9. The value inside the passband is greater than outside the passband. ^A large value for return loss corresponds to a small reflected signal just as a large value for insertion loss corresponds to a small transmitted signal.

To display the same data in terms of re
ection coecient, press Format MORE AND CONTRACT AND ACCOUNTS OF THE CONTRACT Formation and this redisplay and the existing and the existing measurement in a linear measurement in a linear magnitude formation of the second that varies from Γ =1.00 at the top of the display (100% reflection) to 0.00 at the bottom of the display (perfect match).

Standing Wave Ratio (SWR)

To display the resultance in the wave reported wave and characterized the result of the result was founded was S . The analyzer reformation the display in the displacement measurement of S (with S) in S \rightarrow 1, N perfect match, at the bottom of the display).

S-Parameters Measurement S-Parameters Measurement

S-parameters S_{11} and S_{22} are no different from the measurements made in the previous section. S_{11} is the complex reflection coefficient of the DUT's input. S_{22} is the complex reflection coefficient of the DUT's output. In both cases, all unused ports must be properly terminated. To display the trace on the polar chart, press Format T . Polar Chart . I the results of a typical . The results of a typical contract of a typica S_{11} measurement is shown in Figure 10-11. Each point on the polar trace corresponds to a particular value of both magnitude and phase.

Figure 10-11. S_{11} on Polar Chart

Data Readout Using the Marker

Press (Marker) and use the knob to position the marker at any desired point on the trace. Then read the frequency, magnitude, and phase in the upper right hand corner of the display. Or, enter the frequency of interest from the data entry key pad to read the magnitude and phase at that point.

To read the marker data in logarithmic, linear, real/imaginary, impedance $(R+iX)$, admittance $\mathcal{G}(\mathcal{G})$, and $\mathcal{G}(\mathcal{G})$, and $\mathcal{G}(\mathcal{G})$ is the swarf of $\mathcal{G}(\mathcal{G})$ in $\mathcal{G}(\mathcal{G})$ is the swarf of $\mathcal{G}(\$ SMTH/POLAR MENU and select the desired format.

Reflection Measurement (NA)

Impedance Measurement

The amount of power reflection from a device is directly related to the impedance values of both the device and the measuring system. In fact, each value of the reflection coefficient (Γ) uniquely defines a device impedance. For example:

- \blacksquare Γ = 0 occurs when the device and test set impedance are the same.
- A short circuit has a reflection coefficient of $1 = 1$ ± 180 $^{\circ}$ (= -1).
- An open circuit has a reflection coefficient of $1 = 1$ \angle 0 \pm $=$ 1).

Every other value for Γ also corresponds uniquely to a complex device impedance, according to the equation:

$$
Zn = \frac{1 + \Gamma}{1 - \Gamma}
$$

Where Zn is the DUT impedance normalized to (that is, divided by) the measuring system's characteristic impedance (women) or 70 ii). The next is a default impedance of the network analyzer has a σ . To set the impedance to 10 **m**, press [call in MORE SET ZO. The network analyzer uses the formula above to convert the re
ection coecient measurement data to impedance data.

- \sim 1.000 Format Press STATISTIC . THE CHART . THE COMPLETE CHART SHOWS THE CONTRIGUES IMPORTANCE OF THE DUTY OF THE DUTY OF THE DUTY frequency range selected.
- 2. Press M _{arker}) to turn on the marker. Then use the knob to read the resistive and reactive components of the complex impedance at any point along the trace. The marker displays ^a complex impedance readout.

Figure 10-12. Impedance Measurement

Admittance Measurement

- \sim 1.1 ess Format Print MORE ADMITTANCE CHART. The display shows the complex impedance of the DUT over the frequency range selected.
- 2. Use the knob to read the resistive and reactive components of the complex impedance at any point along the trace. The marker displays complex impedance readout.

Figure 10-13. Admittance Measurement

Gain Compression Measurement (NA)

An important measure of active circuits is how well they handle a signal frequency with a varying input amplitude. By using the power sweep function in the network analyzer mode, measurements such as gain compression or automatic gain control slope can be made.

Measurement Setup

Connection

Set up the 4395A as shown in Figure 10-14.

Figure 10-14. Gain Compression Measurement Setup
Analyzer Settings

Press (Preset). Then set the 4395A's controls as follows:

Performing Calibration

Perform ^a power response calibration for this measurement as follows:

- -1.1 COO FOR POST CALIBRATION MENU RESPONSE.
- 2. Connect ^a THRU calibration standard between the measurement cables in place of the DUT (see Figure 10-14).
- $^3\cdot$ Press THRU to perform a power response calibration data measurement.
- ⁴ Press DONE: RESPONSE . (CORRECTION on OFF is automatically set to ON off .)

Measurement

- 5. Replace the THRU standard with the DUT.
- \sim Press Scale Ref. Pa AUTO SCALE if the trace needs rescaling.
- 7. Press Search Priz MAXAMA, too ally the males allegated to males allegated wall boy atly only males. Haven't to
- ິ I LESS | Marker | *L*ui ΔM ODE MENU ΔM KR to set the Δm arker to the maximum point.
- 9. Press Search Pri TARGET I - 1 TO STATE OF THE GAING CALLERY CONTACT COMPRESSION OF THE GAINST CONTACT CONTACT ANOTHER AND A STR Figure $10-15.$)

Absolute Output Level Measurement

The analyzer can show the characteristics input level versus output level by using the absolute measurement capability in the network analyzer mode.

- NKR [UNCOUPLE] to NKR [COUPLE] to couple the marker between both 1. Press Marker $channels$
- 2. Press Chan 2 Meas MORE \overline{B} to select the absolute measurement at the B input.
- 3. LIESS DISPLAY | DI DATA MATH [DATA] OFFSET. Then input the value of the attenuator that is connected between the DUT and the ^B input. In this example measurement, ^a ³⁰ dB attenuator is used. Therefore, enter 30 - AT P
- 4. The 4395A displays the input versus output power levels. The marker shows the input and output power levels at the -1 dB gain compression point.
- \sim TIC 00. FLG Display FLG \sim DUAL CHAN on OFF to ON off to display both channel (see Figure 10-16). Note that you must subtract ⁶ dB from the input value readout. This is necessary because the input signal is attenuated by the power splitter that is between the RF OUT and the DUT.

Input vs. Output Power Level at the -1 dB Gain Compression Point

AM Signal Measurement (SA)

In this example, the following parameters for AM signal measurement are derived:

- **Carrier amplitude** (E_c) and frequency (f_c)
- \blacksquare Modulating frequency (f_m) and modulation index (m)

Test Signal

The following test signal is used in this example:

■ AM Signal \Box Frequency (f_c) : 100 MHz \Box Modulating signal frequency (f_m) : 10 kHz

Measurement Setup

Connect the test signal source to the ^R input port.

Analyzer Settings

Press (Preset). Then set the 4395A's controls as follows:

Carrier Amplitude and Frequency Measurement Using the Marker

Press (Scale Ref) and enter the reference value if the trace needs rescaling.

- 1. Press (Search) to turn the marker on.
- 2 Press MAX to search for the carrier signal. The carrier amplitude and frequency are displayed in the upper right corner as shown in Figure 10-17.

Figure 10-17. Carrier Amplitude and Frequency of AM Signal

The marker shows that the carrier amplitude (E_c) is -20.305 dBm and frequency (f_c) is 100

Modulating Frequency and Modulation Index Measurement Using Marker

- ് II ലോട് Marker | ച ΔM ODE MENU ΔM KR.
- لاحب Search I التصوية التصوية Search SEARCH: PEAK NEXT PEAK to search for a sideband. The offset value from the carrier is displayed as the marker sweep parameter value shown in Figure 10-18. This value is the modulation frequency.

Figure 10-18. Modulating Frequency of AM Signal

The Δ marker shows that the sideband amplitude value relative to the carrier is -19.708 dB (see Figure 10-18). The modulation index (m) can be derived from the following equation:

$$
m = 2 \times 10^{\frac{\Delta Mkr}{20}}
$$

$$
= 20.68\%
$$

AM Signal Measurement (SA)

where ΔMkr is the Δ marker value shown in Figure 10-18.

FM Signal Measurement (SA)

This example describes how to derive the frequency deviation (Δf_{peak}) value.

Test Signal

The following test signal is used in this example:

Wide band FM Signal

- \Box Carrier frequency: 100 MHz.
- \Box Modulating frequency: 1 kHz.
- \Box Frequency deviation: 1 MHz.

Measurement Setup

Connection

Connect the test signal to the R input port.

Analyzer Settings

Press (Preset). Then set the 4395A's controls as follows:

Frequency Deviation of Wide Band FM Signal

Press (Scale Ref) and enter reference value if the trace needs rescaling.

Frequency Deviation

- -1.1 \sim \sim 1 \sim \sim 1 \sim \sim 1 SEARCH: PEAK AND RESIDENCE TO A REPORT OF THE ANNUAL CONTINUES OF THE ANNUAL CONTINUES.
- 2. Press Marker Post ΔM ODE MENU ΔM KR.
- اص S. Tie*o* Search ا SEARCH: PEAK NEXT PEAK .

Figure 10-19. Wide Band FM Signal Measurement

The frequency deviation (Δf_{peak}) can be derived roughly from the following equation:

$$
\Delta f_{peak} = \frac{|\Delta Mkr|}{2}
$$

where ΔMkr is the marker sweep parameter value shown in Figure 10-19. In this example, the frequency deviation is about 987.5 kHz.

Press Marker PRESET MKRS when you are nished with this measurement.

Carrier Level and Modulating Frequency

The carrier level and modulating frequency can be derived using ^a method similar to the AM signal measurement. In this example, the zooming function is used to measure the carrier and the adjacent signal.

- 1. Press $(Marker)$ (1) (0) $\overline{(\mathsf{M}/\mu)}$ to put the maker on the carrier frequency.
- $-$ I LESS IN LARGE \rightarrow I LAR ZOOMING APERTURE 0 . 2 -1.
- 3 Press MKR ZOOM to zoom up to the carrier signal.
- 4. Press Bw/Avg 1 0 -1.
- 5. Press (Scale Ref) and enter reference vale if the trace needs rescaling.
- 6. Press $(Marker)$ 1 \odot \odot (M/μ) to move the marker to the career frequency. The carrier amplitude can be read as the marker value.
- 7.11×100 [Marker | 24 $\triangle MODE$ MENU $\triangle MKR$ to put the \triangle maker on the carrier.
- \sim 1 Less Search Poi SEARCH: PEAK NEXT PEAK LEFT (or NEXT PEAK RIGHT) to move the marker to the sideband.

Figure 10-20. Zooming Carrier Signal of FM Signal

Evaluation of a Chip Capacitor (ZA Mode)

As ^a typical application of impedance analyzer mode, this example shows how to evaluate the impedance characteristics of ^a chip under swept frequency. Also, it shows how to determine the equivalent circuit parameters of a chip capacitor using the equivalent circuit analysis function of the 4395A. Note that using the 4395A as an impedance analyzer requires the 43961A Impedance Test Kit as well as Option 010.

Measurement Setup

Connection

Set up the 4395A as shown in Figure 10-21.

Figure 10-21. Connecting the Impedance Test Kit

Analyzer Settings

Press (Preset). Then set the 4395A's controls as follows:

Calibration

ue

^A proper calibration is requisite for the 4395A to perform measurements within the guaranteed accuracy range. Calibrating the 4395A for impedance analyzer mode requires three different α is a set of α or β or α is β of α is β and α or α is β

Note Be sure to use the calibration kit included in the 43961A package.

- 1. Press \overline{Cal} and choose CALIBRATE MENU.
- ². Connect the 0S termination to the OUTPUT port, and choose QPEN . Wait until the QPEN softkey's label is underlined to indicate that the OPEN calibration is complete.
- 3. Remove the 0S termination.
- 4. Connect the 0 Ω termination to the OUTPUT port, and choose SHORT. Wait until the SHORT softkey's label is underlined to indicate that the SHORT calibration is complete.
-
- 6. Connect the 50 Ω termination to the OUTPUT port, and choose L0AD. Wait until the L0AD softkey's label is underlined to indicate that the LOAD calibration is complete.
- $7.$ Choose DONE: CORRECTION.
- 8. Make sure that a "Cor" marker is displayed at the left-hand edge of the screen.

Connecting the Test Fixture

The test fixture used in this example is the $16192A$ Parallel Electrode SMD Test Fixture. Connect the test fixture to the test kit referring to the documentation for the 16192A Parallel Electrode SMD Test Fixture.

Figure 10-22. Connecting the Test Fixture

Setting the Electrical Length of the Test Fixture

Connecting a test fixture adds an extra electrical length to the test circuit. This electrical length, which is specific to the test fixture you use, must be known to the 4395A so that it can compensate for the extra electrical length and eliminate errors due to phase shifts.

The 4395A incorporates a database of Agilent test fixtures with their own electrical lengths. This database contains the electrical length of the 16192A test fixture.

To set the electrical length of the test fixture, follow these steps:

- 1. Press (Meas)
- $^{\rm 2.}$ Choose FIXTURE [NONE] SELECT FIXTURE .
- 3 As the model number for the test fixture you are going to use, select 16192 . $\,$
- $^{\rm 4.~Choose~RETURN}$.
- 5. A "Del" marker appears at the left edge of the screen.

Fixture Compensation

Fixture compensation is a process that calibrates the 4395A with a test fixture installed, thereby eliminating errors produced between the test fixture electrode and the impedance test kit's OUTPUT port.

Normally, the 4395A must be fixture-compensated for the OPEN and SHORT circuit states. It can optionally be fixture-compensated for the LOAD state.

To carry out fixture compensation, follow these steps:

- 1. Press (Cal) and choose FIXTURE COMPEN COMPEN MENU .
- 2. Make sure that the test circuit is in the open state.
- 3. Choose OPEN, Wait until the OPEN softkey's label is underlined to indicate that the OPEN compensation is complete.
- 4. Connect the appropriate short device to the test fixture.
- $^{\rm 5.~Choose}$ SH0RT . Wait until the SH0RT softkey's label is underlined to indicate that the SHORT compensation is complete.
- $6.$ Choose DONE: COMPEN . $\,$
- 7. Check that a "Cmp" marker is displayed in place of the "Cor" marker.

Capacitance and Dissipation Factor under Swept Frequency

Setting Measurement Parameters

To begin impedance measurement, the 4395A must know which characteristics it should measure and how it should report the measured values.

- 1. Press (Chan 1) to activate Channel 1.
- ². Press (Meas) and choose MORE 1/5 MORE 2/5 MORE 3/5 SER(C_s) to instruct the 4395A to measure $\overline{C_s}$ (serial capacitance) for Channel 1.
- 3. Press $\sqrt{Chan 2}$ to activate Channel 2.
- ^{4.} Press (Meas) and choose MORE 4/5 D FACTOR(D) to instruct the 4395A to measure D (dissipation factor) for Channel 2.
- \sim Press BM/Avg \sim AVERAGING FACTOR 8 -1.
- $^6\cdot$ Toggle AVERAGING on OFF to ON off .
- ⁷. Press $\overline{Display}$ and toggle DUAL CHAN on OFF to ON off to turn ON the dual channel function.

Measurement

Connect the DUT to the test fixture referring to the documentation that comes with the 16192A test fixture.

Press Chan 1 Scale Ref AUTO SCALE , Chan 2 Scale Ref AUTO SCALE if the trace needs rescaling.

Evaluation of ^a Chip Capacitor (ZA Mode)

Figure 10-23. Cs and ^D Characteristics of ^a Chip Capacitor under Swept Frequency

$|Z|$ and θ (Phase) under Swept Frequency

Follow these steps:

- 1. Press (Chan 1) to activate Channel 1.
- ^{2.} Press (Meas) and choose MORE 5/5 IMPEDANCE: $|Z|$ to instruct the 4395A to measure |Z| for Channel 1.
- 3. Press (Format) and choose FORMAT: LOG Y-AXIS.
- $4.$ Press (Scale Ref) and choose $\overline{\mathtt{AUTO}}$ SCALE . $\overline{\mathtt{AUCN}}$
- 5. Press Chan 2) to activate Channel 2.
- $6.$ Press (Meas) and choose $\theta_{\mathbf{z}}$.
- $7.$ Press $\sqrt{3}$ Scale Ref) and choose AUTO SCALE .

The 4395A displays the $|Z|$ and θ characteristics under swept frequency, as shown in Figure 10-24.

Figure 10-24. $|Z|$ and θ Characteristics of a Chip Capacitor under Swept Frequency

Equivalent Circuit Analysis

The 4395A provides a function that automatically calculates approximate values of specific parameters of an equivalent circuit that corresponds to a DUT. This function supports five circuit models. In addition, the resulting parameter values can be used to simulate the frequency-based characteristics of the equivalent circuit; this allows you to compare the simulated characteristics with the actually measured characteristics.

To analyze equivalent circuit parameters, follow these steps:

- 1. Press \widehat{D} isplay) and choose MORE EQUIV CKT MENU to access the equivalent circuit menu.
- ². Choose SELECT EQV CKT [A] and select D as the equivalent circuit model to use.
- ^{3.} Choose CALCULATE EQV PARAMS to calculate the parameters of the equivalent circuit.

Preceded by a beep, the values of the equivalent circuit parameters appear at the bottom of the screen.

Figure 10-25. Equivalent Circuit Parameters

Evaluation of ^a Chip Capacitor (ZA Mode)

To hide the equivalent circuit parameters from the screen, press $(Display)$, choose MORE EQUIV CKT MENU. Then choose DISP EQV PARM [ON] so that the softkey label changes to \Box . The contract of the co

You may wish to use the resulting parameter values to simulate the frequency-based characteristics of the equivalent circuit and compare them with the actually measured characteristics. To do so, follow these steps:

- 4. Press $(Display)$
- $^{\rm 5.}$ Choose MORE EQUIV CKT MENU SIMULATE F-CHRST .

Preceded by ^a beep, the simulation results appear on the screen. They are also stored in the trace memory.

Figure 10-26. Simulation of Frequency-based Characteristics Using Resulting Equivalent Circuit Parameters

You can simulate the frequency-based characteristics with desired parameter values you de de este de la pression de la pre MORE EQUIV CKT MENU DEFINE EQV PARAMS, enter each parameter values using R1 C1. \sim , \sim L1 ,and C0 ,and then press SIMULATE F-CHRST .

To hide the simulation results from the screen, press $(Display)$ and choose DISPLAY [DATA&MEM] DISPLAY: DATA for both Chan 1 and Chan 2.

Evaluation of a Crystal Resonator (ZA Mode)

Measurement Setup

Connection

Connect the 4395A with the 43961A Impedance Test Kit in the same procedure as described in \Evaluation of ^a Chip Capacitor (ZA Mode)".

Analyzer Settings

Press (Preset). Then set the 4395A's controls as follows:

Calibration

Calibrate the 4395A as described in \Evaluation of ^a Chip Capacitor (ZA Mode)".

Connecting the Test Fixture

The test fixture used in this example is the 16092A Spring Clip Test Fixture. Connect the test xture to the test kit referring to the documentation for the 16092A Spring Clip Test Fixture.

Setting the Electrical Length of the Test Fixture

Connecting a test fixture adds an extra electrical length to the test circuit. This electrical length, which is specific to the test fixture you use, must be known to the 4395A so that it can compensate for the extra electrical length and eliminate errors due to phase shifts.

Although the 4395A incorporates a database of Agilent test fixtures with their own electrical lengths, the 16092A test fixture is not contained in this database. Therefore, you need to manually set its electrical length.

Follow these steps:

- 1. Press (Meas).
- $\rm ^2$ Choose FIXTURE [NONE] NODIFY [NONE] DEFINE EXTENSION .
- 3. The $16092A$ test fixture has an electrical length of 0.0034 m. To enter this electrical length, $p + 0.00$. 1.0 1.0 1.0 1.0 1.0 1.0 1.0

Evaluation of ^a Crystal Resonator (ZA Mode)

- 4. Choose LABEL FIXTURE ERASE TITLE . Press $\cap \cap \cap \cap \cap \cap$ and then choose DONE .
- ^{5.} Choose KIT DONE (MODIFIED) .
- 6. A "Del" marker appears at the left edge of the screen.

Fixture Compensation

Carry out fixture compensation as described in "Evaluation of a Chip Capacitor (ZA Mode)".

Setting Measurement Parameters

- 1. Press (Chan 1) to activate Channel 1.
- ^{2.} Press $\overline{\mathsf{Meas}}$ and check that IMPEDANCE: MAG([Z]) is currently selected.
- 3. Press (Format) and choose LOG Y-AXIS .
- 4. Press (Chan 2) to activate Channel 2.
- 5 Press (Meas) and check that $\theta_\mathbf{z}$ is currently selected.
- ^{6.} Press Format) and check that FORMAT: LIN Y-AXIS is currently selected.
- T I I LESS $|BW/AVg|$ H AVERAGING FACTOR 8 -1.
- 8 . Toggle AVERAGING on OFF to ON off .
- ^{9.} Press \overline{D} _{isplay} and toggle DUAL CHAN on OFF to ON off to turn OFF the dual channel display.

Measurement

Connect the DUT to the test fixture referring to the documentation that comes with the 16092A Spring Clip Test Fixture.

If the trace needs rescaling, press $\sqrt{\text{Scale Ref}}$ and choose enter AUTO SCALE after activating Channel 1 with $(\overline{Chan 1}]$ key.

Figure 10-27. Frequency-based Characteristics of a Crystal Resonator

Readout of Resonance Frequency (F_r) and Crystal Impedance (CI)

- 1. Press $(\overline{Chan 2})$ to activate Channel 2.
- 2 Press (Search) and toggle SEARCH TRK on OFF to ON off to turn ON the search track function.
- 3. Choose TARGET.
- ^{4.} Press $\Omega(\overline{X_1})$ and choose SEARCH LEFT. The marker moves to the zero phase (0) point on the lower-frequency side. This is the point at which the resonance frequency (F_r) and crystal impedance (CI) occur.

Figure 10-28. Readout of the F_r and CI Values of a Crystal Resonator

Equivalent Circuit Analysis

The 4395A supports the 4-element equivalent circuit model, which is suitable for evaluating crystal resonator.

- 1. Press $\overline{Display}$ and choose MORE EQUIV CKT MENU to access the equivalent circuit menu.
- ². Choose SELECT EQV CKT [A] and select E as the equivalent circuit model to use.
- ^{3.} Choose CALCULATE EQV PARAMS to calculate the parameters of the equivalent circuit.

Preceded by a beep, the values of the equivalent circuit parameters appear at the bottom of the screen.

Figure 10-29. Equivalent Circuit Parameters

To hide the equivalent circuit parameters from the screen, press Display MORE EQV CKT MENU and toggle DISP EQV PARM [ON] to [OFF].

You may wish to use the resulting parameter values to simulate the frequency-based characteristics of the equivalent circuit and compare them with the actually measured characteristics. To do so, follow these steps:

4. Press Display and choose MORE EQUIV CKT MENU SIMULATE F-CHRST .

To hide the simulation results from the screen, press $(Displ)$ and choose DISPLAY [DATA&MEM]

Figure 10-30. Simulation of Frequency-based Characteristics Using Resulting Equivalent Circuit Parameters

Admittance Chart Admittance Chart

- 1. If the results of equivalent circuit simulation are currently displayed for Channel 1, hide the results by pressing (Chan 1) Display) and choosing DISPLAY [DATA&MEM] DISPLAY: DATA RETURN MORE EQUIV CKT MENU DISP EQV PARM [ON] .
- 2. With the marker located at the resonance frequency (F_r) point, press $\overline{\text{Market}}$ and choose MKR!CENTER to set the sweep center frequency to the resonance frequency.
- 3 · Press (Chan 1) Meas) and choose MORE [1/5] ADMITTNCE: MAG(|Y|).
- ^{4.} Press $\sqrt{1-\frac{1}{n}}$ and choose COMPLEX PLANE to select the complex plane format.
- ^{5.} Press $\overline{Display}$ and choose DUAL CHAN ON off to on OFF to turn OFF the dual channel display.
- $6.$ Press (scale Ref) and choose $\overline{\mathtt{AUT0}}\,$ SCALE to rescale the trace.
- 7. Adjust the span by pressing $\overline{\text{Span}}$ and then $\overline{\text{Im}}$ or $\overline{\text{Im}}$. If the number of sweep points is so small that the admittance chart does not form a circular shape, increase the number of sweep points by pressing $\overline{S\text{weep}}$ and choosing NUMBER OF POINTS then pressing \overline{f} . (Press Scale Ref AUTO SCALE III REQUIRED IN THE REQUIRED OF A RELEASE OF A

On ^a complex plane, the measurement parameters are always expressed as complex numbers even if you have selected a scalar parameter such as |Y|.

Figure 10-31. Admittance Chart for a Crystal Resonator

Using the Marker

1. To move the marker, press (Marker) and turn the rotary knob.

The real and imaginary parts of the complex number that corresponds to the marker position are shown at the upper left corner of the grid area (see Figure 10-31).

If necessary, press (Scale Ref) and rescale the trace.

Evaluation of a Varactor Diode - DC Bias Sweep Using List Sweep Function (ZA Mode)

This section provides an example application of impedance analyzer mode in which the 4395A's internal DC source (Option 001) is controlled through the list sweep function to evaluate the characteristics of a varactor diode under DC bias conditions.

Measurement Setup

Connection

Connect the 4395A with the 43961A Impedance Test Kit in the same procedure as described in "Evaluation of a Chip Capacitor (ZA Mode)". Connect the $BNC(m)$ -BNC(m) cable included in the 43961A package between the 4395A's DC SOURCE connector and the 43961A's DC SOURCE Input connector.

Analyzer Settings

Press (Preset). Then set the 4395A's controls as follows:

Defining the Sweep List

The list sweep function controls the sweep process in accordance with a user-defined sweep list. To define the sweep list, follow these steps:

- 1. Press (Source) and check that DC source output is turned off. (Softkey label must be DOUGLASS IN THE STATE OF TH
- ². Check that DC SRC [VOLTAGE] (voltage mode) is currently selected.
- ³. Choose DC CURRENT LIMIT and press Ω or κ to set the upper limit current to 10 mA . (Note that you may need to specify a greater or smaller value depending on the specifications of the actual DUT).
- 4. Press $\overline{\mathsf{S}_{\mathsf{WeeD}}}$ and choose $\overline{\mathsf{SWEEP}}}$ TYPE MENU EDIT LIST to begin editing the sweep list. First, you define segment 1 of the sweep list.
- 5. Choose ADD SEGMENT: START and press 3 Ω Ω Ω $\overline{M/u}$. This defines both start and stop frequency for segment 1 to be 300 MHz, and instructs the 4395A to keep the frequency for segment 1 constant at 300 MHz.
- 6. Do not change the number of points. (default value is 2)

Evaluation of ^a Varactor Diode - DC Bias Sweep Using List Sweep Function (ZA Mode)

- ⁷. Choose MORE POWER and press \Box \Box \Box \Box to set the power for segment 1 to -13 dBm.
- ^{8.} Choose DC VOLTAGE and press \Box \Box \Box \Box to set the DC bias voltage for segment 1 to -28 V.
- 9. Choose RETURN SEGMENT DONE to finish defining segment 1.
- 10. Repeat steps ⁴ through 8 above for each of segments 2 through 15, increasing the DC bias voltage in ² ^V increments from one segment to another. Note that, when you add ^a new segment by choosing ADD, the new segment inherits the definitions for the immediately preceding segment. Therefore, you can create the sweep list by just changing the DC SOURCE setting for each subsequent segment.

Segment Number Start Frequency		Stop Frequency	Measuring Point	Power		IF Bandwidth DC Bias Voltage
$\mathbf{1}$	300 MHz	300 MHz	$\overline{2}$	-13 dBm	2 Hz	$-28V$
2	300 MHz	300 MHz	2	-13 dBm	2 Hz	-26 V
3	300 MHz	300 MHz	$\overline{2}$	-13 dBm	2 Hz	$-24V$
4	300 MHz	300 MHz	2	-13 dBm	2 Hz	$-22V$
5	300 MHz	300 MHz	2	-13 dBm	2 Hz	$-20V$
6	300 MHz	300 MHz	2	-13 dBm	2 Hz	-18 V
7	300 MHz	300 MHz	2	-13 dBm	2 Hz	-16 V
8	300 MHz	300 MHz	2	-13 dBm	2 Hz	$-14V$
9	300 MHz	300 MHz	2	-13 dBm	2 Hz	$-12V$
10	300 MHz	300 MHz	2	-13 dBm	2 Hz	$-10V$
11	300 MHz	300 MHz	2	-13 dBm	2 Hz	-8 V
12	300 MHz	300 MHz	2	-13 dBm	2 Hz	$-6V$
13	300 MHz	300 MHz	2	-13 dBm	2 Hz	$-4V$
14	300 MHz	300 MHz	2	-13 dBm	2 Hz	$-2V$
15	300 MHz	300 MHz	2	-13 dBm	2 _{Hz}	-0 V

Table 10-1. Sweep List for Evaluating ^a Varactor Diode

11. When you have finished defining segment 15, choose LIST DONE to exit from edit mode.

 12 . Choose LIST FREQ to set the sweep mode to list sweep.

Calibrate the 4395A as described in \Evaluation of a Chip Capacitor (ZA Mode)".

Caution Do not attempt to perform calibration or fixture compensation while the 4395A is applying external DC bias. Doing so could damage the calibration or fixture compensation standard.

Evaluation of ^a Varactor Diode - DC Bias Sweep Using List Sweep Function (ZA Mode)

Connecting the Test Fixture

Connect the 4395A with the 16192A Test Fixture as described in \Evaluation of a Chip Capacitor (ZA Mode)".

Setting the Electrical Length of the Test Fixture

Set the electrical length of the 16192A Test Fixture as described in "Evaluation of a Chip Capacitor (ZA Mode)".

Fixture Compensation

Carry out fixture compensation as described in "Evaluation of a Chip Capacitor (ZA Mode)".

Measuring Capacitance under DC Bias Conditions

- 1. Connect the DUT.
- 2. Press (Source) and toggle DC OUT on OFF to ON off.

Figure 10-32. Characteristics of ^a Varactor Diode under DC Bias Sweep

In this example, you learned how to evaluate the capacitance characteristics of ^a varactor diode under DC voltage bias conditions using the list sweep function. Other possible applications of the list sweep function include evaluating the capacitance of a capacitor under DC voltage bias conditions and evaluating the characteristics of a coil under DC current bias conditions.

Specications and Supplemental Characteristics

These specications are the performance standards or limits against which the instrument is tested. When shipped from the factory, the 4395A meets the specications listed in this section. The performance test procedures are covered in the 4395A Service Manual.

Specifications describe the instrument's warranted performance over the temperature range of ⁰ C to 40C (except as noted). Supplemental characteristics are intended to provide information that is useful in applying the instrument by giving non-warranted performance parameters. These are denoted as SPC (supplemental performance characteristics), typical or nominal. Warm up time must be greater than or equal to 30 minutes after power on for all specifications.

Network Measurement

Source Characteristics

Frequency Characteristics

Network Measurement

Receiver Characteristics

Input Characteristics

 1 Note that it is different from the full scale input level in $\,$ spectrum measurement.

IF bandwidth (IFBW) : 2, 10, 30, 100, 300, ¹ k, ³ k, ¹⁰ k, ³⁰ kHz

Note: The IFBW should be set equal to or less than 1/5 of the lowest frequency in the sweep range.

Noise level (referenced to full scale filbut level, 25 \pm 5° C) $-$

¹ SPC

Maximum input level ::::::::::::::::::::::::+30 dBm (at input attenuator: 40 dB or 50 dB)

Network Measurement

1 A input level (B input level for B/R) = full scale input level -10 dB, R input level (B input level for A/B)= full scale input level -10 dB, IFBW = 10 Hz, ZƏ±Ə U

At the following points, measurement error may exceed the specifications: 124.0 MHz, 136.0 MHz, 415.0 MHz

Figure 11-1. Magnitude Dynamic Accuracy

Phase Characteristics

Measurements format : Standard format, Expanded phase format Frequency response (deviation from linear phase) (A/R, B/R) (SPC for A/B) at - Iv upin input, input attenuator: Tv up, if Dw S5 kHz, 25±9 U

: < 12

Dynamic accuracy (A/R, B/R) (SPC for A/B)

1 A input level (B input level for B/R) = full scale input level -10 dB, R input level (B input level for A/B) = full scale input level -10 dB, IFBW = 10 Hz, ZƏ±Ə° U

At the following points, measurement error may exceed the specifications: 124.0 MHz, 136.0 MHz, 415.0 MHz

Figure 11-2. Phase Dynamic Accuracy

Group Delay Characteristics

Sweep Characteristics

Measurement Throughput ¹

(msec, SPC, IFBW=30 kHz, after through calibration)

 $\,$ - includes system retrace time and RF switching time. Add 80 msec at start frequency \leq 5 $\,$ MHz.

Spectrum Measurement

Frequency Characteristics

(Carrier Frequency: ¹⁰ MHz, ¹⁰⁰ MHz, 500 MHz)

Figure 11-3. Noise Sidebands

Amplitude Characteristics

Amplitude fidelity 1

Log scale²

Linear scale2 : <3% $^\circ$ Amplitude nuelity shows an extent of nonlinearity referenced to the full scale input level $^\circ$ -10 dB. \sim RDW = 10 Hz, $-$ zo dDm \leq reference value \leq +30 dDm, referenced to full scale input level10 dB, input attenuator: auto, 235 C Note: Refer to *Input attenuator* part for the definition of full scale input level. Displayed average noise level at reference value ≤ -40 dBm, input attenuator: auto or 0 dB at frequency >1 kHz \ldots : \ldots : at 100 kHz : 133 dBm/Hz at 10 MHz1 : (145 ⁺ frequency/100 MHz) dBm/Hz

 -100 Average Displayed Noise [dBm/Hz] -110 -120 -130 Spec. Typical -140 -150 -160 10 100 1_k $10k$ 100k $1M$ 10M 100M $1\mathrm{G}$ Frequency [Hz]

 \sim at start frequency \geq 10 MHz $-$

Figure 11-4. Typical Displayed Average Noise Level

On-screen dynamic range

Figure 11-5. Typical On-screen Dynamic Range (Center: ⁵⁰ MHz)

Spurious responses

Typical dynamic range

Figure 11-6. Typical Dynamic Range at Inputs R, A, and ^B

Input attenuator

Setting range \ldots : \ldots \ldots

1 Note that it is different from the full scale input level in network measurement.

Spectrum Measurement

Sweep Characteristics

Sweep type : Linear frequency, List frequency Trigger type : Hold, Single, Number of groups, Continuous, Trigger source :........ Internal (free run), External, Manual, Level gate(Option 1D6), Edge gate(Option 1D6), GPIB (bus)

Sweep time (excluding each sweep setup time)

¹ See the next item for sweep time at zero span

Zero span

Number of display points

Input Characteristics

¹ (SPC)
Spectrum Measurement

Specications when Option 1D6 Time-Gated spectrum analysis is installed

All specifications are identical to the standard 4395A except the following items.

Gate length Range : ⁶ s to 3.2 ^s

Special Special Conversions of the Conversion in the Convention of the Conversion of the Conversion in the Conversion is the conversion of the Conversion of the Conversion in the Conversion of the Conversion of the Convers installed

4395A Option 010 Impedance Measurement

The following specications are applied when the 43961A Impedance Test Kit is connected to

Measurement Functions

Measurement parameters $Z, Y, L, C, Q, R, X, G, B, \theta$ Display parameters $|Z|, \theta_z, R, X, |Y|, \theta_y, G, B, |\Gamma|, \theta_\gamma, \Gamma_x, \Gamma_y, Cp, Cs, Lp, Ls, Rp, Rs, D,$ ^Q

Display Formats

- \blacksquare Vertical lin/log scale
- **Complex plane**
- Polar/Smith/admittance chart

Sweep Parameters

- **Linear frequency sweep**
- **Logarithmic frequency sweep**
- List frequency sweep
- Power sweep (in dBm unit)

IF Bandwidth

2, 10, 30, 100, 300, 1k, 3k, 10k, 30k [Hz]

Calibration

- OPEN/SHORT/LOAD 3 term calibration
- **Fixture compensation**
- Port extension correction

Measurement Port Type

 \blacksquare APC-7

Output Characteristics

when the measurement port is terminated by 50 ¹ ::::::::::::::::::::::::: 56 to +9 dBm when the measurement port is open $\dots\dots\dots\dots\dots\dots\dots\dots\dots\dots\dots\dots$ 0.71 mVrms to 1.26 Vrms $^\circ$ rote. When the measurement port is terminated with 50 $_M$, the signal level at the $^\circ$ measurement port is 6 dB lower than the signal level at the RF OUT port.

Level accuracy

Measurement Basic Accuracy (Supplemental Performance Characteristics)

Accuracy was week well into the control at the connecting surface of the Connection and the the Connection of the 43961A under the following conditions: ¹

124.0 MHz, 136.0 MHz, 415.0 MHz

Figure 11-7. Impedance Measurement Accuracy

$|Z|$ - θ Accuracy

Where, $|Z_m|$ is $|Z|$ measured. A, B, and C are obtained from Figure 11-7.

Measurement Basic Accuracy (Supplemental Performance Characteristics)

$|Y|$ - θ Accuracy

Where, $|Y_m|$ is $|Y|$ measured. A, B, and C are obtained from Figure 11-7.

R - X Accuracy (Depends on D)

Where,

D can be calculated as: R/X , or

 θ can be calculated as:

 $\alpha = \alpha$, $\alpha = \alpha$, $\beta = \alpha$ ^R - 2f - Cs $tan^{-1}(X/R)$, or tan $(\angle \pi f \times L_s / \pi)$, or $tan^{-1}(1/(K \times 2\pi) \times U_s))$

 $\mathbb{R} \times \mathbb{Q}$ - $\mathbb{R} \times \mathbb{R}$ + $\mathbb{R} \times \mathbb{R}$, $\mathbb{R} \times \mathbb$ Xa ⁼ ^A ⁺ (B=jXmj ⁺ ^C - jXmj) - ¹⁰⁰ [%]

 R_m and X_m are the measured R and X, respectively. A, B, and C are obtained from Figure 11-7.

^G - B Accuracy (Depends on D)

Where,

D can be calculated as:
$$
G/B
$$
, or
\n $G/(2\pi f \times C_p)$, or
\n $G \times 2\pi f \times L_p$
\n θ can be calculated as: $\tan^{-1}(B/G)$, or
\n $\tan^{-1}(2\pi f \times C_p/G)$, or
\n $\tan^{-1}(1/(G \times 2\pi f \times L_p))$
\n $G_a = A + (B \times |G_m| + C/|G_m|) \times 100 [\%]$
\n $B_a = A + (B \times |B_m| + C/|B_m|) \times 100 [\%]$

11-18 Specications and Supplemental Characteristics

 B_{μ} = μ + (B_{μ} \sim μ μ + \sim μ μ + μ + \sim μ + \sim μ

Measurement Basic Accuracy (Supplemental Performance Characteristics)

 G_m and B_m are the measured G and B, respectively. A, B, and C are obtained from Figure 11-7.

^D Accuracy

Where, Z_a is $|Z|$ accuracy.

^L Accuracy (Depends on D)

where α and α is a transformation of α in α is a transformation of α

 $\|P\|$ = 2, $\|$ \sim E_{ll} , $\|$ is frequency in Hz, and E_{ll} is measured E, \mathbf{H} , D , and C are obtained from Figure 11-7.

^C Accuracy (Depends on D)

 $\mathcal{L} = \{ \mathcal{L} = \{ \mathcal{L} = \{ \mathcal{L} = \{ \mathcal{L} \mid \mathcal{L} = \{ \mathcal{L} \} \mid \mathcal{L} = \{ \mathcal{L} = \{ \mathcal{L} \} \mid \mathcal{L} = \{ \mathcal{L} \} \mid \mathcal{L} = \{ \mathcal{L} = \{ \mathcal{L} \} \mid \mathcal{L} = \{ \mathcal{L} = \{ \mathcal{L} \} \mid \mathcal{L} = \{ \mathcal{L} \} \mid \mathcal{L} = \{ \mathcal{L} = \{ \mathcal{L} \} \mid \mathcal{L} =$

 $|Z_c| \equiv (2\pi) \times C_m$) -, f is frequency in Hz, and C_m is measured U. A, D, and U are obtained from Figure 11-7.

Common to Network/Spectrum/Impedance Measurement

Display

Marker

Hard copy

Storage

GPIB

Printer parallel port

Option 001 DC Voltage/Current Source

The setting of option ⁰⁰¹ DC voltage/current source is independent of Channel ¹ and Channel ² settings.

Voltage

¹ current at DC source connector ² voltage at DC source connector

Probe Power

Specications When HP Instrument BASIC Is Operated

Figure 11-8. 8 bit I/O Port Pin Assignments

Figure 11-9. 24-bit I/O Interface Pin Assignment

Common to Network/Spectrum/Impedance Measurement

Table 11-1. Signal Source Assignment

General Characteristics

Input and Output Characteristics

Figure 11-10. Trigger Signal (External trigger input)

S-parameter test set interface

Common to Network/Spectrum/Impedance Measurement

Connector : D-SUB (25-pin)

Caution Do not connect ^a printer to this connector. If you connect ^a printer with the S-parameter test set interface connector (TEST SET-I/O INTERCONNECT), it may cause damage to the printer.

Figure 11-11. S-Parameter Test Set Interface Pin Assignments

Operation Conditions

 \overline{a}

Common to Network/Spectrum/Impedance Measurement

Non-operation Conditions

Others

EMC :Complies with CISPR ¹¹ (1990) / EN ⁵⁵⁰¹¹ (1991) : Group 1, Class ^A Complies with EN 50082-1 (1992) / IEC 1000-4-2 (1995) : ⁴ kV CD, 8 kV AD Complies with EN 50082-1 (1992) / IEC 1000-4-3 (1995) : 3 V/m, 27 MHz to 1 GHz Complies with EN 50082-1 (1992) / IEC 1000-4-4 (1995) : 1 kV / Main,0.5kV / Signal Line Complies with IEC 1000-3-2 (1995) / EN 61000-3-2 (1995) Complies with IEC 1000-3-3 (1994) / EN 61000-3-3 (1995)

Note: When tested at 3 V/m according to IEC $801-3/1984$, the residual response will be within specifications over the full immunity test frequency range of ²⁷ MHz to ¹⁰⁰⁰ MHz except when the analyzer frequency is identical to the transmitted interference signal test frequency.

This ISM device complies with Canadian ICES-001. Cet appareil ISM est conforme a la norme NMB-001 du Canada.

Safety Complies with IEC 1010-1 (1990), Amendment 1 (1992), Amendment 2 (1995) Certied by CSA-C22.2 No.1010.1-92

Power requirements

 \ldots : : : : : 90 V to 132 V, or 198 V to 264 V (automatically switched), 47 to 63 Hz, 300 VA max. Weight \ldots : \ldots Dimensions (with Option 001, 1CN, 1D5, and 1D7) (SPC)

Figure 11-12. Front View

Figure 11-13. Rear View

Figure 11-14. Side View

System Performance at Network Measurement

Typical System Performance

Introduction

The performance of the 4395A Network/Spectrum Analyzer (analyzer) depends not only on the performance of the analyzer but also on the conguration, the user-selected operating conditions, and the measurement calibration.

This section explains the residual errors remaining in ^a measurement system after accuracy enhancement. It provides information to calculate the total measurement uncertainty of different configurations. Graphs at the beginning of the section show examples of the performance that can be calculated using the methods in this section.

The sources of measurement errors are explained, with an error model flowgraph and uncertainty equations. Information is provided for conversion of the dynamic accuracy error (in dB) to a linear value for use in the uncertainty equations. The effects of temperature drift on measurement uncertainty are illustrated with graphs.

Typical system performance tables are provided for an ⁷ mm and 3.5mm systems using an $\frac{1}{2}$ to $\frac{1}{2}$ the $\frac{1}{2}$ sustainable the $\frac{1}{2}$ systems using the $\frac{1}{2}$ test sets, and $\frac{1}{2}$ the $\frac{1}{2}$ test sets, and $\frac{1}{2}$ the $\frac{1}{2}$ type-N systems using the 85046B and 87512B test sets.

Procedure and blank worksheets are supplied to compute the total error-corrected measurement uncertainty of ^a system. These procedures combine the terms in the tables, the uncertainty equation, and the nominal S-parameter data of the device under test.

Comparison of Typical Error-Corrected Measurement Uncertainty

Figure 11-15 through Figure 11-22 are examples of the measurement uncertainty data that can be calculated using the information provided in this section. These figures compare the reflection and transmission measurement uncertainty of a 7 mm system using different levels of error correction. Each figure shows uncorrected values and residual uncertainty values after response calibration, response and isolation calibration, and full one or two port calibration. The data applies to ^a frequency range of 300 kHz to 500 MHz with ^a stable temperature (no temperature drift), using compatible 7 mm calibration devices from the 85031B calibration kit.

The results shown in Figure 11-15 through Figure 11-22 can be obtained using the 85046A. Different measurement calibration procedures provide comparable measurement improvement for the following compatible connector types and test sets (using the compatible calibration kits): kits):

- \blacksquare 3.5 mm connectors
- 87511A and 87511A with 50 type-N connectors
- 87511B and 87511B with 75 type-N connectors

Reflection Uncertainty of a One-Port Device

Figure 11-15. Total Reflection Magnitude Uncertainty of One-Port Device

Figure 11-16. Total Reflection Phase Uncertainty of One-Port Device

Reflection Uncertainty of a Two-Port Device

Figure 11-17. Total Reflections Magnitude Uncertainty of Two-Port Device

Figure 11-18. Total Reflection Phase Uncertainty of Two-Port Device

Transmission Uncertainty of ^a Low-Loss Device

Figure 11-20. Total Transmission Phase Uncertainty of a Low-Loss Device

Transmission Uncertainty of ^a Wide Dynamic Range Device

Figure 11-21. Total Transmission Magnitude Uncertainty of a Wide Dynamic Range Device

Figure 11-22. Total Transmission Phase Uncertainty of a Wide Dynamic Range Device

Types of Residual Measurement Errors

Network analysis measurement errors can be separated into three types: systematic, random, and drift errors. Measurement errors that remain after measurement calibration are called residual measurement errors. See "Calibration for Network Measurement" in Appendix A for a detailed description of the systematic errors corrected by measurement calibration.

Residual Systematic Errors

These errors result from imperfections in the calibration standards, connector standards and interface, interconnecting cables, and instrumentation. These are the errors that affect transmission and reflection measurements.

These non-repeatable errors are due to trace noise, noise floor, and connector repeatability. They affect both transmission and reflection measurements.

Residual Drift Errors

These errors stem from frequency drift and instrumentation drift. They affect both kinds of measurements. Instrumentation drift is primarily temperature related.

System Error Model

Any measurement result is the vector sum of the actual test device response plus all error terms. The precise effect of each error term depends upon its magnitude and phase relationship to the actual test device response. When the phase of an error response is not known, phase is assumed to be worst case (0 or 180 degrees). Random errors such as noise and connector repeatability are generally combined in a root-sum-of the squares (RSS) manner. The error term related to thermal drift is combined on a typical basis as shown in each uncertainty equation given in the following paragraphs.

Figure 11-23 shows the error model for the analyzer with the 85046A/B S-parameter test set. This error model shows the relationship of the various error sources in the forward direction and can be used to analyze overall measurement performance. The model for signal flow in the reverse direction is similar. Note the appearance of the dynamic accuracy, noise errors, switch errors, and connector repeatability terms in both the reflection and transmission portions of the model.

Table 11-2. Parameters of System error Model

For measurement of one-port devices, set the crosstalk (C), load match (M_1) , transmission tracking (T_t) , transmission tracking drift (T_{td}), port 2 connector repeatability (R_{r2}, R_{t2}), and port 2 cable stability (S_{r2}, S_{t2}) error terms to zero.

Reflection Uncertainty Equations

Total Reflection Magnitude Uncertainty $(E_{rm}$

An analysis of the error model yields an equation for the reflection magnitude uncertainty. The equation contains all of the first order terms and the significant second order terms. The error term related to thermal drift is combined on a worst case basis with the total of systematic and random errors. The four terms under the radical are random in character and are combined on an RSS basis. The terms in the systematic error group are combined on ^a worst case basis. In all cases, the error terms and the S-parameters are treated as linear absolute magnitudes.

$$
E_{rm(linear)} = V_r + S_{11}T_{rd(magnitude)}
$$

\nand
\n
$$
E_{rm(log)} = 20log \left(1 \pm \frac{E_{rm}}{S_{11}}\right)
$$

\nwhere
\n
$$
V_r = S_r + \sqrt{W_r^2 + X_r^2 + Y_r^2 + Z_r^2}
$$

\n
$$
S_r = systematic error
$$

\n
$$
= (1 + T_{sw})(D + S_{r1}) + (T_{sw} + T_r)S_{11} + (M_{sw} + M_s + S_{r1})S_{11}^2
$$

\n
$$
+ (M_l + S_{r2} + M_{sw})S_{21}S_{12} + (A_m + U_m)S_{11}
$$

\n
$$
W_r = random low-level noise
$$

\n
$$
= 3N_l
$$

\n
$$
X_r = random high-level noise
$$

\n
$$
= 3N_hS_{11}
$$

\n
$$
Y_r = random port1 repeatability
$$

\n
$$
= R_{r1} + 2R_{t1}S_{11} + R_{r1}S_{11}^2
$$

\n
$$
Z_r = random port2 repeatability
$$

\n
$$
= R_{r2}S_{21}S_{12}
$$

Total Reflection Phase Uncertainty (E_{rp})

Reflection phase uncertainty is determined from a comparison of the magnitude uncertainty with the test signal magnitude. The worst case phase angle is computed. This result is combined with the error terms related to thermal drift of the total system, port ¹ cable stability, phase dynamic accuracy, and phase multiplexer switching uncertainty.

$$
E_{rp} = \arcsin\left(\frac{V_r - (A_m + U_m)S_{11}}{S_{11}}\right) + T_{rd(phase)} + 2S_{t1} + A_p + U_p
$$

Transmission Uncertainty Equations

Total Transmission Magnitude Uncertainty (E_{tm})

An analysis of the error model in Figure 11-23 yields an equation for the transmission magnitude uncertainty. The equation contains all of the first order terms and some of the signicant second order terms. The error term related to thermal drift is combined on ^a worst case basis with the total of systematic and random errors. The four terms under the radical are random in character and are combined on an RSS basis. The terms in the systematic error group are combined on a worst case basis. In all cases, the error terms are treated as linear absolute magnitudes.

$$
E_{tm(linear)} = V_t + S_{21}T_{td(magnitude)}
$$

\nand
\n
$$
E_{tm(log)} = 20log\left(1 \pm \frac{E_{tm}}{S_{21}}\right)
$$

\nwhere
\n
$$
V_t = S_t + \sqrt{W_t^2 + X_t^2 + Y_t^2 + Z_t^2}
$$

\n
$$
S_t = systematic error
$$

\n
$$
= C + (T_{sw} + T_t)S_{21} + (M_{sw} + M_s + S_{r1})S_{11}S_{21} + (M_{sw} + M_l + S_{r2})S_{21}S_{22} + (A_m + U_m)S_{21}
$$

\n
$$
W_t = random low-level noise
$$

\n
$$
= 3N_1
$$

\n
$$
X_t = random high-level noise
$$

\n
$$
= 3N_hS_{21}
$$

\n
$$
Y_t = random port1 repeatability
$$

\n
$$
= R_{t1}S_{21} + R_{r1}S_{11}S_{21}
$$

 Z_t = random port2 repeatability

$$
= R_{t2}S_{21} + R_{r2}S_{22}S_{21}
$$

Total Transmission Phase Uncertainty (E_{tp})

Transmission phase uncertainty is calculated from a comparison of the magnitude uncertainty with the test signal magnitude. The worst case phase angle is computed. This result is combined with the error terms related to phase dynamic accuracy, cable phase stability, thermal drift of the total system, and phase multiplexer switching uncertainty.

$$
E_{tp} = \arcsin\left(\frac{V_t - (A_m + U_m)S_{21}}{S_{21}}\right) + T_{td(phase)} + S_{t1} + S_{t2} + A_p + U_p
$$

Dynamic Accuracy

The dynamic accuracy value used in the system uncertainty equations is obtained from the analyzer's dynamic accuracy typical values. The typical value for magnitude dynamic accuracy is in dB, and it must be converted to a linear value to be used in the uncertainty equations. In addition, the analyzer's dynamic accuracy typical values are given for an input signal level from full scale in dB. This must be converted to a relative error (relative to the power at which the measurement calibration occurs) to be used in the system uncertainty equations.

Dynamic Accuracy (linear) = $10^{\frac{2}{20}}$ = $\frac{1}{20}$ = 1

Dynamic Accuracy (dB) = $20log(1 \pm Dy$ namic Accuracy (linear))

Magnitude Dynamic Accuracy

Typical magnitude dynamic accuracy can be expressed in the following equations:

Magnitude Dynamic Accuracy = $E_{\text{d1m}} + E_{\text{d2m}} + E_{\text{d3m}}$ $E_{\text{d1m}} = 1.39 \times 10^{-7} L$ $E_{\text{d2m}} = 1.73 \times 10^{-7}$ $E_{\text{d3m}} = \frac{0.95 \times 10^{-7}}{1}$ <u>Line and the community of the comm</u>

where,

 $L =$ Measurement level (linear, relative to full scale level) E_{d1m} = Magnitude compression error (dominant at high measurement level range) E_{d2m} = Magnitude residual error (dominant at middle measurement level range) E_{d3m} = Magnitude A/D converter differential nonlinearity error (dominant at low measurement level range)

Determining Relative Magnitude Dynamic Accuracy Error Contribution

Typical magnitude dynamic accuracy error contribution to system performance is expressd bellow:

Magnitude dynamic accuracy error = $|E_{\text{d1mMEAS}} - E_{\text{d1mREF}}|$

 $+$ max $(E_{d2mMEAS}, E_{d2mREF})$

 $+$ $E_{d3mMEAS}$ + E_{d3mREF}

where,

Suffix REF means errors at calibration Suffix MEAS means errors at DUT measurement

Phase Dynamic Accuracy

Typical phase dynamic accuracy can be expressed by the following equations:

$$
Magnitude\ \hbox{Dynamic Accuracy} \,=\, E_{\rm d1p} \,+\, E_{\rm d2p} \,+\, E_{\rm d3p}
$$

$$
E_{d1p} = 1.00L2
$$

\n
$$
E_{d2p} = 0.10
$$

\n
$$
E_{d3p} = \frac{6.13 \times 10^{-5}}{L}
$$

where,

 $L =$ Measurement level (linear, relative to full scale level) E_{d1p} = Phase compression error (dominant at high measurement level range) E_{d2p} = Phase residual error (dominant at middle measurement level range) E_{d3p} = Phase A/D converter differential nonlinearity error (dominant at low measurement level range)

Determining Relative Phase Dynamic Accuracy Error Contribution

Typical dynamic accuracy error contribution to system performance is expressd bellow:

Phase dynamic accuracy error = $|E_{d1pMEAS} - E_{d1pREF}|$ $+$ max $(E_{d2pMEAS}, E_{d2pREF})$ $+$ $E_{d3pMEAS}$ + E_{d3pREF}

where,

Suffix REF means errors at calibration Suffix MEAS means errors at DUT measurement

Six example graphs are provided: Figure 11-24 and Figure 11-25 show the typical magnitude and phase dynamic accuracy error with a reference power level of full scale, Figure 11-26 and Figure 11-27 with a reference power level of -20 dB from full scale, and Figure 11-28 and Figure 11-29 with a reference power level of -60 dB from full scale.

Dynamic Accuracy Error Contribution

Figure 11-24. Typical Magnitude Dynamic Accuracy Error (@Reference Power Level=Full Scale)

Figure 11-25. Typical Phase Dynamic Accuracy Error (@Reference Power Level=Full Scale)

Dynamic Accuracy

Dynamic Accuracy Error Contribution

Figure 11-26. Typical Magnitude Dynamic Accuracy Error (@Reference Power Level=20 dB from Full Scale)

Figure 11-27. Typical Phase Dynamic Accuracy Error (@Reference Power Level=20 dB from Full Scale)

Dynamic Accuracy Error Contribution

Figure 11-28. Typical Magnitude Dynamic Accuracy Error (@Reference Power Level = -60 dB from Full Scale)

Figure 11-29. Typical Phase Dynamic Accuracy Error (@Reference Power Level = -60 dB from Full Scale)

Effects of Temperature Drift

Figure 11-30 to Figure 11-33 are graphs showing the effects of temperature drift on error-corrected measurement uncertainty values. Values are shown for changes of \pm 1 C, \pm 5°C and \pm 5°C from the ambient temperature. Figure 11-50 and Figure 11-51 show total reflection magnitude and phase uncertainty with temperature drift following an S_{11} one-port calibration. Figure 11-32 and Figure 11-33 shows the total transmission magnitude and phase uncertainty with temperature drift following a full two-port error correction. The graphs apply to measurements up to 500 MHz.

Temperature Drift with S₁₁ One-Port Calibration

Figure 11-31. Total Refection Phase Uncertainty (@One-Port Cal)

Effects of Temperature Drift

Temperature Drift with Full Two-Port Calibration

Figure 11-32. Total Transmission Magnitude Uncertainty (@Full Two-Port Cal)

Figure 11-33. Total Transmission Phase Uncertainty (@Full Two-Port Cal)

System performance with Different Test Sets and Connector Types

The tables in the following pages provides typical system performance for sytems using different test sets and different connector types. The values listed are for uncorrected measurements and for corrected measurements after measurement calibration. The linear value is shown in parenthesis with the dB value.

System performance with Different Test Sets and Connector Types

Table 11-3. Typical System Performance for Devices with ⁷ mm Connectors 4395A with 87511A Test Set (300 kHz to ⁵⁰⁰ MHz)

1 Accuracy enhancement procedures are performed using 85031B 7 mm calibration kit. Enviromental temperature is 23°C \pm 5°C at calibration: \pm 1°C from calibration temperature must be maintained for valied measurement calibration.

² With IF bandwidth of 10 Hz.

³ With impedance matched load.

⁴ High-level noise is the RMS of a continuous measurement of a short circuit or thru.

- ⁵ Arrived at by bending 11857D cables out perpendicular to front panel and reconnecting. Stability is much better with less flexing.
- ⁶ Arrived at using 11857D cables and full 2-port calibration. Drift is much better without calbes and with 1-port calibration. For this case, drift typically is $[0.1 + 0.05]$ XT (GHz)] χ Δ °C, degrees.

System performance with Different Test Sets and Connector Types

Table 11-4. Typical System Performance for Devices with 3.5 mm Connectors 4395A with 87511A Test Set (300 kHz to ⁵⁰⁰ MHz)

¹ Accuracy enhancement procedures are performed using 85033C 3.5 mm calibration kit. Enviromental temperature is Δ 3°C \pm 3°C at calibration: \pm 1°C from calibration temperature must be maintained for valied measurement calibration.

² With IF bandwidth of 10 Hz.

³ With impedance matched load.

⁴ High-level noise is the RMS of a continuous measurement of a short circuit or thru.

- ⁵ Arrived at by bending 11857D cables out perpendicular to front panel and reconnecting. Stability is much better with less flexing.
- ⁶ Arrived at using 11857D cables and full 2-port calibration. Drift is much better without calbes and with 1-port calibration. For this case, drift typically is $[0.1 + 0.05]$ XI (GHz)] χ Δ °C, degrees.

System performance with Different Test Sets and Connector Types

Table 11-5. $T_{\rm J}$ premi $T_{\rm J}$ second Performance for Devices with 50 μ $T_{\rm J}$ pc in Connections 4395A with 87511A Test Set (300 kHz to ⁵⁰⁰ MHz)

1 Accuract chimitoritativ procedures are performed agnis 85032B 30 M (the It canonal temperature accuracy compo is 25°C \pm 5°C at calibration: \pm 1°C from calibration temperature must be maintained for valied measurement calibration.

² With IF bandwidth of 10 Hz.

³ With impedance matched load.

⁴ High-level noise is the RMS of a continuous measurement of a short circuit or thru.

⁵ Arrived at by bending 11857D cables out perpendicular to front panel and reconnecting. Stability is much better with less flexing.

⁶ Arrived at using 11857D cables and full 2-port calibration. Drift is much better without calbes and with 1-port calibration. For this case, drift typically is $[0.1 + 0.05]$ XT (GHz)] χ Δ °C, degrees.
System performance with Different Test Sets and Connector Types

Table 11-6. $T_{\rm J}$ press $S_{\rm J}$ seem Ferrormance for Devices with 75 μ $T_{\rm J}$ pc in Connections 4395A with 87511B Test Set (300 kHz to ⁵⁰⁰ MHz)

1 Accuract chinancement procedures are performed using 85036B 75 M (196 T) canviature mit matematum temperatur is 25°C \pm 5°C at calibration: \pm 1°C from calibration temperature must be maintained for valied measurement calibration.

² With IF bandwidth of 10 Hz.

³ With impedance matched load.

⁴ High-level noise is the RMS of a continuous measurement of a short circuit or thru.

- ⁵ Arrived at by bending 11857D cables out perpendicular to front panel and reconnecting. Stability is much better with less flexing.
- ⁶ Arrived at using 11857D cables and full 2-port calibration. Drift is much better without calbes and with 1-port calibration. For this case, drift typically is $[0.1 + 0.05]$ XI (GHz)] χ Δ °C, degrees.

System performance with Different Test Sets and Connector Types

Table 11-7. $T_{\rm J}$ press dystem Ferformance for Devices with 50 h $T_{\rm J}$ pc it connected $T_{\rm J}$ 4395A with 87512A Test Set (100 Hz to ⁵⁰⁰ MHz)

2 AACCURACY ENHANCEMENT PROCEDURES ARE PERFORMED WANTED SOURCES IN THE ANNUAL MAY ARRESTED FROM THE PROPERTY OF ω C \pm C at calibration: \pm FC from calibration temperature must be maintained for valied measurement calibration.

² With IF bandwidth of 10 Hz.

³ Transmission Only

4 ω f > 500 kHz.

⁵ High-level noise is the RMS of a continuous measurement of a short circuit or thru.

⁶ Arrived at by bending 11857D cables out perpendicular to front panel and reconnecting. Stability is much better with less flexing.

⁷ Arrived at using 11857D cables and full 2-port calibration. Drift is much better without calbes and with 1-port calibration. For this case, drift typically is $[0.1 + 0.05]$ XT (GHz)] χ Δ °C, degrees.

System performance with Different Test Sets and Connector Types

Table 11-8. $T_{\rm J}$ press dystem Ferrormance for Devices with 75 h $T_{\rm J}$ pc it connected $T_{\rm J}$ 4395A with 87512B Test Set (100 Hz to ⁵⁰⁰ MHz)

¹ Accuracy enhancement procedures are performed using 85036B ⁷⁵ type-N calibration kit. Enviromental temperature is z $3\circ$ C $\pm 5\circ$ C at calibration: $\pm 1\circ$ from calibration temperature must be maintained for valied measurement calibration.

² With IF bandwidth of 10 Hz.

³ High-level noise is the RMS of a continuous measurement of a short circuit or thru.

⁴ Arrived at by bending 11857D cables out perpendicular to front panel and reconnecting. Stability is much better with less flexing.

⁵ Arrived at using 11857D cables and full 2-port calibration. Drift is much better without calbes and with 1-port calibration. For this case, drift typically is $[0.1 + 0.05]$ XI (GHz)] χ Δ C. degrees.

Determining Expected System performance

The uncertainty equations, dynamic accuracy calculations, and tables of system performance values provided in the preceding pages can be used to calculate the expected system performance. The following pages explain how to determine the residual errors of a particular system and combine them to obtain total error-corrected residual uncertainty values, using worksheets provided. The uncertainty graphs at the beginning of this *System performance* section are examples of the results that can be calculated using this information.

Procedures

Table 11-9 is a worksheet used to calculate the residual uncertainty in reflection measurements. Table 11-10 is ^a worksheet for residual uncertainty in transmission measurements. Determine the linear values of the residual error terms and the nominal linear S-parameter data of the device under test as described below and enter these values in the worksheets. Then use the instructions and equations in the worksheets to combine the residual errors for total system uncertainty performance.

S-parameter Values. Convert the S-parameters of the test device to their absolute linear terms.

Noise Floor. See the Receiver Noise Level Performance Test in the Service Manual to determine the actual noise floor performance of your measurement setup.

Crosstalk. See the Input Crosstalk Performance Test. Connect an impedance-matched load to each of the test ports and measure S_{21} or S_{12} after calibration. Turn on the marker statistics function, and measure the mean value of the trace. Use the mean value plus one standard deviation as the residual crosstalk value of your system.

Dynamic Accuracy. Determine the absolute linear magnitude dynamic accuracy as described under Dynamic Accuracy In this chapter.

Other Error Terms. See Table 11-3 through Table 11-8, depending on the test set and connector type in your system. Find the absolute linear magnitude of the remaining error terms.

Combining Error Terms. Combine the above terms using the reflection or transmission uncertainty equation in the worksheets.

Determining Expected System performance

Table 11-9. Reflection Measurement Uncertainty Worksheet

¹ With IF bandwidth of 10 Hz.

Determining Expected System performance

Table 11-10. Transmission Measurement Uncertainty Worksheet

¹ With IF bandwidth of 10 Hz.

Accessories and Options

Options Available

DC SOURCE (Option 001)

DC SOURCE supplies up to ± 40 V / ± 100 mA of DC voltage/current.

High Stability Frequency Reference (Option 1D5)

This option, ^a ¹⁰ MHz crystal in temperature stabilized oven, improves the source signal frequency accuracy and stability. This option can be retrofitted using the 4395U Upgrade Kit Option 1D5.

Time-Gated Spectrum Analyzer (Option 1D6)

This option allows the capability of intermittent or burst signal spectrum measurement. This option can be retrotted using the 4395U Upgrade Kit Option 1D6.

⁵⁰ to ⁷⁵ Input Impedance Conversion (Option 1D7)

This option oers ⁷⁵ input impedance for the spectrum measurement. The 11852B option \sim 0.0 to 1.0 m minimum ross pada and 6.0 m to 1.0 m suppremental characteristics are supplied to with this option. This option can be retrofitted using the 4395U Upgrade Kit Option 1D7.

Impedance Measurement Function (Option 010)

This option allows the capability of impedance measurement function. This option can be retrofitted using the 43961A Impedance Test Kit. This option can be retrofitted using the 4396U Upgrade Kit Option 010.

Handle Kit (Option 1CN)

This option is a rack mount kit containing a pair of handles and the necessary hardware to mount the instrument.

Rack Mount Kit (Option 1CM)

This option is a rack mount kit containing a pair of flanges and the necessary hardware to mount the instrument, with handles detached, in an equipment rack with 482.6 mm (19 inches) horizontal spacing.

Rack Mount and Handle Kit (Option 1CP)

This option is a rack mount kit containing a pair of flanges, and the necessary hardware to mount the instrument with handles attached in an equipment rack with 482.6 mm (19 inches) horizontal spacing.

Measurement accessories available

Test Sets

87511A/B S Parameter Test Set 87511A/B ^S Parameter Test Set

These test sets contain the hardware required to measure all four S-parameters of ^a two-port oo or 10 in deviled in the test set is controlled by the controlled by the distribution by the analyzer so that \sim measurement can be made without changing the connections to the DUT (device under test). Each test set also contains two internal dc bias tees for biasing active devices. The test port connectors for the 87511A are precision ⁷ mm connectors, and the 87511B test port connectors are ⁷⁵ type-N(f).

87512A/B Transmission/Reflection Test Set

These test sets contain the hardware required to measure simultaneous transmission and α is characteristics of a α or α is a α in one direction only. The test port connection is ⁵⁰ type-N(f) on the 87512A and ⁷⁵ type-N(f) on the 87512B.

Active Probes

41800A Active Probe (5 Hz to ⁵⁰⁰ MHz)

This is ^a high input impedance probe for in-circuit measurements that cover the frequency range of ⁵ Hz to ⁵⁰⁰ MHz.

41802 - 11802 - 12802 - 12802 - 1280 - 1290 - 1290 - 1290 - 1290 - 1290 - 1290 - 1290 - 1290 - 1290 - 1290 - 1

This adapter allows use of a high impedance probe. It has ^a frequency range of ⁵ Hz to ¹⁰⁰ MHz.

1141A Differential Probe

This is an FET differential probe with 200 MHz bandwidth and $3000:1$ CMRR, The 1141A must be used with the 1142A Probe Control and Power Module.

Power Splitters

11850C,D Three-way Power Splitters

These are four-port, three-way power splitters. One output arm is used as the reference for the network analyzer in making ratio measurements and the other two output arms are test channels. The 11850C range of December of December of December of December of December and an impedance of 50 M 11880 from a frequency range of DC to 2 GHz and an impedance of 15 m \sim

11667A Power Splitter

This is a two-way power splitter with one output arm used for reference and one for test. It $\mathbf{r}_{\mathbf{u}}$ and $\mathbf{r}_{\mathbf{u}}$ range of D $\mathbf{v}_{\mathbf{u}}$ to $\mathbf{r}_{\mathbf{u}}$ and $\mathbf{r}_{\mathbf{u}}$ and $\mathbf{r}_{\mathbf{u}}$

Calibration Kits Calibration Kits

The following calibration kits contain the precision standards (and the required adapters) for the indicated connector types. The standards facilitate measurement calibration (also called vector error correction). Refer to the applicable data sheet and ordering guide for additional information. Part numbers for the standards are in their respective manuals.

- \blacksquare 85033D 3.5 mm Calibration Kit
- 85031B 7 mm Calibration Kit
- 85032B ⁵⁰ Type-N Calibration Kit
- 85036B ⁷⁵ Type-N Calibration Kit

Cables

The following RF cables are used to return the transmitted signal to the test set when measuring two-port devices. These cables provide shielding for high dynamic range measurements.

11857D 7 mm Test Port Return Cable Set <u>11857 - Medicine Sett Port Return Cable Sett</u>

These are ^a pair of test port return cables for use with the 87511A Option ⁰⁰¹ S-parameter test set. The cables can be used when measuring devices with connectors other than ⁷ mm by using the appropriate precision adapters.

11857B ⁷⁵ Type-N Test Port Return Cable Set

These are ^a pair of test port return cables for use with the 87511B S-parameter test set.

11851B ⁵⁰ Type-N RF Cable Set

This kit contains the three phase-matched ⁵⁰ type-N cables necessary to connect the 87512A transmission/reflection test kits or a power splitter to the analyzer. It also contains an RF cable used to return the transmitted signal of ^a two-port device to the network analyzer.

BNC Cables

- P/N 8120-1838 ⁵⁰ BNC Cable (30 cm)
- P/P/N 8120-010-1839 50 BMC 2010-01-1939 50 BMC 2010
- P/P/N 8220-2020 50 BP/P 8220 FOR CABLE (122 CM)

Adapters

11852B 50 to 75 Minimum Loss Pad (DC to 2 GHz)

This active control to the impedance from open the interest formateless is a control to female or . It will be two swamps as a low in two swamp was interested with a low to the control of the first matches with analyzer or a 50 measurement accessory. An 11852B pad is included with the 87512B 75 <u>ection test and the stranged with three 1185</u> Days in the 1185 Days and 1185 Days are included with the 1185 B pad splitter and one is included with the 4395A Option 1D7.

Adapter Kits

The following adapter kits contain the connection hardware required for making measurements on devices of the indicated connector type.

- 11869 The Second County of the Mathematic County of the Second County of th
- 11954 Basic Basic Adapter Kitchen Adapter Kitchen Kitchen Kitchen Kitchen Kitchen Kitchen Kitchen Kitchen Kitch

Measurement accessories available

- 11955 Type-N Adapter Kitchen K
- 11956 TO BLOCK AND ADDITIONAL PLAN

System accessories available

Printer

The analyzer can output displayed measurement results directly to supported peripherals, not using external computers. Supported printers are as follows.

Printer		Monochrome Printing Fixed Color Printing Variable Color Printing
HP DeskJet 340J		
HP DeskJet 505		
HP DeskJet 560C		
HP DeskJet 694C		
HP DeskJet 850C		
HP DeskJet 1200		
HP DeskJet 1600CM		

Table 12-1. Supported Printers and Printing Modes

GPIB cable

An GPIB cable is required to interface the analyzer with ^a computer, or other external instrument. The following cables are available:

- $10833A(1 m)$
- $10833B(2 m)$
- $10833C(3 m)$
- $10833D(0.5 m)$

External Monitors

The analyzer can control the built-in LCD and an external monitor simultaneously. Color monitors supporting VGA can be used as an external monitor.

Basic Measurement Theory

This chapter provides additional information on analyzer features beyond the basics covered in the previous chapters. It deals with the following topics:

- System Overview
- Data Processing Flow
- Network Analyzer Basic
	- Network Measurement Basic
	- \Box S-parameters
	- \Box Conversion
	- \Box Smith Chart
	- □ Polar Chart
	- \Box Electrical Delay
	- \Box Averaging
	- \Box IF Band Reduction
	- \Box Group Delay
- Spectrum Analyzer Basic
	- $\hfill\Box$

 Detection Mode
	- \Box Swept and FFT Mode
	- \Box Resolution Bandwidth (RBW)
	- \Box Selectivity of the RBW
	- Noise Measurement
	- \Box Gated Sweep for Spectrum Measurement
- Measurement and Display Points
- **Limit Line Concept**
- Marker
- GPIB
- Calibration for Network Measurement

System Overview

The 4395A has three analyzer modes; network, spectrum, and impedance (available with option 010).

In network analyzer mode, the 4395A measures the reflection and transmission characteristics of devices and networks by applying ^a known swept signal and measuring the response of the test device. The signal transmitted through the device or reflected from its input is compared with the incident signal generated by a swept RF source. The signals are applied to ^a receiver for measurement, signal processing, and display. The network analyzer system consists of ^a source, signal separation devices, a receiver, and a display.

In spectrum analyzer mode, the 4395A measures the amplitude and frequency of ^a signal spectral line by sweeping the tuning frequency of the receiver. The test signal is applied to ^a receiver through an input attenuator. The spectrum analyzer consists of an input attenuator, ^a receiver, and a display.

Impedance analyzer mode is available with option 010, and requires the 43961A RF impedance test kit as well. In impedance analyzer mode, the 4395A applies test signals to the DUT through the impedance test kit, and determines the impedance characteristics of the DUT by ^a method called the I-V analysis method, that is, by measuring the voltage (V) and current across the DUT. The 4395A's impedance analyzer system consists of ^a signal source, a test kit (the 43961A RF impedance test kit), ^a receiver, and ^a data display device.

Figure A-1 is a schematic block diagram that briefly illustrates the $4395A$'s principle of operation. For more information, refer to *Service Manual (English)*(Agilent part number: 04395-90100), which describes the 4395A's principle of operation in greater detail with ^a complete block diagram.

Figure A-1. Schematic block diagram

Data Processing

Overview

The 4395A's receiver converts the R, A, and B input signals into useful measurement information. This conversion occurs in two main steps. First, the high frequency input signal is translated to fixed low frequency IF signals using analog mixing techniques (see the "Theory of Operation" in the Service Manual for details). Second, the IF signals are converted into digital data by an analog-to-digital converter (ADC). From this point on, all further signal processing is performed mathematically by the analyzer microprocessor and digital signal processor. The following paragraphs describe the sequence of math operations and the resulting data arrays as the information flows from the ADC to the display. They provide a good foundation for understanding most of the measurement functions and the order in which they are performed.

The 4395A has three data processing flow paths: one is for network analyzer mode, another for spectrum analyzer mode, and the other is for impedance analyzer mode. The data flow is automatically changed when analyzer mode is changed.

Figure A-2, Figure A-3, and Figure A-4 provide data processing flow diagrams that represent the flow of numerical data from IF detection to display. The data passes through several math operations (shown as single-line boxes). Most of these operations can be selected and controlled through the front panel MEASUREMENT block menus. The data is also stored in data arrays (shown as double-line boxes). These arrays are places in the flow path where the data is accessible via GPIB or using the internal disk drive or the memory disk.

Note While only a single flow path is shown, two identical paths are available that correspond to channel ¹ and channel 2. When the channels are uncoupled, each channel can be independently controlled so that the data processing operations for one can be different from the other.

Data Processing for Network Measurement

Figure A-2. Data Processing for Network Measurement

Digital Filter

The digital filter detects the IF signal by performing a discrete Fourier transform (DFT) on the digital data. The samples are converted into complex number pairs (real plus imaginary, $R+jI$) that represent both the magnitude and phase of the IF signal. The filter shape can be altered by selecting the IF bandwidth in Hz from the 10, 30, 100, 300, 1 k, 3 k, 10 k, and 40 k choices. Changing the filter shape is a highly effective technique for noise reduction.

Ratio Calculations

These calculations are performed if the selected measurement is a ratio of two inputs (for example, A/R or B/R). This is simply a complex divide operation. If the selected measurement is absolute (for example, A or B), no operation is performed. The R, A, and B values are also split into channel data at this point.

Frequency Characteristics Correction by Corrective Data Arrays

This corrects the frequency response for absolute measurement value, using corrective data arrays. If the selected measurement is ratio (for example, A/R or B/R), no operation is performed.

Averaging

This is one of the noise reduction techniques. This calculation involves taking the complex exponential average of up to 999 consecutive sweeps. See "Averaging (Sweep Averaging)" under the heading "Network Measurement Basics" in this chapter.

Raw Data Arrays

These arrays store the results of all the preceding data processing operations. When full 2-port error correction is on, the raw data arrays contain all four S-parameter measurements required for accuracy enhancement. When the channels are uncoupled (coupled channels off), there may be as many as eight raw data arrays. These arrays are directly accessible via GPIB, or using the internal disk drive or the memory disk. Note that the numbers here are still complex pairs.

Calibration Coefficient Arrays

When ^a measurement calibration has been performed and correction is turned on, error correction removes the repeatable systematic errors (stored in the calibration coefficient arrays) from the raw data arrays. This can vary from simple vector normalization to full 12-term error correction.

The calibration coefficient arrays themselves are created during a measurement calibration using data from the raw data arrays. These are subsequently used whenever correction is on, and are accessible via GPIB, or using the internal disk drive or the memory disk.

Data Arrays

The results of error correction are stored in the data arrays as complex number pairs. These arrays are accessible via GPIB or by using the internal disk drive or the memory disk.

Memory Arrays

If the data-to-memory operation is performed (using the $DATA-MEMORY$ softkey), the data arrays are copied into the memory arrays (data trace arrays are also copied into the memory trace array at same time). These arrays are accessible using the internal disk drive or the memory disk. When accessed via GPIB, these arrays are read-only.

If memory is displayed, the data from the memory arrays goes through the same data processing flow path as the data from the data arrays.

Electrical Delay and Phase Offset

This involves adding or subtracting a linear phase in proportion to frequency. This is equivalent to "line-stretching" or artificially moving the measurement reference plane. For more information, see "Electrical Delay" under the heading "Network Measurement Basics" in this chapter. .

Conversion

Transforms S-parameter measurement data into equivalent complex impedance (Z) or admittance (Y) values, to inverse S-parameters $(1/S)$, or to phase multiples of 4, 8, or 16. See "Conversion Function" under the heading "Network Measurement Basics" in this chapter..

Data Processing

Format

This converts complex number pairs into ^a scalar representation for display, according to the selected format. This includes group delay calculations. Note that, once complex data has been formatted, it cannot be restored. See "Group Delay" for information on group delay principles.

Data Hold

This keeps the maximum or minimum value at each display point when the data hold function is turned on.

Data Math

This calculates the complex ratio of the two (data/memory), the difference (data-memory), or summation (data+memory) when the data math function is selected. In addition, this function multiplies the ratio, difference, or summation by a constant, or subtracts a constant from them.

Data Trace Arrays

The results are stored in the data trace arrays. It is important to note those marker values and marker functions are all derived from the data trace arrays. Limit testing is also performed on this array. The data trace arrays are accessible via GPIB, or using the internal disk drive or the memory disk.

Memory Trace Arrays

If the data-to-memory operation is performed, the data trace arrays are copied into the memory trace arrays (data arrays are also copied into the memory array at same time). These arrays are accessible using the internal disk drive or the memory disk. When accessed via GPIB, these arrays are read-only.

Scaling

These operations prepare the formatted data for display on the LCD. This is where the appropriate reference line position, reference line value, and scale calculations are performed.

Data Processing for Spectrum Measurement

Figure A-3. Data Processing for Spectrum Measurement

Decimation Windowing

This function reduces the sampling rate to resolve the spectrum closer than the frequency resolution (which is decided by an inherent sampling rate and finite sampling number).

Fast Fourier Transform (FFT)

This operation transforms a time domain signal into a frequency domain data using the Fast Fourier Transform.

Data Processing

Absolute Squared (ABS²)

This calculates the power of the spectrum.

Video Averaging

Video Averaging is one of the noise reduction techniques. The video bandwidth can be selected to be RBW/1, RBW/3, RBW/10, RBW/100, or RBW/300.

Detection

This detects the value of ^a given display point in one of three modes: positive, negative, and sample. For more information, see "Detection Modes" under the heading "Network Measurement Basics" in this chapter.

Attenuator Adjustment

This adjustment corrects the value to what it was before being attenuated.

Averaging

Refer to "Averaging" under "Data Processing for Network Measurement" in this chapter.

Frequency Characteristics Level Correction

This process digitally corrects for frequency response errors in the analog down-conversion path.

Raw Data Arrays

These arrays store the results of all the data produced by the peak detector. These arrays are directly accessible via GPIB or by using the internal disk drive or the memory disk. In spectrum analyzer mode, row data arrays hold only the real number part of values.

Memory Arrays

If the data-to-memory operation is performed (using the $DATA-MEMORY$ softkey), the data arrays are copied into the memory arrays (data trace arrays are also copied into the memory trace arrays at same time). These arrays are accessible using the internal disk drive or the memory disk. When accessed via GPIB, these arrays are read-only. are also output via GPIB, but data cannot be input into them via GPIB.

If memory is displayed, the data from the memory arrays goes through the same data processing flow path as the data from the data arrays.

Format/Unit conversion

This converts the measured values (dB value) to other unit (dBV, $dB\mu V$, watt, and volt). When noise measurement is selected, this divides measured values by the equivalent noise bandwidth to measure noise level directly.

Data Hold

Refer to "Data Hold" under "Data Processing for Network Measurement" in this chapter.

Data Math

Refer to "Data Math" under "Data Processing for Network Measurement" in this chapter.

Data Trace Array

Refer to "Data Trace Array" under "Data Processing for Network Measurement" in this chapter. Note that, in spectrum analyzer mode, data trace arrays hold only the real number part of data.

Memory Trace Array

Refer to "Memory Trace Array" under "Data Processing for Network Measurement" in this chapter. Note that, in spectrum analyzer mode, memory trace arrays hold only the real number part of data.

Scaling

Refer to "Scaling" under "Data Processing for Network Measurement" in this chapter.

Data Processing

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Figure A-4. Data Processing for Impedance Measurement

Digital Filter

Refer to "Digital Filter" under "Data Processing for Network Measurement" in this chapter.

Voltage/Current Ratio

This is simply a complex divide operation. The R and A values are split into channel data at this point.

LV to Reflection Coefficient Conversion I-V to Re
ection Coecient Conversion

Converts the calculated V/I (voltage/current ratio) into Γ (reflection coefficient) data. The 4395A uses the reflection coefficient as its internal data.

Calibration Coefficient Arrays/Calibration

During calibration, the 4395A measures three types of standards and stores them in the calibration coefficient arrays. This data is used to carry out S_{11} 1 port calibration against the Γ value determined through the I-V $\rightarrow \Gamma$ conversion and to determine the APC-7 calibration level of the 43961A.

Averaging

Refer to "Averaging" under "Data Processing for Network Measurement" in this chapter.

Raw Data Arrays

These arrays store the results of all the preceding data processing operations as reflection coefficients (Γ) . These arrays are directly accessible via GPIB, or using the internal disk drive or the memory disk. Note that the numbers here are still complex pairs.

Fixture Compensation Coefficient Arrays/Fixture Compensation

During fixture compensation, 4395A measures three types of standards and stores them in the fixture compensation coefficient arrays. This data is used to remove errors attributable to the fixture. These arrays are directly accessible via GPIB, or using the internal disk drive or the memory disk.

Data Arrays

The results of fixture compensation are stored in the data arrays as complex number pairs. These arrays are accessible via GPIB or by using the internal disk drive or the memory disk.

Memory Arrays

If the data-to-memory operation is performed (using the $DATA-MEMORY$ softkey), the data arrays are copied into the memory arrays (data trace arrays are also copied into the memory trace arrays at same time). These arrays are accessible using the internal disk drive or the memory disk. When accessed via GPIB, these arrays are read-only.

If memory is displayed, the data from the memory arrays goes through the same data processing flow path as the data from the data arrays.

Conversion

When impedance or admittance is specied as a measurement parameter, the 4395A converts the corresponding reflection coefficient into the impedance or admittance value. In this case, however, the raw data, data, and memory arrays store the data as reflection coefficients, not as an impedance value.

Format

Refer to "Format" under "Data Processing for Network Measurement" in this chapter.

Data Hold \sim \sim \sim \sim \sim \sim \sim \sim

Refer to "Data Hold" under "Data Processing for Network Measurement" in this chapter.

Data Processing

Data Math

Refer to "Data Math" under "Data Processing for Network Measurement" in this chapter.

Data Trace Array

Refer to "Data Trace Array" under "Data Processing for Network Measurement" in this chapter.

Memory Trace Array

Refer to "Memory Trace Array" under "Data Processing for Network Measurement" in this chapter.

Scaling

Refer to "Scaling" under "Data Processing for Network Measurement" in this chapter.

Network Measurement Basics

S-parameters

S-parameters (scattering parameters) are a convention that characterizes the way a device modifies signal flow. A brief explanation is provided here of the S-parameters of a two-port device. For additional details see Agilent Technologies Application Notes A/N 95-1 and A/N 154.

S-parameters are always ^a ratio of two complex (magnitude and phase) quantities. S-parameter notation identies these quantities using the numbering convention:

\sim out in

Where the first number (out) refers to the port where the signal is emerging and the second number (in) is the port where the signal is incident. For example, the S-parameter S_{21} identifies the measurement as the complex ratio of the signal emerging at port ² to the signal incident at port 1.

Figure A-5 is ^a representation of the S-parameters of ^a two-port device, together with an equivalent flow graph. In the illustration, "a" represents the signal entering the device and "b" represents the signal emerging. Note that ^a and ^b are not related to the ^A and ^B input ports on the analyzer.

Figure A-5. S-Parameters of a Two-Port Device

S-parameters are exactly equivalent to the more common description terms below, requiring only that the measurements are taken with all DUT ports properly terminated.

Conversion Function

This function converts the measured reflection or transmission data to the equivalent complex impedance (Z) or admittance (Y) values. This is not the same as a two-port Y or Z parameter conversion, as only the measured parameter is used in the equations. Two simple one-port conversions are available, depending on the measurement conguration.

An S_{11} or S_{22} trace measured as reflection can be converted to an equivalent parallel impedance or admittance using the model and equations shown in Figure A-6.

Figure A-6. Reflection Impedance and Admittance Conversions

In ^a transmission measurement, the data can be converted to its equivalent series impedance or admittance using the model and equations shown in Figure A-7.

Figure A-7. Transmission Impedance and Admittance Conversions

Avoid using Smith chart, SWR, and delay formats for displaying Z and Y conversions, as these formats are not the status interpreted interpreted. Marker values in the contrest of the contrest in the ma conversions, or admittance values in S units for Y conversions in any format.

Smith Chart Smith Charles Co

A Smith chart is used in reflection measurements to provide a readout of the data in terms of impedance. The intersecting lines on a Smith chart represent constant resistance and constant reactance values, normalized to the characteristic impedance, Z_0 , of the system. Reactance values in the upper half of the Smith chart circle are positive (inductive) reactance, and in the lower half of the circle are negative (capacitive) reactance. lower half of the circle are negative (capacitive) reactance.

Polar Chart

Each point on the polar format corresponds to a particular value of both magnitude and phase. Quantities are read vectorally: the magnitude at any point is determined by its displacement from the center (which has zero value), and the phase by the angle counterclockwise from the positive x-axis. Magnitude is scaled in ^a linear fashion, with the value of the outer circle usually set to a ratio value of 1. Because there is no frequency axis, frequency information is read from the markers.

Electrical Delay

The electrical delay function simulates ^a variable length loss-free transmission line that can be added to or removed from a receiver input to compensate for interconnecting cables, etc. This function is similar to the mechanical or analog \line stretchers" of conventional network analyzers. Delay is annotated in units of time with secondary labeling in electrical length, associated with equivalent length of the transmission line if a value for VELOCITY FACTOR (see below) is specified.

To obtain the characteristics of the DUT itself free of the in
uence of interconnecting cables, use ELECTRICAL DELAY under ELECTRICAL DELAY MENU, and enter the following setting:

Electrical delay
$$
\Delta t = \frac{\Delta \theta}{F \times 360} [sec]
$$

where:

 F (Hz) Measuring frequency

 $\Delta\theta$ (degree) Difference between measuring frequency without cables and that with the

In this case, the 4395A displays the electrical length of the interconnecting cable to compensate for, along with the value of electrical delay:

$$
\Delta l = v \circ \times \Delta t [m]
$$

where:

 $vo (=2.997925E8)$ (m/sec) light velocity in vacuum

If the average relative permittivity (ϵ_r) of the DUT is known over the frequency span, the length calculation can be adjusted to reflect the actual length of the DUT more closely. This can be done by entering the relative velocity factor for the DUT using VELOCITY FACTOR under the $\overline{(\mathsf{Ca})}$ key:

$$
\frac{1}{\sqrt{\epsilon_r}}
$$

assuming a relative permeability of 1.

Averaging (Sweep Averaging)

Averaging computes each data point based on an exponential average of consecutive sweeps weighted by ^a user-specied averaging factor. Each new sweep is averaged into the trace until the total number of sweeps is equal to the averaging factor, for a fully averaged trace. Each point on the trace is the vector sum of the current trace data and the data from the previous sweep. ^A high averaging factor gives the best signal-to-noise ratio, but slows the trace update time. Doubling the averaging factor reduces the noise by 3 dB. The algorithm used for averaging is:

$$
A_{(n)} = \frac{S_{(n)}}{n} + (1 - \frac{1}{n}) \times A_{(n-1)}
$$

where:

- $A(n)$ = current average $(1 \leq n \leq F)$ $S(n)$ = current measurement $(1 \leq n \leq F)$
- $F = average factor$

IF Band Reduction

IF bandwidth reduction lowers the noise floor by reducing the receiver input bandwidth. It has an advantage over averaging in reliably filtering out unwanted responses such as spurs, odd harmonics, higher frequency spectral noise, and line-related noise. Sweep-to-sweep averaging, however, is better at ltering out very low frequency noise. ^A tenfold reduction in IF bandwidth (from 200 Hz to 20 Hz, for example) lowers the measurement noise floor by about

Another difference between sweep-to-sweep averaging and variable IF bandwidth is the sweep time. Averaging displays the first complete trace faster but takes several sweeps to reach a fully averaged trace. IF bandwidth reduction lowers the noise floor in one sweep, but the sweep time may be slower.

Group Delay

For many networks, the linearity of the phase shift over a range of frequencies is an important parameter.

Group delay is the measurement of signal transmission time through a test device. It is defined as the derivative of the phase characteristic with respect to frequency. Because the derivative is the instantaneous slope (or rate of change of phase with frequency), a perfectly linear phase shift results in ^a constant slope, and therefore ^a constant group delay (Figure A-8).

Figure A-8. Constant Group Delay

Note, however, that the phase characteristic typically consists of both linear (first order) and higher order (deviations from linear) components. The linear component can be attributed to the electrical length of the test device and represents the average signal transit time. The higher order components are interpreted as variations in transit time for different frequencies, and represent ^a source of signal distortion (Figure A-9).

Figure A-9. Higher Order Phase Shift

The 4395A computes group delay from the phase slope. Phase data is used to find the phase deviation, $\Delta\varphi$, at the center point of a specified frequency aperture, Δf , to obtain an approximation for the rate of change of phase with frequency (Figure A-10). This value, g, represents the group delay in seconds assuming linear phase change over Δf .

Figure A-10. Rate of Phase Change Versus Frequency

When deviations from linear phase are present, changing the frequency step can result in different values for group delay. Note that in this case the computed slope varies as the aperture Δf is increased (Figure A-11). A wider aperture results in loss of the fine grain variations in group delay. This loss of detail is the reason that in any comparison of group delay data it is important to know the aperture used to make the measurement.

Figure A-11. Variations in Frequency Aperture

In determining the group delay aperture, there is a tradeoff between resolution of fine detail and the effects of noise. Noise can be reduced by increasing the aperture, but this will tend to smooth out the fine detail. More detail will become visible as the aperture is decreased, but the noise will also increase, possibly to the point of obscuring the detail. A good practice is to use a smaller aperture to assure that small variations are not missed, then increase the aperture to smooth the trace.

Spectrum Measurement Basics

Detection Modes

The analyzer displays the value measured at the display point specified by NOP. However, analyzer sweeps with the resolution specified by RBW. Detection chooses one level measured between display points for displaying the trace. One of three detection modes can be selected:

- **Positive Peak Mode**
- Negative Peak Modes
- Sample Mode

These modes are as described in the following subsections.

Positive and Negative Peak Modes

Positive and negative peak modes store signal maximums and minimums between the display points, respectively, in ^a data array.

Sample Mode

In the sample mode, the signal value at the display point is placed in a data array. Sample mode is used to measure noise level.

Swept Spectrum Analyzers versus FFT Analyzers

Usually, two analyzers are used to analyze waveforms transformed from the time domain test signal to the frequency domain; one is ^a swept spectrum analyzer and the other is an FFT analyzer.

When measuring signals over ^a wide frequency span with ^a wide RBW, swept spectrum analyzers are better than FFT analyzers. This is true because the FFT analyzer requires ^a large memory and a fast AD converter to measure the signal and therefore, is not practical. When measuring signals with narrow RBW, FFT analyzers are better than swept spectrum analyzers because the swept spectrum analyzer requires much more time to measure (sweep) the signal. The FFT analyzer can measure the signal in very short time.

In spectrum analyzer mode, the 4395A operates as ^a step FFT analyzer which supports high-speed sweep throughout the entire RBW.

Figure A-12. Swept Spectrum Analyzers versus Step FFT Analyzers

Selectivity of the RBW

The selectivity of the RBW is the ratio of the 60 dB bandwidth to 3 dB bandwidth (RBW) of the filter. The selectivity defines the shape of the filter. This factor is important when resolving small signal that is adjacent to a large signal. The small adjacent signal is hidden by the large signal even when the resolution bandwidth is set to smaller than the difference of frequency between the signals. To resolve small adjacent signals, the resolution bandwidth must be set so that the small signal is not hidden by the large signals as shown in Figure A-13.

Figure A-13. Resolving Small Adjacent Signal

Because the 4395A uses a digital filter technique, the selectivity of the analyzer is better (smaller) than a conventional spectrum analyzer (which uses analog filter technique). This means the 4395A can detect ^a small signal that could not be detected by ^a conventional spectrum analyzer.

Spectrum Measurement Basics

Noise measurement Noise measurement

Noise Format and Marker Noise Form

When a spectrum analyzer measures noise, the power shown by an analyzer is in proportion to RBW (because spectrum analyzers measure total power coming thorough RBW). For noise measurement, the measurement value is usually normalized by an equivalent noise bandwidth of an RBW filter (frequency). The noise format automatically normalizes noise power by the equivalent noise bandwidth and displays the trace on the screen. The marker noise form also reads out the noise level normalized, even if the format is the spectrum.

Sample Detection Mode for Noise Measurement

For noise measurement, the sample detection mode is best. Because the power of noise is uniformly distributed over frequency, it is not necessary to measure all the frequencies between the display points. It is sufficient to measure only the display points. This is why the sample detection mode is used for noise measurement.

VRW for Noise Measurement

You should specify ^a smaller VBW when using the 4395A to measure noise levels.

To obtain accurate noise level measurements, it is essential to determine the average value over ^a relatively long period. With ^a smaller VBW, the 4395A can determine the average time domain at each measurement point.

Impedance Measurement Basics

I-V Measurement Method

Basic Concept of I-V Method

Figure A-14. I-V Measurement Method

The unknown impedance, Z, can be calculated from the measured voltage and current using Ohm's law: (See circuit A in Figure A-14.)

$$
Z = \frac{V}{I}
$$

The current, I, can be also obtained by the voltage level of the known resistance, R_0 .

$$
Z = \frac{V_1}{I} = \frac{V_1}{V_2}R_0
$$

See circuit ^B in Figure A-14.

The 4395A uses circuit ^B to determine the unknown impedance.

How This Is Different From Impedance Conversion in the Network Analyzer Mode

The network analyzer part of the 4395A has an impedance conversion feature that converts the reflection coefficient to impedance. The reflection is determined by the impedance of the DUT.

$$
Z = R_0 \frac{1 - \Gamma}{1 + \Gamma} \qquad (-1 \le \Gamma \le 1)
$$

If the DUT impedance is equal to the characteristic impedance, there is no reflection. When the impedance is an infinite value like OPEN, the all input signal is reflected.

When the impedance is greater than characteristic impedance, the measurement error is increased. For example, for an importance of 2 km w I percent city. In the repeater coempletic is converted to a 24 percent error in impedance.

I-V Measurement Method

However, with the I-V method, the measurement error does not depend on the impedance of the DUT because the I-V method measures the impedance directly from the ratio of the voltage and current. Using the I-V method, you can measure ^a wide range impedance with constant accuracy. This is the major advantage of the I-V method.

The 4395A, when combined with the 43961A, uses ^a RF I-V measurement method to measure the impedance of ^a DUT at higher frequencies. While the RF I-V measurement method is based on the same principal as the I-V measurement method, it is possible to operate at higher frequencies by using an impedance matched measurement circuit (50) and ^a precision coaxial test port.
Impedance Measurement Scheme

Measurement Block Diagram

With the 43961A connected, the measurement circuit is as shown in Figure A-15.

Figure A-15. Impedance Test Kit Block Diagram

The source signal is output from RF OUT port. V_V voltmeter is R port receiver that measures a voltage. V_I voltmeter is A port receiver that measures a voltage of R_0 to obtain a current.

Test Signal Level at DUT

The test signal level actually applied to the DUT depends on the test signal level from the 4395A, the output impedance, the insertion loss of the Impedance Test Kit, and the impedance of the DUT.

Figure A-16 shows the simplied equivalent circuit of the 4395A and 43961A.

Figure A-16. Test Signal Level

Impedance Measurement Scheme

The output signal is divided by the input impedance (R_0) and the impedance of the DUT. You can use the following equation to determine the signal level actually applied to the DUT:

$$
V_{DUT} = V_{SET} \times \frac{Z_{DUT}}{(Z_{DUT} + R_0)} [V]
$$

Where,

 V_{DUT} Voltage level that is actually applied to the DUT.

 V_{SET} Voltage level that is set. See below.

Z_{DUT} Impedance of the DUT.

R0 Input impedance, ⁵⁰ .

The 1395A defined the output level as the literature of the RF OUT points is 50 in the level interfered. Therefore, you can calculate the voltage from dBm,

$$
V_{SET} = \sqrt{10^{\frac{P_{SET}}{10}} \times 0.001 \times R_0}
$$

Where,

P_{SET} Output power setting level. [dBm]

Measurement Points and Display Points

In ^a network measurement, the analyzer measures at only the display points specied by NOP. In ^a spectrum measurement, the analyzer measures all the frequencies between the display points (except for sampling detection mode). This is done so that the analyzer can detect spectrums existing between the display points

Figure A-17. Measurement Points and Display Points

Channel Coupling

When the 4395A is operating in network analyzer mode, you can couple the two channels so that the sweep parameters are linked across the two channels. But, when one channel measures ^a ratio measurement and the other one measures an absolute measurement (for example A/R and B), sweep parameters can not be linked.

In channel coupling mode, the following parameters are linked:

- Frequency
- Number of points
- Source power level
- Number of groups
- **IF** bandwidth
- Sweep time
- Trigger type
- Sweep type

In addition, if both channels have the same input parameter (such as S_{11} or A/R), the following parameters are linked:

- Calibration type
-

The following parameters always have the same value between the two channels, whether or not the channels are coupled:

- Trigger source
- List sweep table
- Calibration kit type and data

The following parameters are always set for each channel independently, whether or not the channels are coupled:

- Measurement parameter
- Display Format
- Title
- Traces displayed
- Scale value
- Electrical delay
- \blacksquare Phase offset
- \blacksquare Averaging (on/off, factor)

Linking of sweep parameter values for the two channels is independent of the

DUAL CHAN on OFF softkey under the Display key and of the MKR [UNCOUPLED] / [COUPLED] coupled to the coupled to t

softwee under the Market and Market the Market and Market and Market and Market and Market and Market and Marke COUPLED COUPLED COUPLED AND COUPLED COUPLED AND COUPLED AND LODGED AT ALLEY AN ALTERNATIVE AND ALTERNATIVE COUPLED AND A RESERVE AND A RESERVE AND A RESERVE AND A RESERVE AND LODGED AND A RESERVE AND A RESERVE AND A RESERV dual channel display is on. In this mode, the 4395A alternates between the two sets of sweep parameter values for measurement of data and both are displayed.

Limit Line Concept

These are lines drawn on the display to represent upper and lower limits or device specifications with which to compare the DUT. Limits are defined by specifying several segments, where each segment is a portion of the sweep parameter span. Each limit segment has an upper and a lower starting limit value.

Limits can be defined independently for the two channels with up to 18 segments for each channel (a total of 36 for both channels). These can be in any combination of the two limit types.

Limit testing compares the measured data with the defined limits, and provides pass or fail information for each measured data point. An out-of-limit test condition is indicated in the following ways:

- Displaying a FAIL message on the screen
- **E**mitting a beep
- Displaying an asterisk in tabular listings of data
- Writing ^a bit into GPIB event status register ^B (for more information on GPIB event status registers, refer to 4395A Programming Guide)

Limits are entered in tabular form. Limit lines and limit testing can be either on or off while limits are defined. As new limits are entered, the tabular columns on the display are updated, and the limit lines (if on) are modified to the new definitions. The complete limit set can be offset in either sweep parameter or amplitude value.

How Limit Lines are Entered

Before limit lines can be explained, the concept of "segments" must be understood. A segment is the node of two limit lines.

Figure A-18. The Concept of Segments as a Point between Two Sets of Limit Lines

Limit Line Concept

As you can see in Figure A-18, segments are distinct points that define where limit lines begin or end. Limit lines span the distance between segments and represent the upper and lower test limits. Figure A-18 shows another important aspect of limit lines. The far left hand side of a set of limit lines will continue from the minimum sweep parameter value (START) and the far right hand side of a set of limit lines will continue until the maximum sweep parameter value (stop).

^A segment is placed at ^a specic sweep parameter value (a single frequency for example). The first segment defines the limit line value from the minimum sweep parameter value. Once its sweep parameter value is entered, the upper and lower test limit $(+5 \text{ dB and } -5 \text{ dB for})$ example) need to be supplied.

Defining a second segment defines where the first set of limit lines ends. This process is repeated to create different sets of limit lines, each having new upper and lower limits. Up to ¹⁸ segments can be entered.

Limits can be defined independently for the two channels.

The example in Figure A-18 shows ^a combination of limit lines that change instantly and gradually.

Segment 1 is at 2 MHz and has an upper and lower limit of $+5$ and -5 dB, respectively. Notice the upper and lower limit lines start at the start frequency (1 MHz) and end at segment 1.

Segment 2 is also at 2 MHz with different upper and lower limits of $+10$ dB and -10 dB, changing the limit values instantly.

Segment 3 is at 3 MHz with the same limit value as segment 2 to obtain a flat limit lines.

Segment 4 is at 4 MHz with upper and lower limit values of $+15$ dB and -15 dB, changing the limit values gradually. Notice the upper and lower limit lines start at the segment and continue until the stop frequency (5 MHz).

Note Limit lines cannot be cut. Therefore, when limit lines are needed partially along the sweep parameter axis, the non-limit-testing portion must also be entered. Set the non-limit-testing portion by forcing the upper and lower limit values out of range $(+500$ dB and -500 dB for example).

> Both an upper limit and a lower limit (or delta limits) must be defined. If only one limit is required for a particular measurement, force the other limit out of range $(+500$ dB or -500 dB for example).

Turning ON/OFF Limit Line/Limit Test

Limit lines and limit testing features are off unless explicitly turned on by the user. After entering the limit line information, you can turn on the limit line feature and optionally the limit testing features. Turning these features of F has no effect on the entered limit line information.

Segments Entering Order Needs Notice

Generally, the segments do not have to be entered in any particular order. The analyzer automatically sorts them and lists them on the display in increasing order of sweep parameter value.

One exception is when two segments have the same sweep parameter value as described in Figure A-18. If the same sweep parameter values exist, the analyzer draws the limit lines according to entered segment order. For example, in Figure A-18, segment 1 should be entered in advance of segment 2.

Saving the Limit Line Table

Limit line information is lost if the LINE switch is turned off. However, the $\sqrt{\frac{S_{\text{av}}}{S_{\text{av}}}$ and $\sqrt{\frac{R_{\text{ccall}}}{S_{\text{av}}}}$ keys can save limit line information along with all other current analyzer settings. Limit line table information can be saved on a disk.

Offsetting the Sweep Parameter or Amplitude of the Limit Lines

All limit line entries can be offset in either sweep parameter or amplitude values. The offset affects all segments simultaneously.

Supported Display Formats

Limit lines are displayed only in Cartesian format. In polar and Smith chart formats, limit testing of one value is available. The value tested depends on the marker mode and is the magnitude or the first value in a complex pair. The message "NO LIMIT LINES DISPLAYED" is shown on the display in polar and Smith formats.

Use a Sufficient Number of Points or Errors May Occur

Limits are checked only at the actual measured data points. If you do not select a sufficient number of points, it is possible for ^a device to be out of specication without a limit test failure indication.

To avoid this, be sure to specify ^a high enough number of points. In addition, if specic sweep parameter points must be checked, use the list sweep features described in "Reducing Sweep Time (Using List Sweep)" in Chapter ⁹ so that the actual measured data points are checked.

Displaying, Printing, or Plotting Limit Test Data

The "list values" feature in the copy menu prints or displays a table of each measured sweep parameter value. The table includes limit line and limit test information (if these functions are turned on). If limit testing is on, an asterisk \" is listed next to any measured value that is out of limits.

If the limit lines are on, and other listed data allows sufficient space, the following information is also displayed:

- Upper limit and lower limit
- The margin by which the device passes or fails the nearest limit

Results of Plotting or Printing the Display with Limit Lines ON

If limit lines are on, they are shown when you print or plot the display. If limit testing is on, the PASS or FAIL message is included as well.

Markers

Three Types of Markers

Three types of markers are provided for each channel. The first is the movable marker that is displayed on the screen (as ∇) when (Marker), (Maker \rightarrow), (Search), or (Utility) is pressed. When a marker is turned on and no other function is active, the marker can be controlled with the knob, or the step keys.

The second is the sub-markers that appear at the present marker position when ^a softkey in the sub-marker menu is pressed. The seven sub-markers can be displayed for each channel at same time (a total of 14).

The third is the Δ marker that defines a reference position of the delta mode. This type of marker includes three variations: Δ marker(normal), tracking Δ marker, and fixed Δ marker.

Marker Value

Markers have a sweep parameter value (the x-axis value in ^a Cartesian format) and ^a measurement value (the y-axis value in ^a Cartesian format). In ^a polar, Smith, or admittance chart format, the second part of ^a complex data pair is also provided as an auxiliary measurement value.

The marker can be moved to any point on the trace, Its measurement and sweep parameter values are displayed at the top right corner of the graticule for each displayed channel (in units appropriate to the display format). The displayed marker measurement values are valid even when the measured data is above or below the range displayed on the graticule. When marker list is turned on, sweep parameter values and measurement values of all markers are listed on the graticule. In ^a polar, Smith , or admittance chart format, auxiliary measurement values of all markers are also listed

Marker Time Mode

When marker time mode is turned on, the x-axis is changed to the time scale. The start point of the x-axis is θ seconds and the stop point indicates the sweep time. The markers have a time instead of ^a sweep parameter value.

Continuous/Discrete Mode

Marker values of the network analyzer are normally continuous (that is, they are interpolated between measured points). Alternatively, they can be set to read only discrete measured points. The marker of the spectrum analyzer always reads only the discrete measured point.

Marker on the Data Trace or on the Memory Trace

If both data and memory are displayed, you can select which marker values apply to the data trace or the memory trace. If data or memory is displayed (not both), the marker values apply to the trace displayed. In a data math display $(data + memory$, data-memory, or data/memory), the marker values apply to the trace resulting from the memory math function.

$\Delta \textbf{Mode}$ ————————————————————

With the use of ^a delta marker, ^a delta marker mode is available that displays both the sweep parameter and measurement values of the marker relative to the reference. Any position on the trace or a fixed point can be designated as the delta marker. The Δ marker can be put on a current position of the marker. If the delta reference is the fixed Δ marker, both its sweep parameter value and its magnitude value (y-axis value) can be set arbitrarily anywhere in the display area (not necessarily on the trace). If the delta marker is the tracking Δ marker, its sweep parameter value can be controlled and its measurement value is the value of the trace at that sweep parameter value.

Marker Search Function

Markers can search for the trace maximum/minimum, mean point, any other point, peak maximum/minimum or peak-to-peak value of all or part of the trace. The marker and sub-markers can be used together to search for specified bandwidth cutoff points and calculate the bandwidth. Statistical analysis uses markers to provide ^a readout of the mean, standard deviation, and peak-to-peak values of all or part of the trace.

Width Function

The bandwidth search feature analyzes ^a bandpass or band reject trace and calculates the center point, bandwidth, and ^Q (quality factor) for the specied bandwidth. These parameters depend on the Δ marker mode. The following table shows how each parameter is determined for each Δ marker mode.

Parameter	Tracking Δ marker	Fixed Δ marker					
BW	Displays the bandwidth value set by WIDTH VALUE.						
center	Displays the center sweep parameter value between the cutoff points (this is marked by sub-marker 1).						
Q	Displays the Q value $(=$ cent/BW) of the trace.						
Insertion Loss	Displays the absolute value of the marker.	Displays the difference between the marker and the fixed Δ marker.					
ΔF (Left)	Displays the sweep parameter value difference between marker 2 and the center frequency specified by the [Center] key.	Displays the sweep parameter value difference between marker 2 and the fixed Amarker.					
ΔF (Right)	Displays the sweep parameter value difference between marker 3 and center frequency specified by the $[Center]$ key.	Displays the sweep parameter value difference between marker 3 and the fixed Amarker.					

Table A-1. Obtaining Parameters in Δ Marker Mode

Figure A-19 shows an example of the bandwidth search feature.

Figure A-19. Bandwidth Search Example

Peak Definition Peak Denition

The search function provides the define peak feature, which specifies the properties of the peaks searched for by the peak search function. The dene peak feature also allows the peak search function to discriminate peaks from noise.

The peak definitions are different for the network analyzer mode and the spectrum analyzer mode

Peak Definition for Network Analyzer Mode

The following parameters are used in the peak definition for the network measurement:

- **Peak polarity (positive or negative)**
- \blacksquare ΔX , ΔY (gradient)
- Threshold value

The search functions search for a peak where the parameters of the peak match the following conditions:

The search functions search for ^a peak where the parameters of the peak match the following conditions:

 $\frac{\frac{X}{\Delta X}$ \times 5 PAN \times min(Δ y_L, Δ y_R)

and

 $Threshold < Peak$ Amplitude Value

 Δy_L , Δy_R are the difference in amplitude value between a peak and the adjacent measurement points on both sides.

That is, the search functions search for a peak where, the gradient is greater than $\Delta Y/\Delta X$, and the amplitude is greater than the threshold value. The search functions ignore a peak when the amplitude value is less than the threshold even if the peak polarity is set to negative.

Figure A-20. Peak Definition for Network Analyzer Mode

Peak Definition for Spectrum Analyzer Mode

The following parameters are used in the peak definition for the spectrum measurement:

- \Box Δ Y (difference of amplitude between a peak and an adjacent local minimum point)
- **Threshold value**

The search functions search for ^a peak where the parameters of the peak match the following conditions:

 $\Delta Y \leq min(max(\Delta y_L, \Delta y_R), \Delta y_{TH})$

where:

 Δy_L , Δy_R are the difference in amplitude value between a peak and the adjacent local minimum point.

 Δ y_{TH} is the difference between a peak and the threshold value.

That is, the search functions search for a peak where the difference of amplitude between the peak and the smaller of the adjacent local minimum points is greater than ΔY , and the difference between the peak and the threshold is greater than ΔY .

The peak polarity is always positive for the spectrum analyzer peak search functions.

Figure A-21. Peak Definition for Spectrum Analyzer Mode

GPIB

The analyzer is factory-equipped with a remote programming digital interface using the General Purpose Interface Bus (GPIB). This allows the analyzer to be controlled by an external computer that sends commands or instructions to and receives data from the analyzer using the GPIB. In this way, a remote operator has the same control of the instrument available to ^a local operator from the front panel, except for the line power switch.

In addition, the analyzer itself can use GPIB to directly control compatible peripherals, without the use of an external controller. It can output measurement results directly to ^a compatible printer or plotter.

This section provides an overview of GPIB operation. More complete information on programming the analyzer remotely over GPIB is provided in Programming Manual. The *Programming Manual* includes examples of remote measurements using an HP 9000 series 200 or 300 computer with BASIC programming. The *Programming Manual* assumes familiarity with front panel operation of the instrument.

^A complete general description of the GPIB is available in Tutorial Description of the General Purpose Interface Bus, Agilent publication 5952-0156. For more information on the IEEE 488.1 standard, see IEEE Standard Digital Interface for Programmable Instrumentation, published by the Institute of Electrical and Electronics Engineers, Inc., ³⁴⁵ East 47th Street, New York 10017, USA.

How GPIB Works

The GPIB uses ^a party-line bus structure in which up to ¹⁵ devices can be connected on one contiguous bus. The interface consists of ¹⁶ signal lines and ⁶ grounded lines in ^a shielded cable. With this cabling system, many different types of devices including instruments, computers, plotters and printers can be connected in parallel.

Every GPIB device must be capable of performing one or more of the following interface functions:

Talker

^A talker is ^a device capable of sending device-dependent data when addressed to talk. There can be only one active talker at any given time. Examples of this type of device are voltmeters, counters, and tape readers. The analyzer is ^a talker when it sends trace data or marker information over the bus.

Listener

^A listener is a device capable of receiving device-dependent data when addressed to listen. There can be any number of active listeners at any given time. Examples of this type of device are printers, power supplies, and signal generators. The analyzer is a listener when it is controlled over the bus by a computer.

A controller is a device capable of managing the operation of the bus and addressing talkers and listeners. There can be only one active controller at any time. Examples of controllers include desktop computers and minicomputers. In a multiple-controller system, active control can be passed between controllers, but there can only be one system controller that acts as the master, and can regain active control at any time. The analyzer is an active controller when it plots or prints in the addressable mode. The analyzer is a system controller when it is in the system controller mode.

GPIB Requirements

GPIB Capabilities of the 4395A

As defined by the IEEE 488.1 standard, the analyzer has the following capabilities:

GPIB

Bus Mode Bus Mode

The analyzer uses ^a single-bus architecture. The single bus allows both the analyzer and the host controller to have complete access to the peripherals in the system.

Figure A-22. Analyzer Single Bus Concept

Two different modes are possible, system controller and addressable.

- System Controller This mode allows the analyzer to control peripherals directly in ^a stand-alone environment (without an external controller). This mode can only be selected manually from the analyzer front panel. Use this mode for operation when no computer is connected to the analyzer. Printing and plotting use this mode.
- Addressable This is the traditional programming mode, in which the computer is involved in all peripheral access operations. When the external controller is connected to the analyzer through GPIB (as shown in Figure A-22), this mode allows you to control the analyzer over GPIB in the talker mode in order to send data, and in the listener mode to receive commands. It also allows the analyzer to take or pass control in order to plot and print.

Setting Addresses

In GPIB communications, each instrument on the bus is identied by an GPIB address. This address code must be unique to each instrument on the bus. These addresses are not affected when you press (Preset) or cycle the power. For more information on how to set the address, refer to the description of the $\overline{[Local]}$ key in Appendix B "Softkey Reference".

Calibration for Network Measurement

Introduction

Network measurement calibration is an accuracy enhancement procedure that effectively reduces the system errors that cause uncertainty in measuring a DUT. It measures known standard devices, and uses the results of these measurements to characterize the system.

This section explains the theoretical fundamentals of accuracy enhancement and the sources of measurement errors. It describes the different measurement calibration procedures available in the analyzer, which errors they correct, and the measurements for which each should be used. The later part of this section provides further information on characterizing systematic errors and using error models to analyze the overall measurement performance.

Accuracy Enhancement

If it were possible for a perfect measurement system to exist, it would have infinite dynamic range, isolation, and directivity characteristics, no impedance mismatches in any part of the test setup, and flat frequency response. Vector accuracy enhancement, also known as measurement calibration or error correction, provides the means to simulate ^a perfect measurement system.

In any high frequency measurement, there are measurement errors associated with the system that contribute uncertainty to the results. Parts of the measurement setup such as interconnecting cables and signal separation devices (as well as the analyzer itself) all introduce variations in magnitude and phase that can mask the actual performance of the DUT.

For example, crosstalk due to the channel isolation characteristics of the analyzer can contribute an error equal to the transmission signal of a high-loss test device. For reflection measurements, the primary limitation of dynamic range is the directivity of the test setup.

The measurement system cannot distinguish the true value of the signal reflected by the DUT from the signal arriving at the receiver input due to leakage in the system. For both transmission and reflection measurements, impedance mismatches within the test setup cause measurement uncertainties that appear as ripples superimposed on the measured data.

Measurement calibration simulates a perfect analyzer system. It measures the magnitude and phase responses of known standard devices, and compares the measurement with actual device data. It uses the results to characterize the system and effectively remove the system errors from the measurement data of a test device, using vector math capabilities internal to the analyzer.

When measurement calibration is used, the dynamic range and accuracy of the measurement are limited only by system noise and stability, connector repeatability, and the accuracy to which the characteristics of the calibration standards are known.

Sources of Measurement Errors

Network analysis measurement errors can be separated into systematic, random, and drift errors.

Correctable systematic errors are the repeatable errors that the system can measure. These are errors due to mismatch and leakage in the test setup, isolation between the reference and test signal paths, and system frequency response.

The system cannot measure and correct for the non-repeatable random and drift errors. These errors affect both reflection and transmission measurements. Random errors are measurement variations due to noise and connector repeatability. Drift errors include frequency drift,

temperature drift, and other physical changes in the test setup between calibration and measurement.

The resulting measurement is the vector sum of the DUT response plus all error terms. The precise effect of each error term depends upon its magnitude and phase relationship to the actual test device response.

In most high frequency measurements the systematic errors are the most signicant source of measurement uncertainty. Because each of these errors can be characterized, their effects can be effectively removed to obtain a corrected value for the test device response. For the purpose of vector accuracy enhancement these uncertainties are quantied as directivity, source match, load match, isolation (crosstalk), and frequency response (tracking). Each of these systematic errors is described below.

Random and drift errors cannot be precisely quantified, so they must be treated as producing a cumulative uncertainty in the measured data.

Directivity

Normally ^a device that can separate the reverse from the forward traveling waves (a directional bridge or coupler) detects the signal reflected from the DUT. Ideally the coupler would completely separate the incident and reflected signals, and only the reflected signal would appear at the coupled output (Figure A-23-a).

Figure A-23. Directivity

However, an actual coupler is not perfect (Figure A-23-b). A small amount of the incident signal appears at the coupled output due to leakage as well as to reflection from the termination in the coupled arm. Also, reflections from the main coupler output connector appear at the coupled output, adding uncertainty to the signal reflected from the device. The figure of merit for how well a coupler separates forward and reverse waves is directivity. The greater the directivity of the device, the better the signal separation. Directivity is the vector sum of all leakage signals appearing at the analyzer receiver input due to the inability of the signal separation device to separate incident and reflected waves, and to residual reflection effects of test cables and adapters between the signal separation device and the measurement

plane. The error contributed by directivity is independent of the characteristics of the test device and it usually produces the major ambiguity in measurements of low reflection devices.

Source Match

Source match is defined as the vector sum of signals appearing at the analyzer receiver input due to the impedance mismatch at the test device looking back into the source. Source match is degraded by adapters and extra cables. A non-perfect source match leads to mismatch uncertainties that affect both transmission and reflection measurements. Source match is most often given in terms of return loss in dB (therefore, the larger the number, the smaller the error.

- In a reflection measurement, the source match error signal is caused by some of the reflected signal from the DUT being reflected from the source back toward the DUT and re-reflected from the DUT (Figure A-24).
- In a transmission measurement, the source match error signal is caused by reflection from the test device that is re-reflected from the source.

Figure A-24. Source Match

The error contributed by source match is a mismatch error caused by the relationship between the actual input impedance of the test device and the equivalent match of the source. It is a factor in both transmission and reflection measurements. Mismatch uncertainty is particularly a problem in measurements where there is a large impedance mismatch at the measurement plane.

Load Match Load Match

Load match error results from an imperfect match at the output of the test device. It is caused by impedance mismatches between the test device output port and port 2 of the measurement system. As illustrated in Figure A-25, some of the transmitted signal is reflected from port 2 back to the test device. A portion of this wave can be re-reflected to port 2, or part can be transmitted through the device in the reverse direction to appear at port 1. If the DUT has low insertion loss (for example a transmission line), the signal reflected from port 2 and re-reflected from the source causes a significant error because the DUT does not attenuate the signal significantly on each reflection. Load match is usually given in terms of return loss in dB (therefore, the larger the number, the smaller the error).

Figure A-25. Load Match

The error contributed by load match depends on the relationship between the actual output impedance of the test device and the effective match of the return port (port 2). It is a factor in all transmission measurements and in reflection measurements of two-port devices. Load match and source match are usually ignored when the test device insertion loss is greater than about 6 dB. This happens because the error signal is greatly attenuated each time it passes through the DUT. However, load match effects produce major transmission measurement errors for a test device with a highly reflective output port.

Isolation (Crosstalk)

Leakage of energy between analyzer signal paths contributes to error in a transmission measurement much as directivity does in a reflection measurement. Isolation is the vector sum of signals appearing at the analyzer receivers due to crosstalk between the reference and test signal paths, including signal leakage within the test set and in both the RF and IF sections of the receiver.

The error contributed by isolation depends on the characteristics of the DUT. Isolation is a factor in high-loss transmission measurements. However, analyzer system isolation is more than sufficient for most measurements, and correction for it may be unnecessary. For measuring devices with high dynamic range, accuracy enhancement can provide improvements in isolation that are limited only by the noise floor.

Frequency Response (Tracking)

This is the vector sum of all test setup variations in which magnitude and phase change as a function of frequency. This includes variations contributed by signal separation devices, test cables, and adapters, and variations between the reference and test signal paths. This error is ^a factor in both transmission and reflection measurements.

For further explanation of systematic error terms and the way they are combined and represented graphically in error models, see the later section, titled Accuracy Enhancement Fundamentals - Characterizing Systematic Errors.

Compensation for Measurement Errors

There are twelve different error terms for a two-port measurement that can be corrected by accuracy enhancement in the analyzer. These are directivity, source match, load match, isolation, reflection tracking, and transmission tracking, each in both the forward and reverse direction. The analyzer has several different measurement calibration routines to characterize one or more of the systematic error terms and remove their effects from the measured data. The procedures range from ^a simple frequency response calibration to ^a full two-port calibration that effectively removes all twelve error terms.

The Response Calibration effectively reduces the frequency response errors of the test setup for reflection or transmission measurements. This calibration procedure may be adequate for measurement of well-matched low-loss devices. This is the simplest error correction to perform, and should be used when extreme measurement accuracy is not required.

The Response and Isolation Calibration effectively removes frequency response and crosstalk errors in transmission measurements, or frequency response and directivity errors in reflection measurements. This procedure may be adequate for measurement of well-matched high-loss devices.

The S_{11} and S_{22} One-Port Calibration procedures provide directivity, source match, and frequency response vector error correction for reflection measurements. These procedures provide high accuracy reflection measurements of one-port devices or properly terminated two-port devices.

The **Full Two-Port Calibration** provides directivity, source match, load match, isolation, and frequency response vector error correction, in both forward and reverse directions, for transmission and reflection measurements of two-port devices. This calibration provides the best magnitude and phase measurement accuracy for both transmission and reflection measurements of two-port devices, and requires an S-parameter test set.

The **One-Path Two-Port Calibration** provides directivity, source match, load match, isolation, and frequency response vector error correction in one direction. It is used for high accuracy transmission and reflection measurements using a transmission/reflection test kit, such as the 87512A, B. (The DUT must be manually reversed between sweeps to accomplish measurements in both the forward and reverse directions.)

All the calibration procedures described above are accessed from the \overline{CA} key.

Modifying Calibration Kits

For most applications, use the default cal kit models. Modifying calibration kits is necessary only if unusual standards are used or the very highest accuracy is required. Unless a cal kit model is provided with the calibration devices used, a solid understanding of error correction and the system error model are essential to making modifications. Read all of this section.

During measurement calibration, the analyzer measures actual, well-defined standards and mathematically compares the results with ideal "models" of those standards. The differences are separated into error terms which are later reduced during error correction. Most of the differences are due to systematic errors - repeatable errors introduced by the analyzer, test set, and cables - which are correctable. However, the difference between the standard's mathematical *model* and its *actual performance* has an adverse affect; it reduces the system's ability to remove systematic errors, and thus degrades error-corrected accuracy. Therefore, in addition to the default cal kit models, a "user kit" is provided that can be modified to an alternate calibration standards model.

Several situations exist that may require a user-defined cal kit:

- You use a connector interface different from the four built-in cal kits. (Examples: SMA, or BNC.)
- \blacksquare You are using standards (or combinations of standards) that are different from the predefined cal kits. (For example, using three offset SHORTs instead of an OPEN, SHORT, and LOAD to perform ^a 1-port calibration.)
- You want to improve the built-in standard models for predened kits. Remember that the more closely the model describes the actual performance of the standard, the better the α instead is α . The α mm Lorentz is determined to be 50.4 m motors of 50.0 mm
- Unused standards for ^a given cal type can be eliminated from the default set, to eliminate possible confusion during calibration. (Example: ^A certain application requires calibrating ^a male test port. The standards used to calibrate a female test port can be eliminated from the set, and will not be displayed during calibration.)

Glossary

This section provides ^a glossary of terms related to calibration.

- A standard is a specific, well-defined, physical device used to determine systematic errors.
- A standard type is one of five basic types that define the form or structure of the model to be used with that standard (for example, ^a SHORT or ^a LOAD).
- Standard coefficients are numerical characteristics of the standards used in the model selected. selected.
- A standard class is a grouping of one or more standards that determines which standards are used in a particular calibration procedure.

Defining the Standards

Standard definition is the process of mathematically modeling the electrical characteristics (delay, attenuation, and impedance) of each calibration standard. These electrical characteristics (coefficients) can be mathematically derived from the physical dimensions and material of each calibration standard, or from its actual measured response. The parameters of the standards can be listed in Standards Definitions, Table A-2.

Calibration for Network Measurement

Table A-2. Standard Definitions

Each standard must be identified as one of five "types": OPEN, SHORT, LOAD, DELAY/THRU, or arbitrary impedance.

Standard Types

OPEN

OPENs assigned a terminal impedance of infinite ohms, but delay and loss offsets may still be added. For information of the delay and loss offsets, see the "Offset and Delay" paragraph.

As a reflection standard, an OPEN offers the advantage of broadband frequency coverage. However, an OPEN rarely has perfect reflection characteristics because fringing (capacitance) effects cause phase shift that varies with frequency. This can be observed in measuring an OPEN termination after calibration, when an arc in the lower right circumference of the Smith chart indicates capacitive reactance. These effects are impossible to eliminate, but the calibration kit models include the OPEN termination capacitance at all frequencies for compatible calibration kits. The capacitance model is ^a second order polynomial (squared term), as ^a function of frequency, where the polynomial coefficients are user-definable. The capacitance model equation is:

 $C = C_0 + C_1 \times F + C_2 \times F$

where F is the measurement frequency.

\blacksquare SHORT

, but delay and loss are assigned and loss in the contract of the company and loss of the contractive and loss added.

\blacksquare LOAD

LOADs are assigned a terminal impedance equal to the system characteristic impedance Z_0 , but delay and loss offsets may still be added. If the LOAD impedance is not Z_0 , use the arbitrary impedance standard definition.

DELAY/THRU

DELAY/THRUs are assigned a transmission line of specied length, for calibrating transmission measurements.

ARBITARY IMPEDANCE

ARBITRARY IMPEDANCEs are assigned a standard type (LOAD), but with an arbitrary impedance (different from system Z_0).

Offset and Delay

Offsets may be specified with any standard type. This means defining a uniform length of transmission line to exist between the standard being dened and the actual measurement plane. For reflection standards, the offset is assumed to be between the measurement plane and the standard (one-way only). For transmission standards, the offset is assumed to exist between the two reference planes (in effect, the offset is the THRU). Three characteristics of the offset can be defined: its delay (length), loss, and impedance.

- **Offset Delay** specifies the one-way electrical delay from the measurement (reference) plane to the standard, in seconds (s). (In a transmission standard, offset delay is the delay from plane to plane.) Delay can be calculated from the precise physical length of the offset, the permittivity constant of the medium, and the speed of light.
- **Offet Loss** specifies energy loss, due to skin effect, along a one-way length of coaxial cable offset. The value of loss is entered as ohms/nanosecond (or Giga ohms/second) at 1 GHz.
- **Offset Z₀** specifies the characteristic impedance of the coaxial cable offset. This is not the impedance of the standard itself.

Note Numerical data for most Agilent Technologies calibration kits is provided in the calibration kit manuals.

Specifying the Standard Class

Once ^a standard is specied, it must be assigned to ^a standard class. This is ^a group of from one to seven standards that is required to calibrate for ^a single error term. The standards within ^a single class are assigned to locations ^A through ^G as listed on the Standard Class Assignments Table (Table A-3). ^A class often consists of ^a single standard, but may be composed of more than one standard.

Class	A	B	C	D	Е	\mathbf{F}	G	Standard Class label
$\mathbf{S}_{11\,\mathrm{A}}$								
$\mathbf{S}_{11\,\mathrm{B}}$								
$\mathbf{S}_{11\,\mathrm{C}}$								
$\mathbf{S}_{22\mathrm{A}}$								
$\mathbf{S}_{22\mathrm{B}}$								
\mathbf{S}_{22C}								
Forward Transmission								
Reverse Transmission								
Forward Match								
Reverse Match								
Response								
Response & Isolation								

Table A-3. Standard Class Assignments Table

The number of standard classes required depends on the type of calibration being performed, and is identical to the number of error terms corrected. (Examples: ^A response cal requires only one class, and the standards for that class may include an OPEN, or SHORT, or THRU. ^A 1-port cal requires three classes. ^A full 2-port cal requires ¹⁰ classes, not including two for isolation.)

The number of standards that can be assigned to ^a given class may vary from none (class not used) to one (simplest class) to seven. When ^a certain class of standards is required during calibration, the analyzer will display the labels for all the standards in that class (except when the class consists of ^a single standard). This does not, however, mean that all standards in a class must be measured during calibration. Only ^a single standard per class is required. Note that it is often simpler to keep the number of standards per class to the bare minimum needed (often one) to avoid confusion during calibration.

Standards are assigned to ^a class simply by entering the standard's reference number (established while defining a standard) under a particular class.

Each class can be given a user-definable label.

Accuracy Enhancement Fundamentals-Characterizing Systematic Errors

One-Port Error Model

In a measurement of the reflection coefficient (magnitude and phase) of an unknown device, the measured data differs from the actual, no matter how carefully the measurement is made. Directivity, source match, and reflection signal path frequency response (tracking) are the major sources of error (Figure A-26).

Measuring reflection coefficient. The reflection coefficient is measured by first separating the incident signal (I) from the reflected signal (R) , then taking the ratio of the two values (Figure A-27). Ideally, (R) consists only of the signal reflected by the test device (S_{11A}) .

Figure A-27. Reflection Coefficient

Directivity Error. However, all of the incident signal does not always reach the unknown (see Figure A-28). Some of (I) may appear at the measurement system input due to leakage through the test set or other signal separation device. Also, some of (I) may be reflected by imperfect adapters between signal separation and the measurement plane. The vector sum of the leakage and miscellaneous reflections is directivity, E_{DF} . Understandably, the measurement is distorted when the directivity signal combines vectorally with the actual reflected signal from the unknown, S_{11A} .

Figure A-28. Effective Directivity E_{DF}

Source match error. Because the measurement system test port is never exactly the characteristic impedance (50 m st 10 m), some of the remedia signal is re-refered on the test port, or other impedance transitions further down the line, and back to the unknown, adding to the original incident signal (I). This effect causes the magnitude and phase of the incident signal to vary as a function of S_{11A} and frequency. Leveling the source to produce constant (I) reduces this error, but because the source cannot be exactly leveled at the test device input, leveling cannot eliminate all power variations. This re-reflection effect and the resultant incident power variation are caused by the source match error, E_{SF} (Figure A-29).

Figure A-29. Source Match E_{SF}

Frequency response error. Frequency response (tracking) error is caused by variations in magnitude and phase flatness versus frequency between the test and reference signal paths. These are due mainly to imperfectly matched receiver circuits and differences in length and loss between incident and test signal paths. The vector sum of these variations is the reflection signal path tracking error, E_{BF} (Figure A-30).

Figure A-30. Reflection Tracking E_{RF}

How calibration standards are used to quantify these error terms. It can be shown that these three errors are mathematically related to the actual data, S_{11A} , and measured data, S_{11M} , by the following equation:

$$
S_{11M} = E_{DF} + \frac{S_{11A}(E_{RF})}{1 - E_{SF}S_{11A}}
$$

If the value of these three " E " errors and the measured test device response were known for each frequency, the above equation could be solved for S_{11A} to obtain the actual test device response. Because each of these errors changes with frequency, their values must be known at each test frequency. These values are found by measuring the system at the measurement plane using three independent standards whose S_{11A} is known at all frequencies.

The first standard applied is a "perfect load" that makes $S_{11A} = 0$ and essentially measures directivity (Figure A-31). "Perfect load" implies a reflection-free termination at the measurement plane. All incident energy is absorbed. With $S_{11A} = 0$ the equation can be solved for E_{DF} , the directivity term. In practice, of course, the "perfect load" is difficult to achieve, although very good broadband LOADs are available in the 4296A compatible calibration kits.

Figure A-31. "Perfect Load" Termination

Because the measured value for directivity is the vector sum of the actual directivity plus the actual reflection coefficient of the "perfect load," any reflection from the termination represents an error. System effective directivity becomes the actual reflection coefficient of the "perfect load" (Figure A-32). In general, any termination having a return loss value greater than the uncorrected system directivity reduces reflection measurement uncertainty.

Figure A-32. Measured Effective Directivity

Next, ^a SHORT termination whose response is known to ^a very high degree establishes another condition (Figure A-33).

Figure A-33. Short Circuit Termination

The OPEN gives the third independent condition. In order to accurately model the phase variation with frequency due to radiation from the OPEN connector, a specially designed shielded OPEN is used for this step. (The OPEN capacitance is different with each connector type). Now the values for E_{DF} , directivity, E_{SF} , source match, and E_{RF} , reflection frequency response, are computed and stored (Figure A-34).

Figure A-34. Open Circuit Termination

Now the unknown is measured to obtain a value for the measured response, S_{11M} , at each frequency (Figure A-35).

Figure A-35. Measured S_{11}

This is the one-port error model equation solved for S_{11A} . Because the three errors and S_{11M} are now known for each test frequency, S_{11A} can be computed as follows:

$$
S_{11A} = \frac{S_{11M} - E_{DF}}{E_{SF}(S_{11M} - E_{DF}) + E_{RF}}
$$

For reflection measurements on two-port devices, the same technique can be applied, but the test device output port must be terminated in the system characteristic impedance. This termination should be at least as good (have as low a reflection coefficient) as the LOAD used to determine directivity. The additional reflection error caused by an improper termination at the test device output port is not incorporated into one-port error model.

Two-Port Error Model

The error model for measurement of the transmission coefficients (magnitude and phase) of ^a two-port device is derived in ^a similar manner. The major sources of error are frequency response (tracking), source match, load match, and isolation (Figure A-36). These errors are effectively removed using the full two-port error model

Figure A-36. Major Sources of Error

Measuring Transmission Coefficient. The transmission coefficient is measured by taking the ratio of the incident signal (I) and the transmitted signal (T) (Figure A-37). Ideally, (I) consists only of power delivered by the source, and (T) consists only of power emerging at the test device output. device output.

Load Match Error. As in the reflection model, source match can cause the incident signal to vary as a function of test device S_{11A} . Also, because the test setup transmission return port is never exactly the characteristic impedance, some of the transmitted signal is reflected from the test set port 2, and from other mismatches between the test device output and the receiver input, to return to the test device. A portion of this signal may be re-reflected at port 2, thus affecting S_{21M} , or part may be transmitted through the device in the reverse direction to appear at port 1, thus affecting S_{11M} . This error term, which causes the magnitude and phase of the transmitted signal to vary as a function of S_{22A} , is called load match, E_{LF} (Figure A-38).

Figure A-38. Load Match ELF

The measured value, S_{21M} , consists of signal components that vary as a function of the relationship between E_{SF} and S_{11A} as well as ELF and S_{22A} , so the input and output reflection coefficients of the test device must be measured and stored for use in the S_{21A} error correction computation. Thus, the test setup is calibrated as described above for the reflection to establish the directivity, E_{DF} , source match, E_{SF} , and reflection frequency response, E_{RF} , terms for the

Now, that a calibrated port is available for reflection measurements, the THRU is connected and load match, E_{LF} , is determined by measuring the reflection coefficient of the THRU connection.

Transmission signal path frequency response is then measured with the THRU connected. The data is corrected for source and load match effects, then stored as transmission frequency response, E_{TF} .

Isolation Errors. Isolation, E_{XF} , represents the part of the incident signal that appears at the receiver without actually passing through the test device (Figure A-39). Isolation is measured with the test set in the transmission configuration and with terminations installed at the points where the test device will be connected.

Figure A-39. Isolation EXF

Error Terms the 4395A Can Reduce. Thus there are two sets of error terms, forward and reverse, with each set consisting of six error terms, as follows:

- **Forward**
	- \square Directivity, E_{DF}
	- \Box Isolation, E_{XF}
	- \Box Source Match, E_{SF}
	- \Box Load Match, E_{LF}
	- \Box Transmission Tracking, E_{TF}

- \Box Reflection Tracking, E_{RF}
- Reverse
	- \Box Directivity, E_{DR}
	- \Box Isolation, E_{XR}
	- \square Source Match, E_{SB}
	- \Box Load Match, E_{LR}
	- \Box Transmission Tracking, E_{TR}
	- \Box Reflection Tracking, E_{RR}

The 87511A, ^B S-parameter Test sets can measure both the forward and reverse characteristics of the test device without the need to manually remove and physically reverse it. With these test sets, the full two-port error model illustrated in Figure A-40 effectively removes both the forward and reverse error terms for transmission and reflection measurements.

The 87512A, B Transmission/Reflection Test kits cannot switch between forward and reverse directions, so the reverse error terms cannot be automatically measured. Therefore, with the one-path two-port calibration, the forward error terms are duplicated and used for both forward and reverse measurements by manually reversing the test device.

Figure A-40. Full Two-Port Error Model

The following equations show the full two-port error model equations for all four S-parameters of a two-port device. Note that the mathematics for this comprehensive model use all forward and reverse error terms and measured values. Thus, to perform full error correction for any one parameter, all four S-parameters must be measured.

$$
S_{11A} = \frac{\left[\left(\frac{S_{11M} - E_{DF}}{E_{RF}}\right)\left[1 + \left(\frac{S_{22M} - E_{DR}}{E_{RR}}\right)E_{SR}\right]\right] - \left[\left(\frac{S_{21M} - E_{XF}}{E_{TF}}\right)\left(\frac{S_{12M} - E_{XR}}{E_{TR}}\right)E_{LF}\right] \right]}{\left[1 + \left(\frac{S_{11M} - E_{DF}}{E_{RF}}\right)E_{SF}\right]\left[1 + \left(\frac{S_{22M} - E_{DR}}{E_{RR}}\right)E_{SR}\right] - \left[\left(\frac{S_{21M} - E_{XF}}{E_{TF}}\right)\left(\frac{S_{12M} - E_{XR}}{E_{TR}}\right)E_{LF}E_{LR}\right]}
$$
\n
$$
S_{21A} = \frac{\left[1 + \left(\frac{S_{11M} - E_{DF}}{E_{RF}}\right)E_{SF}\right]\left[1 + \left(\frac{S_{22M} - E_{DR}}{E_{RR}}\right)E_{SR}\right] - \left[\left(\frac{S_{21M} - E_{XF}}{E_{TF}}\right)\left(\frac{S_{12M} - E_{XR}}{E_{TF}}\right)E_{LF}E_{LR}\right]}{\left[1 + \left(\frac{S_{11M} - E_{DF}}{E_{RF}}\right)E_{SF}\right]\left[1 + \left(\frac{S_{22M} - E_{DR}}{E_{RF}}\right)E_{SR}\right] - \left[\left(\frac{S_{21M} - E_{XR}}{E_{TF}}\right)\left(\frac{S_{12M} - E_{XR}}{E_{TR}}\right)E_{LF}E_{LR}\right]}
$$
\n
$$
S_{12A} = \frac{\left[1 + \left(\frac{S_{11M} - E_{DF}}{E_{RF}}\right)E_{SF}\right]\left[1 + \left(\frac{S_{22M} - E_{DR}}{E_{RR}}\right)E_{SR}\right] - \left[\left(\frac{S_{21M} - E_{XR}}{E_{TF}}\right)\left(\frac{S_{12M} - E_{XR}}{E_{TF}}\right)E_{LF}E_{LR}\right]}{\left[1 + \left(\frac{S_{22M} - E_{DR}}{E_{RF}}\right)E_{SF}\right]\left[1 + \left(\frac{S_{11M} - E_{DF}}{E_{RF}}\right)E_{SF}\right] - \left[\left(\frac{
$$

In addition to the errors removed by accuracy enhancement, other systematic errors exist due to limitations of dynamic accuracy, test set switch repeatability, and test cable stability. These, combined with random errors, also contribute to total system measurement uncertainty. Therefore, after accuracy enhancement procedures are performed, residual measurement uncertainties remain.

Saving and Recalling Instrument States and Data

This section describes storage devices, the save and recall functions, and the information you need to save instrument states and data into files.

Additional information on how to save and recall instrument states is provided in the "To Save and Recall the Settings and Data" in Chapter 8.

Storage Devices

The analyzer supports two storage devices, a built-in flexible disk drive and a memory disk. The flexible disk drive should be used to store large numbers of files and long term data storage. The memory disk should be used to store temporary tentative data and instrument states and to store or retrieve data quickly.

Note Use the built-in flexible disk to store important data because the memory disk data is lost when the power is turned off.

Disk Requirements

The analyzer's disk drive uses a 720 Kbyte, or 1.44 Mbyte 3.5 inch micro-flexible disk.

Disk Formats

The analyzer's built-in disk drive can access both LIF (logical interchange format) and DOS formatted disks. The disk drive and the memory disk can also initialize ^a new disk in either LIF or DOS format. Note that the analyzer can initalize 1.44 Mbyte disks only.

The following list shows the applicable DOS formats for the analyzer.

- 720 Kbyte, 80 tracks, double-sided, 9 sectors/track
- \blacksquare 1.44 Mbyte, 80 tracks, double-sided, 18 sectors/track

Memory Disk Capacity

The memory disk capacity is 512 Kbyte. The memory disk capacity can be changed. This capacity includes the directory area. The capacity of data area depends on the disk format type.

Copy Files Between the Memory Disk and the Flexible Disk

A copy function is provided to copy files between the memory disk and the flexible disk. FILE UTILITIES in the SAVE menu displays the softkeys used to copy les. The GPIB command FILC is also available to copy files.

Note When you copy files using this function, use the same disk format type for both the memory disk and the flexible disk. This copy function cannot copy files when the format of the memory disk is different from the format of the flexible disk.

File Types And Data Saved

Binary Files and ASCII Files

The analyzer supports two file formats, binary and ASCII, that are used to save data on a disk. Binary files are used to save measurement conditions and data using the SAVE function and to retrieve binary data using the RECALL function. External controllers and Instrument BASIC can read measurement data from binary data les. ASCII measurement data or screen image les can be read by commonly available IBM PC based software for data analysis or other secondary functions. The RECALL function cannot read ASCII files.

Note When saving internal data arrays, note that ASCII data files cannot be recalled on the analyzer. If you need to recall the data, save the le in binary format. This binary data can be recalled and saved as an ASCII file at any time.

Data Groups

Instrument States and Internal Data Arrays (STATE)

This group consists of the instrument states that include raw calibration coefficients (network analyzer only), the data arrays, and the memory arrays. (Binary Files Only)

Internal Data Arrays (DATA ONLY)

The internal data arrays that are stored in the analyzer's memory consists of the following six data arrays. See "Data Processing" for complete information on each data array and their relationships.(Binary and ASCII Files)

- Raw data arrays contain raw, uncalibrated measurement data.
- Calibration Coefficients arrays contain the expanded calibration coefficients obtained by calibration of the network analyzer.
- \blacksquare Data arrays contain the calibrated data obtained using the calibration coefficients.
- \blacksquare Memory arrays contain the memory data arrays obtained using the DATA \rightarrow MEM operation.
- \blacksquare Data Trace arrays contain the formatted data.
- **Memory Trace arrays** contain the formatted data of the "memory arrays."

These arrays can be saved selectively to suit the application. For example, when measuring several devices with the same measurement settings, you may need to save only the trace

File Types And Data Saved

arrays for each device. Saving only the necessary arrays reduces the disk space required and the disk access time. In addition, saving internal data also allows the analysis of the measurement results using an external controller. See \File Structure of Internal Data Arrays File for Binary Files" for more information.

Graphics image (GRAPHICS)

The analyzer saves the graphics image of the screen as a graphics file in the TIFF (Tagged Image File Format) format. The TIFF format is used in ^a wide range of drawing software programs (in binary format only).

File Type and Data Group Combinations

You can select and save to a disk one of the following four combinations of the two file types and the four data groups.

- **Binary File**
	- \Box Instrument states and internal data arrays (STATE)
	- \Box Internal data arrays (DATA ONLY binary)
	- \Box Graphics image (GRAPHICS)
- \blacksquare ASCII File
	- \Box Internal data arrays (DATA ONLY ascii)

Note DATA ONLY does not save instrument settings such as start and stop frequencies. BE CAREFUL! Always make sure that you save the existing STATE if you want to use the setup again.
File Names

All data saved using the built-in disk drive and the memory disk has an identifying file name. A file name consists of the lower and upper case alphabet, numbers, and valid symbol characters. Up to 8 characters can be used for a file name. The following table shows the valid characters for LIF and DOS file names.

Valid Characters		Description
LIF	DOS Format	
$A - Z$	$A - Z$	Upper case alphabet
$a - z$	$a - z$	Lower case alphabet
$0 - 9$	$0 - 9$	Numeric characters
	$8 & 4 & 8' 10 - Q^{2}$	Symbol characters

Table A-4. Valid Characters for File Names

One of the following suffixes or extensions is automatically added to the file name depending on the data group type stored in the file.

Data Groups	Suffixes for LIF Extensions for	DOS
STATE ¹ Instrument States and Internal Data Arrays ($\mathsf{_}$.STA
(Internal Data Arrays (DATA ONLY (binary))	$_D$.DTA
Internal Data Arrays as an ASCII File (DATA ONLY (ASCII))		. TXT
Graphics Image as an TIFF File (GRAPHICS)		.TIF

Table A-5. Suffixes and Extensions Added Automatically

Auto Recall Function

When the 4395A is turned on, it looks for a file named "AUTOREC" from the built-in flexible disk or memory disk, and if found, the 4395A automatically reads the file to retrieve its data.

- Note **When you save the AUTOREC** file into the memory disk, you must perform memory disk backup operation. Otherwise, the AUTOREC file is lost when the power is turned off.
	- When the 4395A is turned ON, the 4395A looks for the AUTOREC file on the flexible disk first. If there is no AUTOREC file on the flexible disk, the 4395A looks for it on the memory disk.

File Structure

File Structure of Internal Data Arrays File for Binary Files

Note Binary and ASCII file structures are not compatible.

When internal data arrays are saved as a binary file, the arrays' file consists of a file header at the top of the file and the data groups following the file header.

File Header

Every internal data array file begins with a file header. Figure A-41 shows the header structure.

Figure A-41. File Header Structure

Six data switches define the data groups that follow the file head. Each one-byte switch is either 1 or 0 (decimal value) if the applicable data group exists or not, respectively. The data group to be followed is in the same order of these switches. For example, when the data switches, RAW DATA and DATA TRACE are 1 (on), while the others are off, only the RAW DATA and DATA TRACE (in this order) groups will follow the header.

Data Group

Data group of each channel begins with a header and consists of the same structured data segments. The number of data segments depends on the data group type as follows:

RAW DATA of the network analyzer consists of a header and four data segments per channel as shown in Figure A-42. They will follow the file header in this order:

Figure A-42. RAW Data Group Structure for the Network Analyzer

RAW DATA of the spectrum analyzer consists of a header and a data segment by a channel as shown in Figure A-43. They will follow the file header in this order:

Figure A-43. RAW Data Group Structure for the Spectrum Analyzer

 \blacksquare CAL of the network analyzer consists of 12 data segments by a channel as shown in Figure A-44. The first half of the segments are for channel 1 and the second half of the segments are for channel 2. The contents of each segment depend on the type of calibration performed. CAL data is available for only the network analyzer.

Figure A-44. CAL Data Group Structure for the Network Analyzer

Figure A-45. CAL Data Group Structure for the Spectrum Analyzer

- DATA consists of a header and a data segment by a channel.
- \blacksquare MEMORY consists of a header and a data segment by a channel.
- DATA TRACE consists of a header and a data segment by a channel.

 \blacksquare MEMORY TRACE consists of a header and a data segment by a channel.

Figure A-46. DATA, MEMORY, DATA TRACE and MEMORY TRACE Data Group Structure

- Analyzer Type is a two-byte INTEGER value. This shows the analyzer type of each channel. $\degree 0$ " is set when the network analyzer is selected and $\degree 1$ " is set when the spectrum analyzer is selected.
- \blacksquare Number Of Points (NOP) is a two-byte INTEGER value. This number is equal to the number of complex or real data that follows the NOP.
- \blacksquare DATA is a set of the values for each measurement point. The values are IEEE 754 double precision floating number. When the network analyzer mode is selected, the values are two numbers (the first value is the real part, the second value is the imaginary part). The data size in σ , and the determined σ is to selected, and the spectrum unuffied mode is selected, the values are one number and the data size in bytes can be determined by 8-A-19-1

File Structure of Internal Data Arrays File for ASCII File

Numerical data and strings in an ASCII data file are separated by a tab, and a string is bound by double quotation marks.

Status Block and Data Block

An ASCII data file consists of a status block and data blocks. The status block consists of two lines, the revision number and the date code. The data block consists of three parts, the state part, the title line, and the data part.

■ State

The state part consists of the following instrument states:

- \Box Channel number
- \Box Title on the screen
- \Box Measurement type
- \Box Format type (and Unit)
- \Box Number of points
- \Box Sweep time
- \Box Sweep type
- \Box Source power or CW frequency
- \Box IF, or RBW and VBW bandwidth
- Title

The title part consists of the data array names saved. Data array names are described in the next section.

■ Data

The data part consists of sweep parameter and numerical data of data arrays.

Table A-6 shows an example of an ASCII data file.

Table A-6. Contents of ASCII Files

1 This is the date when the file is saved.

2 This line is listed when the title is defined (displayed).

- ³ Shows the power level of the source for a frequency sweep. If power sweep is selected, the CW frequency is listed (for example "CW FREQ: ¹⁰⁰ MHz").
- $4 \degree \rightarrow$ " means tab code. Data is separated by the tab code.
- 5 This line lists the names of the data array saved in this file. Titles used in the ASCII files are shown in Table A-7 through Table A-10.
- ⁶ Each line lists the measurement data at each measurement point. The number of lines in the data block is the same as the number of points.
- ⁷ In the network analyzer mode, complex data is saved. In the spectrum analyzer mode, only real data is saved.

File Structure for Single Channel and Dual Channel

If you save an ASCII file when DUAL CHANNEL is turned OFF, the ASCII data file consists of the active channel's data. If DUAL CHANNEL is turned ON, the ASCII data file consists of the data of both channels ¹ and 2. The channel ² data follows the channel 1 data as follows:

Dual Channel OFF	Dual Channel ON
Status Block	Status Block
Data Block of Active Channel	Data Block of Channel 1
(end of file)	Status Block
	Data Block of Channel 2

File Structures for Single and Dual Channels

Data Array Names for the Spectrum Analyzer

Data array names are used in the title line of the data block. Each data array of the spectrum analyzer has one name, Table A-7 lists all names.

Table A-7. Data Groups and Data Array Names for Spectrum Analyzer

Data Groups	Data Array Names	Descriptions
Raw Data	Raw	Raw data array.
Data	Data	Corrected Data arrays
Memory	Memorv	Corrected Memory arrays
Data Trace	Data Trace	Data Trace arrays
Memory Trace	Memory Trace	Memory Trace arrays

Data Array Names for the Network Analyzer

Data array names are used in the title line of the data block. Each real and imaginary part of the internal data array of the network analyzer has one name, Table A-8 lists all names.

Data Groups	Data Array Names		Descriptions
	Real Part	Imaginary Part	
Raw Data	Raw S111 Real	Raw[S11] Imag	Raw data arrays for S11 meas.
	Raw S211 Real	Raw[S21] Imag	Raw data arrays for S21 meas.
	Raw[S12] Real	Raw[S12] Imag	Raw data arrays for S12 meas.
	Raw[S22] Imag	Raw[S22] Imag	Raw data arrays for S22 meas.
Calibration Data ¹	$Ca1[1]$ Real	$Cal[1]$ Imag	$\mathrm{Er,}^2$ Et, 2 Ex, 3 Ed, 3,4 or Edf 5
	Cal[2] Real	Cal[2] Imag	$Et, ^{3}Er, ^{3}Es, ^{4}$ or Esf^{5}
	Cal[3] Real	Cal[3] Imag	$Er4$ or $Erf5$
	Cal[4] Real	$Cal[4]$ Imag	Exf ⁵
	Cal[5] Real	$Cal[5]$ Imag	$E1f^5$
	Cal[6] Real	$Cal[6]$ Imag	Etf^5
	Cal[7] Real	Cal[7] Imag	Edr ⁵
	Cal[8] Real	$Cal[8]$ Imag	Esr^5
	Cal[9] Real	$Cal[9]$ Imag	Err ⁵
	Cal[10] Real	$Cal[10]$ Imag	Exr^5
	Cal[11] Real	$Cal[11]$ Imag	$E1r^5$
	$Ca1[12]$ Real	$Cal[12]$ Imag	Etr ⁵
Data	Data Real	Data Imag	Corrected Data arrays
Memory	Memory Real	Memory Imag	Corrected Memory arrays
Data Trace	Data Trace Real	Data Trace Imag	Data Trace arrays
Memory Trace	Memory Trace Real	Memory Trace Imag	Memory Trace arrays

Table A-8. Data Groups and Data Array Names for the Network Analyzer Mode

¹ For more information on calibration, see \Calibration for Network Measurement". Calibration data is available for only network analyzer mode.

² When response calibration is used.

- ³ When response and isolation calibration are used.
- ⁴ When ¹ port calibration is used.
- ⁵ When 2 port calibration is used.

Data Groups of the Spectrum Analyzer

Every data group of the spectrum analyzer consists of one data array.

Data Groups of the Network Analyzer

Every data group of the network analyzer consists of data arrays. The number of data arrays depends on the data group types. The saved data arrays RAW and CAL depend on the instrument state.

RAW DATA of the network analyzer consists of eight data arrays. The data arrays saved depend on the calibration type and the measurement type. If RAW DATA is saved in an ASCII data file when 2-port calibration is used, all eight RAW data arrays will be saved in the ASCII data file for any measurement type. If another calibration type is used, the data arrays saved depend on the measurement type. Table A-9 lists the RAW data array combinations that are saved for each measurement type selected.

Measurement Type	Raw Data Arrays Saved ¹	
A/R	"Raw[S11] Real", "Raw[S11] Imag"	
B/R	"Raw[S21] Real", "Raw[S21] Imag"	
A/B	"Raw[S12] Real", "Raw[S12] Imag"	
А	"Raw[S11] Real", "Raw[S11] Imag"	
В	"Raw[S21] Real", "Raw[S21] Imag"	
R	"Raw[S12] Real","Raw[S12] Imag"	
S11	"Raw[S11] Real", "Raw[S11] Imag"	
S ₁₂	"Raw[S12] Real", "Raw[S12] Imag"	
S21	"Raw[S21] Real", "Raw[S21] Imag"	
S ₂₂	"Raw[S22] Real", "Raw[S22] Imag"	

Table A-9. Network Measurement Type Versus Raw Data Saved

¹ When 2-port calibration is turned ON, all Raw Data is saved.

CAL DATA of the network analyzer consists of twenty data arrays. The data arrays saved depend on the calibration type used. Table A-10 lists the CAL data arrays that are saved for each calibration type selected.

Table A-10. Calibration Type for Network Measurement Versus CAL Data Saved

Calibration Type	CAL Data Saved	Error Terms ¹
Response	"Cal[1] Real", "Cal[1] Imag"	Er or Et
Response and Isolation	"Cal[1] Real", "Cal[1] Imag"	Ex or Ed
	"Cal[2] Real", "Cal[2] Imag"	Et or Er
1 port Calibration	"Cal[1] Real", "Cal[1] Imag"	Ed
	"Cal[2] Real", "Cal[2] Imag"	Es
	"Cal[3] Real", "Cal[3] Imag"	Er
2 port Calibration	"Cal[1] Real", "Cal[1] Imag"	Edf
	"Cal[2] Real", "Cal[2] Imag"	Esf
	"Cal[3] Real", "Cal[3] Imag"	Erf
	"Cal[4] Real", "Cal[4] Imag"	Exf
	"Cal[5] Real", "Cal[5] Imag"	Elf
	"Cal[6] Real", "Cal[6] Imag"	Etf
	"Cal[7] Real", "Cal[7] Imag"	Edr
	"Cal[8] Real", "Cal[8] Imag"	Esr
	"Cal[9] Real", "Cal[9] Imag"	Err
	"Cal[10] Real", "Cal[10] Imag"	Exr
	"Cal[11] Real", "Cal[11] Imag"	Elr
	"Cal[12] Real", "Cal[12] Imag"	Etr

¹ For more information on error terms, refer to \Calibration for Network Measurement".

- DATA of the network analyzer consists of two data arrays.
- MEMORY of the network analyzer consists of two data arrays.
- DATA TRACE of the network analyzer consists of two data arrays.
- MEMORY TRACE of the network analyzer consists of two data arrays.

Save Data Format

When you store the internal district the internal data array by Save and DATA ONLY , the stored binary le format is same as the network/spectrum analyzer except for the calibration and fixture compensation coefficients. This section provides the information about the save file format of the calibration and the fixture compensation coefficients.

CAL Data Group

This group consists of the calibration and the fixture compensation coefficients data segements by a channel as shown in Figure A-47. The first half of the segments are for channel 1 and the second half of the segments are for channel 2. The contents of each segment depend on the type of calibration performed.

Figure A-47. CAL Data Group Structure

^B

Softkey Reference

¹ Changing analyzer type will preset all the parameters for the active channel.

B-4 Softkey Reference

Format

Display

Scale Ref

 (Bw/Avg)

 $\boxed{\binom{Ca}{a}}$

Sweep

(Source)

Trigger

 $(Marker)$ $(Marker \rightarrow)$

¹ In the spectrum analyzer mode, the marker is always in the discontinuous mode.

(Search)

Utility

System

1 After you change the hour setting, press $ENTER$ to restart the clock.

¹ Because of the limited number of printer ink colors, the printed color is not always the same as the displayed color.

Save

Recall

Input Range and Default Settings

When the $(Present)$ key is pressed, or the analyzer is turned ON, the analyzer reverts to a known state. There are subtle differences between the preset state and the power-up state.

Some power-up states are recalled from non-volatile memory (battery backup memory). If power to the non-volatile memory is lost, the analyzer will have certain parameters set to factory settings. "Results of Power Loss to Battery Backup Memory (Factory Setting)" lists the factory settings. The operating time of the battery backup memory is approximately ⁷² hours(typical). The battery is automatically recharged while the instrument is ON. The recharge time (time required to fully recharge the battery) is approximately ¹ hour(typical).

This appendix also contains Table C-2 to Table C-7 which provide descriptions of the calibration kits predened for the calibraion functions of the network analyzer.

When line power is cycled the analyzer performs ^a self-test routine. Upon successful completion of the self-test routine, the instrument state is set to the following preset conditions. The same conditions are true following a "PRES" or "*RST" command over the GPIB bus.

Active Channel Block

 $(\overline{Chan 1}]$ and $(\overline{Chan 2}]$

Measurement Block

Meas

¹ When an S-parameter test set is connected to the analyzer.

² Both channel ¹ and ²

Format

Display

Measurement Block

1 a = 10^{-18}

Scale Ref

Measurement Block

Measurement Block

Measurement Block

¹ Except for Log Y-axis or Complex Plane.

Top Value Analyzer Mode:ZA, Format:Log Y-axis

Measurement Block

Bottom Value Analyzer Mode:ZA, Mode:Log Y-axis

Measurement Block

(Bw/Avg)

Sweep Block

Sweep Block

Sweep

¹ NOP is automatically set and can not be changed by user, except for ZERO SPAN.

Source

Sweep Block

Trigger

¹ With option 1D6.

Center

$(\overline{\text{Span}})$

Marker Block

Marker

Marker Block

¹ Zero will be returned if the marker position is read using GPIB command after presetting and before the marker turn to ON.

 $(Marker \rightarrow)$

Search

Utility

Instrument State Block

System

Save

Local

Results of Power Loss to Battery Backup Memory (Factory Setting)

Predefined Calibration Kits

NO.	STANDARD TYPE	$_{\rm CO}$ $\times 10^{-15}$ F	C1	C2 $\times 10^{-27}$ F/Hz $\times 10^{-36}$ F/Hz ²	OFFSET DELAY $_{\rm \bf{p}s}$	OFFSET LOSS $G\Omega/s$	OFFSET Z_0 Ω	STANDARD LABEL
1	SHORT				16.695	1.3	50	SHORT
$\overline{2}$	OPEN	53	150	θ	14.491	1.3	50	OPEN
3	LOAD				θ	1.3	50	BROADBAND
$\overline{4}$	DELAY/THRU				Ω	1.3	50	THRU
5	LOAD				θ	1.3	50	SLIDING
6	LOAD				Ω	1.3	50	LOWBAND
7	SHORT				Ω	1.3	50	SHORT
8	OPEN	79.4	$\mathbf{0}$	40	θ	1.3	50	OPEN

Table C-1. 3.5 mm Standard Cal Kit

Table C-2. ⁷ mm Standard Cal Kit

NO.	STANDARD TYPE	$_{\rm CO}$ $\times 10^{-15}$ F	C1	C2 \times 10 ⁻²⁷ F/Hz \times 10 ⁻³⁶ F/Hz ²	OFFSET DELAY $\mathbf{p}\mathbf{s}$	OFFSET LOSS $M\Omega/s$	OFFSET Z_0 Ω	STANDARD LABEL
1	SHORT				θ	700	50	SHORT
$\overline{2}$	OPEN	92.85	θ	7.2	θ	700	50	OPEN
3	LOAD				θ	700	50	BROADBAND
4	DELAY/THRU				θ	700	50	THRU
5	LOAD				θ	700	50	SLIDING
6	LOAD				θ	700	50	LOWBAND
7	SHORT				θ	700	50	
8	OPEN	79.4	θ	40	θ	700	50	OPEN

Table C-3. ⁵⁰ Type-N Standard Cal Kit

NO.	STANDARD TYPE	$_{\rm CO}$ $\times 10^{-15}$ F	C1 \times 10 ²⁷ F/Hz	C ₂ $\times 10^{-36}$ F/Hz ²	OFFSET DELAY $_{\rm ps}$	OFFSET LOSS $M\Omega/s$	OFFSET Z_0 Ω	STANDARD LABEL
1	SHORT				$\mathbf{0}$	1.13×10^{3}	75	SHORT[M]
$\overline{2}$	OPEN	63.5	84	56	$\mathbf{0}$	1.13×10^{3}	75	OPEN[M]
3	LOAD				$\mathbf{0}$	1.13×10^{3}	75	BROADBAND
$\overline{4}$	DELAY/THRU				θ	1.13×10^{3}	75	THRU
$\overline{5}$	LOAD				θ	1.13×10^{3}	75	SLIDING
6	LOAD				$\mathbf{0}$	1.13×10^{3}	75	LOWBAND
7	SHORT				17.544	1.13×10^{3}	75	SHORT[F]
8	OPEN	41	40	5	17.544	1.13×10^{3}	75	OPEN[F]

 $T_{\rm M}$ _y \sim $T_{\rm M}$, $T_{\rm M}$ $T_{\rm M}$, $T_{\rm M}$ $T_{\rm M}$ $T_{\rm M}$ $T_{\rm M}$ $T_{\rm M}$ $T_{\rm M}$

Predefined Standard Class Assignments

CLASS	A	\bf{B}	$\mathbf C$	D	E	$\mathbf F$	G	STANDARD CLASS LABEL
$\mathbf{S}_{11\,\mathrm{A}}$	$\overline{2}$							OPEN
S_{11B}	1							SHORT
S_{11C}	3							LOAD
$\mathbf{S}_{22\mathrm{A}}$	$\overline{2}$							OPEN
$\mathbf{S}_{22\mathrm{B}}$	1							SHORT
S_{22C}	3							LOAD
Forward Transmission	4							THRU
Reverse Transmission	4							THRU
Forward Match	4							THRU
Reverse Match	4							THRU
Response	1	$\overline{2}$	4					RESPONSE
Response & Isolation	1	$\overline{2}$	4					RESPONSE

Table C-5. Standard Class Assignments Table (7 mm and 3.5 mm)

Table C-6. Standard Class Assignments Table (50 Type-N)

CLASS	A	B	$\mathbf C$	D	E	F	G	STANDARD CLASS LABEL
S_{11A}	$\overline{2}$	8						OPENS
$\mathbf{S}_{11\,\mathrm{B}}$	1	7						SHORTS
S_{11C}	3							LOAD
S_{22A}	$\overline{2}$	8						OPENS
S_{22B}	1	7						SHORTS
$\mathrm{S}_{\mathrm{22C}}$	3							LOAD
Forward Transmission	4							THRU
Reverse Transmission	4							THRU
Forward Match	4							THRU
Reverse Match	4							THRU
Response	1	7	2	8	4			RESPONSE
Response & Isolation	1	7	$\overline{2}$	8	4			RESPONSE

CLASS	A	В	$\mathbf C$	D	Е	F	G	STANDARD CLASS LABEL
	$\overline{2}$	8						OPENS
$\mathbf{S}_{1\,1\,\mathrm{A}}$								
S_{11B}	1	7						SHORTS
S_{11C}	3							LOAD
S_{22A}	$\overline{2}$	8						OPENS
S_{22B}	1	7						SHORTS
S_{22C}	3							LOAD
Forward Transmission	4							THRU
Reverse Transmission	4							THRU
Forward Match	4							THRU
Reverse Match	4							THRU
Response	1	7	$\overline{2}$	8	$\overline{4}$			RESPONSE
Response & Isolation	1	7	$\overline{2}$	8	4			RESPONSE

Table C-7. Standard Class Assignments Table (75 Type-N)

Manual Changes

Introduction

This appendix contains the information required to adapt this manual to earlier versions or congurations of the analyzer than the current printing date of this manual. The information in this manual applies directly to the 4395A Network/Spectrum Analyzer serial number prefix listed on the title page of this manual.

Manual Changes

To adapt this manual to your 4395A, see Table D-1 and Table D-2, and make all the manual changes listed opposite your instrument's serial number and firmware version.

Instruments manufactured after the printing of this manual may be different from those documented in this manual. Later instrument versions will be documented in ^a manual changes supplement that will accompany the manual shipped with that instrument. If your instrument's serial number is not listed on the title page of this manual or in Table D-1, it may be documented in a *yellow MANUAL CHANGES* supplement.

In additions to change information, the supplement may contain information for correcting errors (Errata) in the manual. To keep this manual as current and accurate as possible, Agilent Technologies recommends that you periodically request the latest MANUAL CHANGES supplement.

For information concerning serial number prefixes not listed on the title page or in the MANUAL CHANGE supplement, contact the nearest Agilent Technologies office.

Turn on the line switch or execute the *IDN? command by GPIB to confirm the firmware version. See the GPIB Command Reference manual for information on the *IDN? command.

Serial Prefix or Number	Make Manual Changes
1 P 1 K F 1	

Table D-1. Manual Changes by Serial Number

Serial Number

Agilent Technologies uses a two-part, nine-character serial number that is stamped on the serial number plate (see Figure D-1) attached to the rear panel. The first five characters are the serial prefix and the last five digits are the suffix.

Figure D-1. Serial Number Plate (sample)

Miscellaneous Changes

The option system of the 4395A has changed since June 2002. Apply the following changes.

¹ In the previous system, an option for the DC bias source was available only for \Add". In the new option system, it is available for "Add" and "No", requiring the customer to select either of them.

- ² In the previous system, an option for the time-gated spectrum analysis was available only for "Add". In the new option system, it is available for "Add" and "No", requiring the customer to select either of them.
- ³ In the previous system, an option for the frequency reference was available only for the high stability frequency reference. In the new option system, it is available for the high stability and standard references, requiring the customer to select either of them.
- ⁴ In the previous option system, the keyboard comes as one of standard accessories. In the new option system, it will be attached only when you choose option 810.

The option system of the 4395A has changed since May 2003. Apply the following changes.

¹ In the previous system, the option number is used to choose the language of the operation manual set (standard accessory). In the new option system, it is used to add an operation manual set (optional accessory) of the language the customer desires.

² No selection of addition/deletion is required for the operation manual set because it is only available as an optional accessory in the new option system. When 2 or more sets are required, specify option ABA,ABJ * (number of required sets).

Error Messages

This section lists the error messages that are displayed on the analyzer display or transmitted by the instrument over GPIB. Each error message is accompanied by an explanation, and suggestions are provided to help in solving the problem. Where applicable, references are provided to the related chapter of the appropriate manual.

When displayed, error messages are preceded with the word "CAUTION:." That part of the error message has been omitted here for the sake or brevity. Some messages without the \CAUTION:" are for information only, and do not indicate an error condition. The messages are listed first in alphabetical order because the displayed messages do not contain the message number. The messages are then listed in numerical order to make them easier to find if they are read over the GPIB.

In addition to error messages, The analyzer's status is indicated by status notations in the left margin of the display. Examples are \ast , Cor, and Avg. Sometimes these appear together with error messages. ^A complete listing of status notations and their meanings is provided in Chapter ⁴ of this manual.

Error Messages in Alphabetical Order

\mathbf{A}

¹⁷³ ACTIVE/SYSTEM CONTROLLER REQUIRED

When the 4395A and its peripherals are controlled using the Instrument BASIC, you must set the GPIB system's control mode to the system controller mode.

¹⁰ ADDITIONAL STANDARDS NEEDED 10

Error correction for the selected calibration class cannot be computed until all the necessary standards have been measured.

⁸⁴ ANALYZER TYPE MISMATCH 84

The analyzer receives a command that is not available for the current analyzer type. Please confirm GPIB command or change analyzer type before sending the command.

B

¹⁷ BACKUP DATA LOST

Data checksum error on the battery backup memory has occurred. The battery is recharged for approximately 10 minutes after power was turned on.

Error Messages in Alphabetical Order

-160 160 Block data error

This error, as well as errors -161 and -168 , are generated when analyzing the syntax of a block data element. This particular error message is used if the analyzer cannot detect ^a more specific error.

-168 Block data not allowed

^A legal block data element was encountered but was not allowed by the analyzer at this point in parsing.

^C

¹³ CALIBRATION ABORTED

The calibration in progress was terminated due to ^a change of the active channel or stimulus parameters.

CALIBRATION REQUIRED 11

No valid calibration coefficients were found when you attempted to turn calibration on.

126 CAN'T CHANGE NUMBER OF POINTS

The number of points of the spectrum analyzer mode cannot be to change manually, except in zero span.

133 CAN'T CHANGE ON LIST SWEEP

When list sweep is selected, the following parameters are not allowed to be changed:

- CENTER, SPAN, START, STOP
- \blacksquare NOP
- IFBW or RBW
- **POWER**
- **DC SOURCE**

Modify the list table to change these parameters in the list sweep.

97 CAN'T CHANGE WHILE DATA MATH ON

The setting cannot be changed when the data math function is used.

⁹⁹ CAN'T CHANGE WHILE DUAL CHAN OFF

The Cross channel cannot be turned on when dual channel is off. Turn on the dual channel before the cross channel is turned on.

82 CAN'T CHANGE- ANOTHER CONTROLLER ON BUS

The analyzer cannot assume the mode of system controller until the active controller is removed from the bus or relinquishes the bus. See *Programming Manual*.

134 CAN'T COUPLE IN CURRENT INPUTS

When one channel measures a ratio measurement, and the other one measures an absolute measurement (for example: A/R and B), COUPLED CH can not be turned on.

¹¹⁴ CAN'T SAVE GRAPHICS WHEN COPY IN PROGRESS

If you attempt to save graphics when a print is in progress, this error message is displayed.

¹ CAN'T SET RBW AUTO IN ZERO SPAN

The RBW AUTO mode cannot be selected in the zero span. The RBW must be specied manually in the zero span. (spectrum analyzer mode only).

¹²⁷ CAN'T SET SWEEP TIME AUTO IN ZERO SPAN

The automatic sweep time cannot be in zero span of the spectrum analyzer mode. (The network analyzer mode allows that the automatic sweep time is turned on.)

-281 Cannot create program

Indicates that an attempt to create ^a program was unsuccessful. ^A reason for the failure might include not enough memory.

-140 Character data error

This error, as well as errors -141 through -148 , are generated when analyzing the syntax of a character data element. This particular error message is used if the analyzer cannot detect ^a more specific error.

-148 Character data not allowed

^A legal character data element was encountered where prohibited by the analyzer.

-144 Character data too long

The character data element contains more than twelve characters (see IEEE 488.2, 7.7.1.4).

-100 Command error

This is a generic syntax error that the analyzer cannot detect more specific errors. This code indicates only that a command error, as defined in IEEE 488.2, 11.5.1.1.4, has occurred.

-110 Command header error

An error was detected in the header. This error message is used when the analyzer cannot detect the more specific errors described for errors -111 through -119 .

⁷⁵ COMMAND IGNORED - SEGMENT NOT DONE YET

The GPIB command the analyzer received is ignored, because the segment is editing (GPIB only). Send LIMSDON (limit segment done) or SDON (segment done) to terminate editing segment. (See Programming Manual.)

²⁶⁹ COMPENSATION ABORTED 269

Compensation data acquisition process is aborted.

²⁶⁷ COMPENSTATION REQUIRED

Compensation is required. Perform compansation to obtain compensation data.

Error Messages in Alphabetical Order

⁵⁰ CONT SWITCHING MAY DAMAGE MECH SW 50

RF output power switch, input attenuator switch at input R/A/B, or internal mechanical switch in the S-parameter test set is switching sweep by sweep, because RF power level or the input attenuator setting is different between two channels and the dual channel is turn on, or continuous trigger mode is selected after full 2-port calibration is performed when 4395A is used with the S-parameter test set. To avoid premature wearing out of the output power switch, input attenuator switch, or internal switch of the S-parameter test set, change trigger type to HOLD, SINGLE, or NUMBER of GROUP to hold sweep after measurement required. Or, for example, turn off the dual channel, or set the power level and the input attenuator of both channels to the same setting.

135 ¹³⁵ COUPLED CHAN - BETWEEN NA&NA OR ZA&ZA

The analyzer types of both channels must be the network analyzer mode or impedance analyzer mode when the coupled channel is turned on. It is not possible to turn the coupled channel on in spectrum analyzer mode.

CURRENT EDITING SEGMENT SCRATCHED 74

The current editing segment for the list table and the limit line is scratched when the following cases occur (GPIB only) :

- When EDITLIST (edit list table) command is received while editing a segment for the list table. table.
- When EDITLIML (edit limit line) command is received while editing ^a segment for the limit line.

Send LIMSDON (limit segment done) or SDON (segment done) to terminate editing segment.

¹⁶ CURRENT PARAMETER NOT IN CAL SET 16

GPIB only. Correction is not valid for the selected measurement parameter.

^D

230 Data corrupt or stale

Possibly invalid data. New reading started but not completed since last access.

-225 Data out of memory

The analyzer has insufficient memory to perform the requested operation.

-222 Data out of range

A legal program data element was parsed but could not be executed because the interpreted value was outside the legal range as defined by the analyzer (see IEEE 488.2, 11.5.1.1.5).

231 Data questionable

Indicates that measurement accuracy is suspect.

-104 Data type error

The parser recognized an unallowed data element. For example, numeric or string data was expected but block data was encountered.

Messages-4

DC CURRENT LIMIT OCCURED 137

The output current at DC SOURCE port is reached the upper limit; the output voltage is reduced so that the current does not exceed the upper limit. This message appears when the DC SOURCE port is used in voltage control mode.

¹³⁶ DC SOURCE OVERLOAD

The DC SOURCE output is overloded.

138 DC VOLTAGE LIMIT OCCURED

The output voltage at DC SOURCE port is reached the upper limit; the output current is reduced so that the voltage does not exceed the upper limit. This message appears when the DC SOURCE port is used in current control mode.

37 DISPLAY BUFFER IS FULL

The display buffer is filled with the overlay traces or traces drawn by IBASIC DRAW/MOVE commands, etc.

¹¹⁷ DUPLICATE FILE EXTENSION

The extension name entered is already used for other file types. Use other extension name.

-15

A maximum of seven standards can be defined for any class.

200 Execution error

This is the generic syntax error that the analyzer cannot detect more specific errors. This code indicates only that an execution error as defined in IEEE 488.2, 11.5.1.1.5 has occurred.

-123 Exponent too large

The magnitude of the exponent was larger than 32000 (see IEEE 488.2, 7.7.2.4.1).

^F

257 File name error

Indicates that a legal program command or query could not be executed because the file name on the device media was in error. For example, an attempt was made to copy to a duplicate file name. The definition of what constitutes a file name error is device-specific.

-256 File name not found

A legal program command could not be executed because the file name on the device media was not found: for example, an attempt was made to read or copy a nonexistent file.

Error Messages in Alphabetical Order

FLOATING POINT ERROR OCCURED 143

Indicate that a floating point error occured in the analyzer. Data processing may not be correct. This error message is used when an internal application was executed for illegal data sent from an external device, or when an internal software bug was detected. Contact your nearest Agilent Technologies office.

⁸³ FORMAT NOT VALID FOR MEASUREMENT

The conversion function except the 1/S and the multiple phase modes is not valid for the Smith, admittance, and SWR formats.

FREQUENCY SWEEP ONLY 131

The sweep type must be frequency sweep when the center step size is set.

-105 **GET** not allowed

^A Group Execute Trigger (GET) was received within a program message (see IEEE 488.2, 7.7).

^H

-240 Hardware error

Indicates that a legal program command or query could not be executed because of ^a hardware problem in the analyzer. Definition of what constitutes a hard ware problem is completely device-specific. This error message is used when the analyzer cannot detect the more specific errors described for errors -241 through -249 .

-241 Hardware missing

^A legal program command or query could not be executed because of missing analyzer hardware. For example, an option was not installed.

-111 Header separator error

A character that is not a legal header separator was encountered while parsing the header. For example, no white space followed the header, thus *SRE4 is an error.

-114 Header Suffix out of range

The value of a numeric suffix attached to a program mnemonic makes the header invalid.

^I

-224 Illegal parameter value

Used where exact value, from a list of possibilities, was expected.

-282 Illegal program name

The name used to reference a program was invalid. For example, redefining an existing program, deleting a nonexistent program, or in general, referencing a nonexistent program.

-283 Illegal variable name

An attempt was made to reference ^a nonexistent variable in a program.

-213 Init ignored

^A request for ^a measurement initiation was ignored as another measurement was already in progress.

141 **INSUFFICIENT MEMORY**

If a lot of tasks is executed at same time, memory might be insufficient for a while. (For example, running HP Instrument BASIC program, printing ^a screen, and sending or receiving data array by GPIB are required at same time.) Please wait until finishing some tasks then execute the next task.

-161 Invalid block data

^A block data element was expected, but was invalid for some reason (see IEEE 488.2, 7.7.6.2). For example, an END message was received before the length was satisfied.

-141 Invalid character data

Either the character data element contains an invalid character or the particular element received is not valid for the header.

Invalid character in number -121

An invalid character for the data type being parsed was encountered. For example, an alpha character in ^a decimal numeric or ^a \9" in octal data.

-101 Invalid character

^A syntax element contains a character that is invalid for that type. For example, ^a header containing an ampersand (SENSE&).

154 INVALID DATE

The date entered to set the real time clock is invalid. Reenter correct date.

¹¹² INVALID FILE NAME

 $GPIB$ only. The file name for the RECALL, PURGE, or RE-SAVE function must have a " $_D$ " or _S" extension for LIF format.

-103 Invalid separator

The parser was expecting a separator and encountered an illegal character. For example, the semicolon was omitted after a program message unit, *RST:TRIG.

Error Messages in Alphabetical Order

-151 Invalid string data

A string data element was expected, but was invalid for some reason (see IEEE 488.2, 7.7.5.2). For example, an END message was received before the terminal quote character.

-131 Invalid suffix

The suffix does not follow the syntax described in IEEE $488.2, 7.7.3.2$, or the suffix is inappropriate for the analyzer.

^L

¹¹⁵ LIF-DOS COPY NOT ALLOWED

If you try to copy a file between the memory disk and the flexible disk when the format of the memory disk is different from the format of the flexible disk, this message is displayed.

124 LIST TABLE EMPTY OR INSUFFICIENT TABLE

The frequency list is empty. To implement the list frequency mode, add segments to the list table.

-250 Mass storage error

Indicates that ^a mass storage error occurred. This error message is used when the analyzer cannot detect the more specific errors described for errors -257 .

311 Memory error

An error was detected in the analyzer's memory.

-109 Missing parameter

Fewer parameters were received than required for the header. For example, the *SRE command requires one parameter, so receiving only *SRE is not allowed.

^N

98 NO ACTIVE MARKER

The marker \rightarrow command cannot be execute when no marker is displayed on the screen. Turn on the marker before executing the marker \rightarrow commands.

12 NO CALIBRATION CURRENTLY IN PROGRESS

The RESUME CAL SEQUENCE softkey is not valid unless a calibration is in progress. Start a new calibration.

²⁶⁸ NO COMPENSATION CURRENTLY IN PROGRESS

No compensation is currently in progress.

NO DATA TRACE DISPLAYED 119

The SCALE FOR [DATA] is selected when the data trace is not displayed.

NO DATA TRACE 93

The MARKER ON [DATA] is selected when the data trace is not displayed.

+0 No error

The error queue is empty. Every error in the queue has been read (OUTPERRO? query) or the queue was cleared by power-on or the *CLS command.

¹⁰⁰ NO FIXED DELTA MARKER

The FIXED AMKR VALUE and FIXED AMKR AUX VALUE softkey requires that fixed delta marker is turned on.

96

The $MRA \rightarrow$ SEARCH RNG softkey requires that delta marker is turned on.

⁹⁵ NO MARKER DELTA - SPAN NOT SET

The $\overline{MKRA} \rightarrow SPAN$ softkey requires that delta marker mode be turned on.

120 **NO MEMORY TRACE DISPLAYED**

The SCALE FOR [MEMORY] is selected when the memory trace is not displayed.

94 NO MEMORY TRACE

The MARKER ON [MEMORY] is selected when the memory trace is not displayed.

¹¹³ NO STATE/DATA FILES ON DISK

There are no files on the flexible disk with extensions, " $_D$ " or " $_S$ " for LIF format, or "STA" or \.DTA" for DOS format.

NO STATE/DATA FILES ON MEMORY 116

There are no files on the memory disk with extensions, " $_D$ " or " $_S$ " for LIF format, or ".STA" or ".DTA" for DOS format.

184 NOT ALLOWED IN SVC MODE

The operation is not allowed in service mode.

⁵⁵ NOT ENOUGH DATA

The amount of data sent to the analyzer is less than that expected (GPIB only).

¹⁴ NOT VALID FOR PRESENT TEST SET

The calibration requested is inconsistent with the test set present. This message occurs in the following situations:

Error Messages in Alphabetical Order

- A full 2-port calibration is requested with a test set other than an S-parameter test set.
- A one-path 2-port calibration is requested with an S-parameter test set (this procedure is typically used with a transmission/reflection test set).

NO VALID MEMORY TRACE -34

If a memory trace is to be displayed or otherwise used, a data trace must first be stored to memory.

-120 Numeric data error

This error, as well as errors -121 through -129 , are generated when parsing a data element that appears to be numeric, including the nondecimal numeric types. This particular error message is used if the analyzer cannot detect a more specific error.

-128 Numeric data not allowed

^A legal numeric data element was received, but the analyzer does not accept it in this position for ^a header.

Ω

146 ON POINT NOT ALLOWD FOR THE CURRENT TRIG

The trigger event mode cannot be changed to the ON POINT mode because the current trigger source setting does not allow the ON POINT mode. The ON POINT mode is available for only MANUAL, EXTERNAL, and BUS trigger sources of the network analyzer mode.

OPTION NOT INSTALLED 56

This error occurs when an GPIB command which is optional command is sent and the analyzer is not installed the option $(GPIB \text{ only})$. Please confirm options installed to the analyzer using *OPT? command (see Programming Manual.)

⁴⁵ OVERLOAD ON INPUT ^A

The power level at one of the four receiver inputs exceeds ^a certain level greater than the maximum input level.

44 **OVERLOAD ON INPUT B**

The power level at one of the four receiver inputs exceeds ^a certain level greater than the maximum input level.

⁴⁶ OVERLOAD ON INPUT R

The power level at one of the four receiver inputs exceeds a certain level greater than the maximum input level.

220 Parameter error

Indicates that a program data element related error occurred. This error message is used when the analyzer cannot detect the more specific errors described for errors -221 through -229 .

^P

-108 Parameter not allowed

More parameters were received than expected for the header. For example, the *SRE command only accepts one parameter, so receiving *SRE 4,16 is not allowed.

PHASE LOCK LOOP UNLOCKED 48

EXT REF Input of ¹⁰ MHz is not proper, or the instrument is needed to adjust or repair. Check the external reference signal first. Contact your nearest Agilent Technologies office for adjustment or repair.

POWER ON TEST FAILED 193

Power on test failed. Contact your nearest Agilent Technologies office.

PRINTER: not on, not connected, out of paper 26

The printer does not respond to control. Check the supply to the printer, online status, sheets, and so on.

-284 Program currently running

Certain operations dealing with programs may be illegal while the program is running. For example, deleting ^a running program might not be possible.

280 Program error

Indicates that ^a downloaded program-related execution error occurred. This error message is used when the analyzer cannot detect the more specific errors described for errors -281 through -289 .

-112 Program mnemonic too long

The header contains more than twelve characters (see IEEE 488.2, 7.6.1.4.1).

286 Program runtime error

^A program runtime error of the HP Instrument BASIC has occurred. To get ^a more specic error information, use the ERRM\$ or ERRN command of the HP Instrument BASIC.

285 Program syntax error

Indicates that a syntax error appears in ^a downloaded program. The syntax used when parsing the downloaded program is device-specic.

^Q

400 Query errors

This is the generic query error that the analyzer cannot detect more specific errors. This code indicates only that a query error as defined in IEEE 488.2, 11.5.1.1.7 and 6.3 has occurred.

410 Query INTERRUPTED

A condition causing an interrupted query error occurred (see IEEE 488.2, 6.3.2.3). For example, a query followed by DAB or GET before a response was completely sent.

Error Messages in Alphabetical Order

-420 420 Query UNTERMINATED

A condition causing an unterminated query error occurred (see IEEE 488.2, 6.3.2.2). For example, the analyzer was addressed to talk and an incomplete program message was received by the controller.

-350 Queue overflow

^A specic code entered into the queue in lieu of the code that caused the error. This code indicates that there is no room in the queue and an error occurred but was not recorded.

^R

¹¹¹ RECALL ERROR: INSTR STATE PRESET

A serious error, for example corrupted data, is detected on recalling a file, and this forced the analyzer to be PRESET.

$\overline{\mathbf{s}}$

110 **SAVE ERROR**

A serious error, for example physically damaged disk surface, is detected on saving a file.

SEGMENT START/STOP OVERLAPPED 76

Segments are not allowed to be overlapped. Reenter appropriate value for start or stop value of segments to avoid that segment is not overlapped.

330 Self-test failed

A self-test failed. Contact your nearest Agilent Technologies office or see the Service Manual for troubleshooting.

-221 Settings conflict

^A legal program data element was parsed but could not be executed due to the current device state (see IEEE 488.2, 6.4.5.3 and 11.5.1.1.5).

128 $SPAN = 0$ ONLY

The setup must be zero span and spectrum analyzer mode when turning on the RF OUTPUT.

150 String data error

This error, as well as errors -151 and -158 , are generated when analyzing the syntax of a string data element. This particular error message is used if the analyzer cannot detect a more specific error.

-158 String data not allowed

A string data element was encountered but was not allowed by the analyzer at this point in parsing.
Suffix error -130

This error, as well as errors -131 through -139 , are generated when parsing a suffix. This particular error message is used if the analyzer cannot detect a more specific error.

-138 Suffix not allowed

A suffix was encountered after a numeric element that does not allow suffixes.

-134 Suffix too long

The suffix contained more than 12 characters (see IEEE 488.2, 7.7.3.4).

-102 Syntax error

An unrecognized command or data type was encountered. For example, ^a string was received when the analyzer was not expecting to receive ^a string.

-310 System error

Some error, termed "system error" by the analyzer, has occurred.

-124 Too many digits

The mantissa of ^a decimal numeric data element contains more than ²⁵⁵ digits excluding leading zeros (see IEEE 488.2, 7.7.2.4.1).

⁷⁷ TOO MANY SEGMENTS OR POINTS 77

Frequency list mode is limited to 31 segments or ⁸⁰¹ points.

64

The maximum number of segments for the limit line table is 18.

-223 Too much data

A legal program data element of block, expression, or string type was received that contained more data than the analyzer could handle due to memory or related device-specic requirements.

TOO MUCH DATA 54

Either there is too much binary data to send to the analyzer when the data transfer format is FORM 2, FORM 3 or FORM 5, or the amount of data is greater than the number of points.

⁷⁸ TOO SMALL POINTS OR TOO LARGE STOP

 $STOP + SPAN/ (NOP-1)$ is out of sweep range. Increase NOP or change STOP value to lower frequency to avoid this error.

-210 Trigger error

A trigger related error occurred. This error message is used when the analyzer cannot detect the more specific errors described for errors -211 through -219 .

Error Messages in Alphabetical Order

-211 Trigger ignored

A GET, *TRG, or triggering signal was received and recognized by the analyzer but was ignored because of analyzer timing considerations. For example, the analyzer was not ready to respond.

^U

-113 Undefined header

The header is syntactically correct, but it is undefined for the analyzer. For example, *XYZ is not defined for the analyzer.

$0 - 100$

The error queue is empty. Every error in the queue has been read (OUTPERRO? query) or the queue was cleared by power-on or the *CLS command.

¹ CAN'T SET RBW AUTO IN ZERO SPAN

The RBW AUTO mode cannot be selected in the zero span. The RBW must be specied manually in the zero span. (spectrum analyzer mode only).

¹⁰ ADDITIONAL STANDARDS NEEDED 10

Error correction for the selected calibration class cannot be computed until all the necessary standards have been measured.

¹¹ CALIBRATION REQUIRED

No valid calibration coefficients were found when you attempted to turn calibration on.

12 NO CALIBRATION CURRENTLY IN PROGRESS

The RESUME CAL SEQUENCE softkey is not valid unless a calibration is in progress. Start a new calibration.

CALIBRATION ABORTED 13

The calibration in progress was terminated due to ^a change of the active channel or stimulus parameters.

14

The calibration requested is inconsistent with the test set present. This message occurs in the following situations:

- A full 2-port calibration is requested with a test set other than an S-parameter test set.
- A one-path 2-port calibration is requested with an S-parameter test set (this procedure is typically used with a transmission/reflection test set).

¹⁵ EXCEEDED 7 STANDARDS PER CLASS -15

A maximum of seven standards can be defined for any class.

¹⁶ CURRENT PARAMETER NOT IN CAL SET

GPIB only. Correction is not valid for the selected measurement parameter.

BACKUP DATA LOST 17

Data checksum error on the battery backup memory has occurred. The battery is recharged for approximately 10 minutes after power was turned on.

26 PRINTER:not on, not connect, wrong address

The printer does not respond to control. Check the supply to the printer, online status, sheets, and so on.

NO VALID MEMORY TRACE -34

If a memory trace is to be displayed or otherwise used, a data trace must first be stored to memory.

37 DISPLAY BUFFER IS FULL

The display buffer is filled with the overlay traces or traces drawn by IBASIC DRAW/MOVE commands, etc.

OVERLOAD ON INPUT B 44

The power level at one of the four receiver inputs exceeds ^a certain level greater than the maximum input level.

45 OVERLOAD ON INPUT A

The power level at one of the four receiver inputs exceeds ^a certain level greater than the maximum input level.

OVERLOAD ON INPUT R 46

The power level at one of the four receiver inputs exceeds ^a certain level greater than the maximum input level.

PHASE LOCK LOOP UNLOCKED 48

EXT REF Input of ¹⁰ MHz is not proper, or the instrument is needed to adjust or repair. Check the external reference signal first. Contact your nearest Agilent Technologies office for adjustment or repair.

50 ⁵⁰ CONT SWITCHING MAY DAMAGE MECH SW

RF output power switch, input attenuator switch at input R/A/B, or internal mechanical switch in the S-parameter test set is switching sweep by sweep, because RF power level or the input attenuator setting is different between two channels and the dual channel is turn on, or continuous trigger mode is selected after full 2-port calibration is performed when 4395A is used with the S-parameter test set. To avoid premature wearing out of the output power switch, input attenuator switch, or internal switch of the S-parameter test set, change trigger type to HOLD, SINGLE, or NUMBER of GROUP to hold sweep after measurement required. Or, for example, turn off the dual channel, or set the power level and the input attenuator of both channels to the same setting.

⁵⁴ TOO MUCH DATA

Either there is too much binary data to send to the analyzer when the data transfer format is FORM 2, FORM 3 or FORM 5, or the amount of data is greater than the number of points.

55 **NOT ENOUGH DATA**

The amount of data sent to the analyzer is less than that expected (GPIB only).

⁵⁶ OPTION NOT INSTALLED 56

This error occurs when an GPIB command which is optional command is sent and the analyzer is not installed the option $(GPIB \text{ only})$. Please confirm options installed to the analyzer using *OPT? command (see Programming Manual.)

TOO MANY SEGMENTS 64

The maximum number of segments for the limit line table is 18.

74 ⁷⁴ CURRENT EDITING SEGMENT SCRATCHED

The current editing segment for the list table and the limit line is scratched when the following cases occur (GPIB only) :

- When EDITLIST (edit list table) command is received while editing ^a segment for the list table.
- When EDITLIML (edit limit line) command is received while editing ^a segment for the limit line.

Send LIMSDON (limit segment done) or SDON (segment done) to terminate editing segment.

COMMAND IGNORED - SEGMENT NOT DONE YET 75

The GPIB command the analyzer received is ignored, because the segment is editing (GPIB only). Send LIMSDON (limit segment done) or SDON (segment done) to terminate editing segment. (See Programming Manual.)

76

Segments are not allowed to be overlapped. Reenter appropriate value for start or stop value of segments to avoid that segment is not overlapped.

77 **TOO MANY SEGMENTS OR POINTS**

Frequency list mode is limited to ³¹ segments or ⁸⁰¹ points.

⁷⁸ TOO SMALL POINTS OR TOO LARGE STOP

 $STOP + SPAN/ (NOP-1)$ is out of sweep range. Increase NOP or change STOP value to lower frequency to avoid this error.

82 CAN'T CHANGE- ANOTHER CONTROLLER ON BUS

The analyzer cannot assume the mode of system controller until the active controller is removed from the bus or relinquishes the bus. See Programming Manual.

83 FORMAT NOT VALID FOR MEASUREMENT

The conversion function except the 1/S and the multiple phase modes is not valid for the Smith, admittance, and SWR formats.

84 **ANALYZER TYPE MISMATCH** ⁸⁴ ANALYZER TYPE MISMATCH

The analyzer receives a command that is not available for the current analyzer type. Please confirm GPIB command or change analyzer type before sending the command.

93 NO DATA TRACE

The MARKER ON [DATA] is selected when the data trace is not displayed.

NO MEMORY TRACE 94

The MARKER ON [MEMORY] is selected when the memory trace is not displayed.

⁹⁵ NO MARKER DELTA - SPAN NOT SET

The MKRA-SPAN softkey requires that delta marker mode be turned on.

⁹⁶ NO MARKER DELTA - RANGE NOT SET ុណ

The MKRA-SEARCH RNG softkey requires that delta marker is turned on.

97 CAN'T CHANGE WHILE DATA MATH ON

The setting cannot be changed when the data math function is used.

NO ACTIVE MARKER 98

The marker \rightarrow command cannot be execute when no marker is displayed on the screen. Turn on the marker before executing the marker \rightarrow commands.

99 CAN'T CHANGE WHILE DUAL CHAN OFF

The Cross channel cannot be turned on when dual channel is off. Turn on the dual channel before the cross channel is turned on.

100

The FIXED AMKR VALUE and FIXED AMKR AUX VALUE softkey requires that fixed delta marker is turned on.

¹⁰¹ - ²⁰⁰

110 **SAVE ERROR**

A serious error, for example physically damaged disk surface, is detected on saving a file.

¹¹¹ RECALL ERROR: INSTR STATE PRESET

A serious error, for example corrupted data, is detected on recalling a file, and this forced the analyzer to be PRESET.

¹¹² INVALID FILE NAME

 $GPIB$ only. The file name for the RECALL, PURGE, or RE-SAVE function must have a " $_D$ " or _S" extension for LIF format.

NO STATE/DATA FILES ON DISK 113

There are no files on the flexible disk with extensions, " D " or " S " for LIF format, or "STA" or \.DTA" for DOS format.

¹¹⁴ CAN'T SAVE GRAPHICS WHEN COPY IN PROGRESS

If you attempt to save graphics when a print is in progress, this error message is displayed.

¹¹⁵ LIF-DOS COPY NOT ALLOWED

If you try to copy a file between the memory disk and the flexible disk when the format of the memory disk is different from the format of the flexible disk, this message is displayed.

116 NO STATE/DATA FILES ON MEMORY

There are no files on the memory disk with extensions, " D " or " $\subseteq S$ " for LIF format, or " \cdot STA" or ".DTA" for DOS format.

117 **DUPLICATE FILE EXTENSION**

The extension name entered is already used for other file types. Use other extension name.

NO DATA TRACE DISPLAYED 119

The SCALE FOR [DATA] is selected when the data trace is not displayed.

120

The SCALE FOR [MEMORY] is selected when the memory trace is not displayed.

The frequency list is empty. To implement the list frequency mode, add segments to the list table.

¹²⁶ CAN'T CHANGE NUMBER OF POINTS

The number of points of the spectrum analyzer mode cannot be to change manually, except in zero span.

¹²⁷ CAN'T SET SWEEP TIME AUTO IN ZERO SPAN

The automatic sweep time cannot be in zero span of the spectrum analyzer mode. (The network analyzer mode allows that the automatic sweep time is turned on.)

128 $SPAN = 0$ ONLY

The setup must be zero span and spectrum analyzer mode when turning on the RF OUTPUT.

131 FREQUENCY SWEEP ONLY

The sweep type must be frequency sweep when the center step size is set.

133 CAN'T CHANGE ON LIST SWEEP

When list sweep is selected, the following parameters are not allowed to be changed:

- CENTER, SPAN, START, STOP
- \blacksquare NOP
- IFBW or RBW
- **POWER**
- DC SOURCE

Modify the list table to change these parameters in the list sweep.

¹³⁴ CAN'T COUPLE IN CURRENT INPUTS

When one channel measures a ratio measurement, and the other one measures an absolute measurement (for example: A/R and B), COUPLED CH can not be turned on.

COUPLED CHAN - BETWEEN NA&NA OR ZA&ZA -135 135 COUPLEM CHAN - BETWEEN NAAR OR DE GROOTS

The analyzer types of both channels must be the network analyzer mode or impedance analyzer mode when the coupled channel is turned on. It is not possible to turn the coupled channel on in spectrum analyzer mode.

¹³⁶ DC SOURCE OVERLOAD

The DC SOURCE output is overloded.

137 DC CURRENT LIMIT OCCURED

The output current at DC SOURCE port is reached the upper limit; the output voltage is reduced so that the current does not exceed the upper limit. This message appears when the DC SOURCE port is used in voltage control mode.

¹³⁸ DC VOLTAGE LIMIT OCCURED

The output voltage at DC SOURCE port is reached the upper limit; the output current is reduced so that the voltage does not exceed the upper limit. This message appears when the DC SOURCE port is used in current control mode.

¹⁴¹ INSUFFICIENT MEMORY

If a lot of tasks is executed at same time, memory might be insufficient for a while. (For example, running HP Instrument BASIC program, printing ^a screen, and sending or receiving data array by GPIB are required at same time.) Please wait until finishing some tasks then execute the next task.

143

Indicate that a floating point error occured in the analyzer. Data processing may not be correct. This error message is used when an internal application was executed for illegal data sent from an external device, or when an internal software bug was detected. Contact your nearest Agilent Technologies office.

146 ON POINT NOT ALLOWD FOR THE CURRENT TRIG

The trigger event mode cannot be changed to the ON POINT mode because the current trigger source setting does not allow the ON POINT mode. The ON POINT mode is available for only MANUAL, EXTERNAL, and BUS trigger sources of the network analyzer mode.

154 **INVALID DATE**

The date entered to set the real time clock is invalid. Reenter correct date.

ACTIVE/SYSTEM CONTROLLER REQUIRED 173

When the 4395A and its peripherals are controlled using the Instrument BASIC, you must set the GPIB system's control mode to the system controller mode.

NOT ALLOWED IN SVC MODE 184

The operation is not allowed in service mode.

193 POWER ON TEST FAILED

Power on test failed. Contact your nearest Agilent Technologies office.

$201 - 300$

267 ²⁶⁷ COMPENSTATION REQUIRED

Compensation is required. Perform compansation to obtain compensation data.

268 ²⁶⁸ NO COMPENSATION CURRENTLY IN PROGRESS

No compensation is currently in progress.

²⁶⁹ COMPENSATION ABORTED

Compensation data acquisition process is aborted.

270 COMPENSATION STD LIST UNDEFINED

Compensation standard list is undefined.

 $-1 -100$

100 Command error

This is a generic syntax error that the analyzer cannot detect more specific errors. This code indicates only that a command error, as defined in IEEE 488.2, 11.5.1.1.4, has occurred.

-101 Invalid character

^A syntax element contains ^a character that is invalid for that type. For example, a header containing an ampersand (SENSE&).

102 Syntax error

An unrecognized command or data type was encountered. For example, a string was received when the analyzer was not expecting to receive a string.

-103 Invalid separator

The parser was expecting a separator and encountered an illegal character. For example, the semicolon was omitted after a program message unit, *RST:TRIG.

-104 Data type error

The parser recognized an unallowed data element. For example, numeric or string data was expected but block data was encountered.

-105 **GET** not allowed

A Group Execute Trigger (GET) was received within a program message (see IEEE 488.2, 7.7).

-108 Parameter not allowed

More parameters were received than expected for the header. For example, the *SRE command only accepts one parameter, so receiving *SRE 4,16 is not allowed.

-109 Missing parameter

Fewer parameters were received than required for the header. For example, the *SRE command requires one parameter, so receiving only *SRE is not allowed.

Command header error -110

An error was detected in the header. This error message is used when the analyzer cannot detect the more specific errors described for errors -111 through -119 .

-111 Header separator error

^A character that is not ^a legal header separator was encountered while parsing the header. For example, no white space followed the header, thus *SRE4 is an error.

-112 Program mnemonic too long

The header contains more than twelve characters (see IEEE 488.2, 7.6.1.4.1).

-113 Undefined header

The header is syntactically correct, but it is undefined for the analyzer. For example, $*XYZ$ is not defined for the analyzer.

-114 Header Suffix out of range

The value of a numeric suffix attached to a program mnemonic makes the header invalid.

120 Numeric data error

This error, as well as errors -121 through -129 , are generated when parsing a data element that appears to be numeric, including the nondecimal numeric types. This particular error message is used if the analyzer cannot detect a more specific error.

-121 Invalid character in number

An invalid character for the data type being parsed was encountered. For example, an alpha character in a decimal numeric or a \9" in octal data.

-123 **Exponent too large**

The magnitude of the exponent was larger than 32000 (see IEEE 488.2, 7.7.2.4.1).

-124 Too many digits

The mantissa of a decimal numeric data element contains more than 255 digits excluding leading zeros (see IEEE 488.2, 7.7.2.4.1).

-128 Numeric data not allowed

A legal numeric data element was received, but the analyzer does not accept it in this position for a header.

-130 Suffix error

This error, as well as errors -131 through -139 , are generated when parsing a suffix. This particular error message is used if the analyzer cannot detect a more specific error.

-131

The suffix does not follow the syntax described in IEEE 488.2 , 7.7.3.2, or the suffix is inappropriate for the analyzer.

-134 Suffix too long

The suffix contained more than 12 characters (see IEEE 488.2, 7.7.3.4).

-138 Suffix not allowed

A suffix was encountered after a numeric element that does not allow suffixes.

-140

This error, as well as errors -141 through -148 , are generated when analyzing the syntax of a character data element. This particular error message is used if the analyzer cannot detect ^a more specific error.

-141 Invalid character data

Either the character data element contains an invalid character or the particular element received is not valid for the header.

-144 Character data too long

The character data element contains more than twelve characters (see IEEE 488.2, 7.7.1.4).

-148 Character data not allowed

^A legal character data element was encountered where prohibited by the analyzer.

-150 String data error

This error, as well as errors -151 and -158 , are generated when analyzing the syntax of a string data element. This particular error message is used if the analyzer cannot detect a more specific error.

-151 Invalid string data

A string data element was expected, but was invalid for some reason (see IEEE 488.2, 7.7.5.2). For example, an END message was received before the terminal quote character.

-158 String data not allowed

A string data element was encountered but was not allowed by the analyzer at this point in parsing.

-160 160 Block data error

This error, as well as errors -161 and -168 , are generated when analyzing the syntax of a block data element. This particular error message is used if the analyzer cannot detect ^a more specific error.

-161 Invalid block data

^A block data element was expected, but was invalid for some reason (see IEEE 488.2, 7.7.6.2). For example, an END message was received before the length was satisfied.

-168 Block data not allowed

^A legal block data element was encountered but was not allowed by the analyzer at this point in parsing.

-200 **Execution error**

This is the generic syntax error that the analyzer cannot detect more specific errors. This code indicates only that an execution error as defined in IEEE 488.2 , $11.5.1.1.5$ has occurred.

$-201 - -300$ -3000 - 300 - 310 - 321 - 322 - 323 - 324 - 325 - 326 - 327 - 328 - 329 - 320 - 321 - 322 -

-210 Trigger error

A trigger related error occurred. This error message is used when the analyzer cannot detect the more specific errors described for errors -211 through -219 .

-211 Trigger ignored

^A GET, *TRG, or triggering signal was received and recognized by the analyzer but was ignored because of analyzer timing considerations. For example, the analyzer was not ready to respond.

-213 Init ignored

^A request for ^a measurement initiation was ignored as another measurement was already in progress.

220 Parameter error

Indicates that a program data element related error occurred. This error message is used when the analyzer cannot detect the more specific errors described for errors -221 through -229 .

-221 **Settings conflict**

A legal program data element was parsed but could not be executed due to the current device state (see IEEE 488.2, 6.4.5.3 and 11.5.1.1.5).

-222 Data out of range

A legal program data element was parsed but could not be executed because the interpreted value was outside the legal range as defined by the analyzer (see IEEE $488.2, 11.5.1.1.5$).

-223 Too much data

A legal program data element of block, expression, or string type was received that contained more data than the analyzer could handle due to memory or related device-specic requirements.

-224 Illegal parameter value

Used where exact value, from ^a list of possibilities, was expected.

-225 Data out of memory

The analyzer has insufficient memory to perform the requested operation.

-230 Data corrupt or stale

Possibly invalid data. New reading started but not completed since last access.

231 Data questionable

Indicates that measurement accuracy is suspect.

-240 Hardware error

Indicates that ^a legal program command or query could not be executed because of a hardware problem in the analyzer. Definition of what constitutes a hard ware problem is completely device-specific. This error message is used when the analyzer cannot detect the more specific errors described for errors -241 through -249 .

-241 Hardware missing

^A legal program command or query could not be executed because of missing analyzer hardware. For example, an option was not installed.

250 Mass storage error

Indicates that a mass storage error occurred. This error message is used when the analyzer cannot detect the more specific errors described for errors -257 .

-256 File name not found

^A legal program command could not be executed because the le name on the device media was not found: for example, an attempt was made to read or copy a nonexistent le.

-257 File name error

Indicates that a legal program command or query could not be executed because the file name on the device media was in error. For example, an attempt was made to copy to a duplicate file name. The definition of what constitutes a file name error is device-specific.

280 Program error

Indicates that a downloaded program-related execution error occurred. This error message is used when the analyzer cannot detect the more specific errors described for errors -281 through -289 .

-281 Cannot create program

Indicates that an attempt to create a program was unsuccessful. A reason for the failure might include not enough memory.

-282 Illegal program name

The name used to reference a program was invalid. For example, redefining an existing program, deleting ^a nonexistent program, or in general, referencing a nonexistent program.

283 Illegal variable name

An attempt was made to reference ^a nonexistent variable in ^a program.

-284 Program currently running

Certain operations dealing with programs may be illegal while the program is running. For example, deleting ^a running program might not be possible.

285 Program syntax error

Indicates that ^a syntax error appears in ^a downloaded program. The syntax used when parsing the downloaded program is device-specic.

286 Program runtime error

A program runtime error of the HP Instrument BASIC has occurred. To get a more specific error information, use the ERRM\$ or ERRN command of the HP Instrument BASIC.

$-301 - -400$ 300 **- 400** - 400

310 System error

Some error, termed "system error" by the analyzer, has occurred.

Memory error -311

An error was detected in the analyzer's memory.

-330 Self-test failed

A self-test failed. Contact your nearest Agilent Technologies office or see the Service Manual for troubleshooting.

-350 Queue overflow

A specic code entered into the queue in lieu of the code that caused the error. This code indicates that there is no room in the queue and an error occurred but was not recorded.

400 Query errors

This is the generic query error that the analyzer cannot detect more specific errors. This code indicates only that a query error as defined in IEEE 488.2 , 11.5.1.1.7 and 6.3 has occurred.

$-401 - -500$

410 Query INTERRUPTED

A condition causing an interrupted query error occurred (see IEEE 488.2, 6.3.2.3). For example, a query followed by DAB or GET before ^a response was completely sent.

420 Query UNTERMINATED

^A condition causing an unterminated query error occurred (see IEEE 488.2, 6.3.2.2). For example, the analyzer was addressed to talk and an incomplete program message was received by the controller.

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